

Plots of System Verification

Appendix A. Plots of System Verification

The plots for system verification are shown as follows.

Plots of System Verification

Measurement Report S01 System Check H835_240507

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		835

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.92	42.5

Hardware Setup

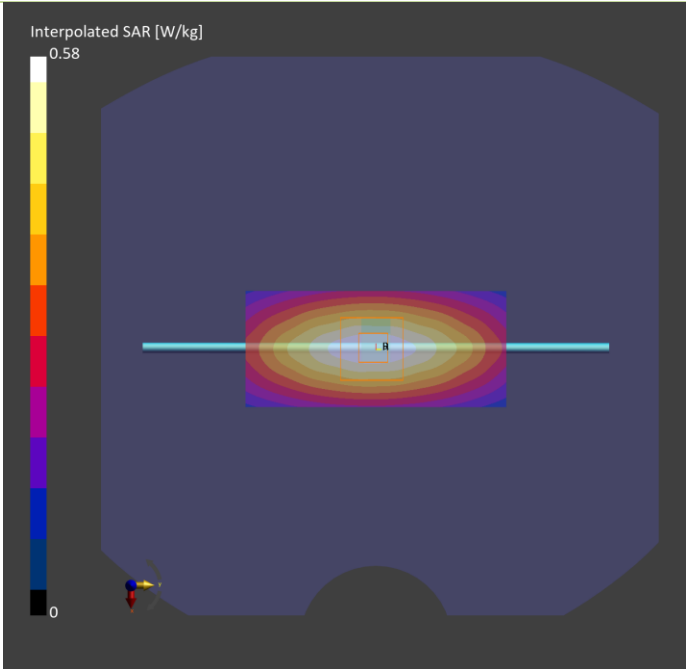
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	0.500	0.504
psSAR10g [W/kg]	0.329	0.335
Power Drift [dB]	0.01	0.05



Plots of System Verification

Measurement Report
S02 System Check H1900_240507
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1900

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.43	41.1

Hardware Setup

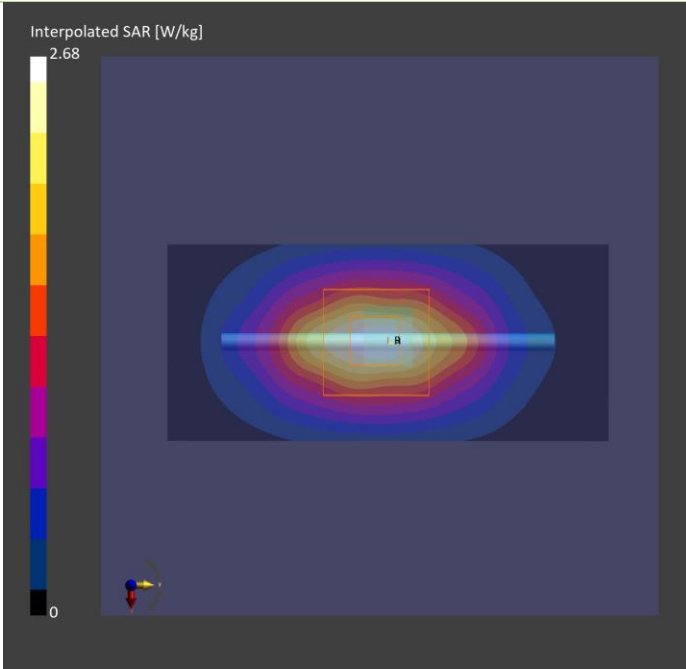
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	2.13	2.14
psSAR10g [W/kg]	1.11	1.14
Power Drift [dB]	0.04	-0.00



Plots of System Verification

Measurement Report

S03 System Check H1900_240415

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.46	40.9

Hardware Setup

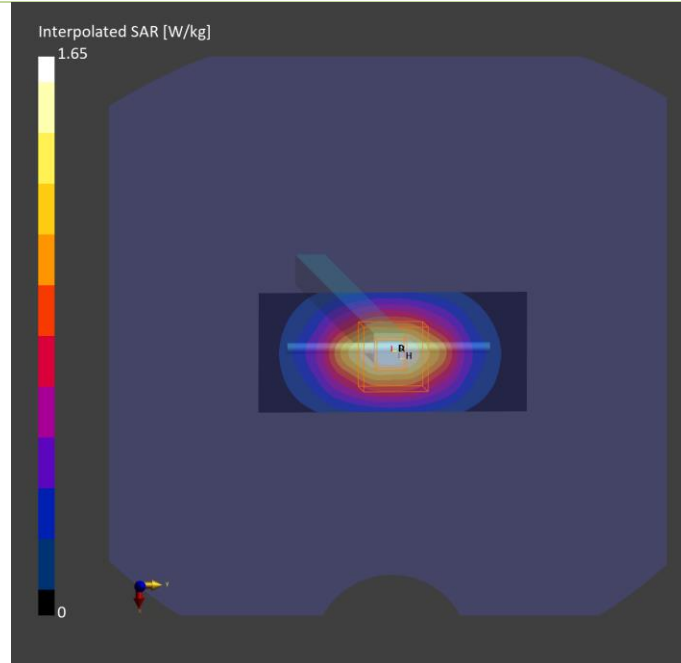
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-15	2024-04-15
psSAR1g [W/kg]	1.78	1.83
psSAR10g [W/kg]	1.071	1.079
Power Drift [dB]	-0.14	-0.03



Plots of System Verification

Measurement Report
S04 System Check H1750_240415
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	8.74	1.37	41.0

Hardware Setup

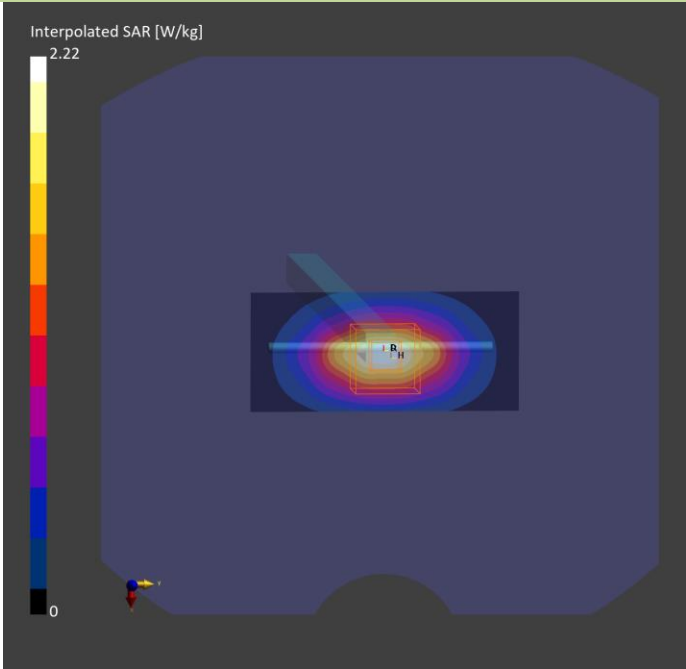
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-15	2024-04-15
psSAR1g [W/kg]	1.77	1.76
psSAR10g [W/kg]	0.938	0.933
Power Drift [dB]	-0.00	-0.00



Plots of System Verification

Measurement Report S05 System Check H835_240415

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.94	43.1

Hardware Setup

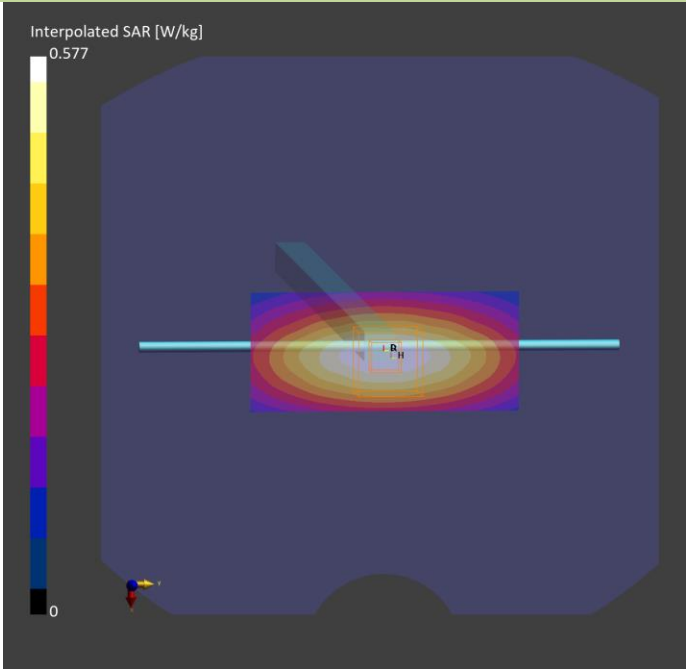
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-15	2024-04-15
psSAR1g [W/kg]	0.499	0.498
psSAR10g [W/kg]	0.328	0.325
Power Drift [dB]	0.01	0.00



Plots of System Verification

Measurement Report
S06 System Check H1900_240418
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.45	40.7

Hardware Setup

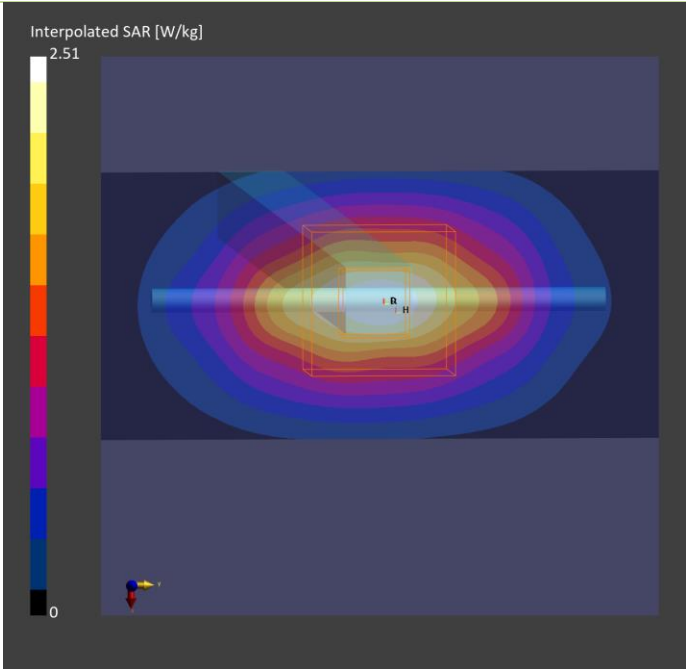
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-18	2024-04-18
psSAR1g [W/kg]	1.99	2.00
psSAR10g [W/kg]	1.02	1.03
Power Drift [dB]	-0.04	-0.14



Plots of System Verification

S07 System Check H1750_240418

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	8.74	1.36	40.9

Hardware Setup

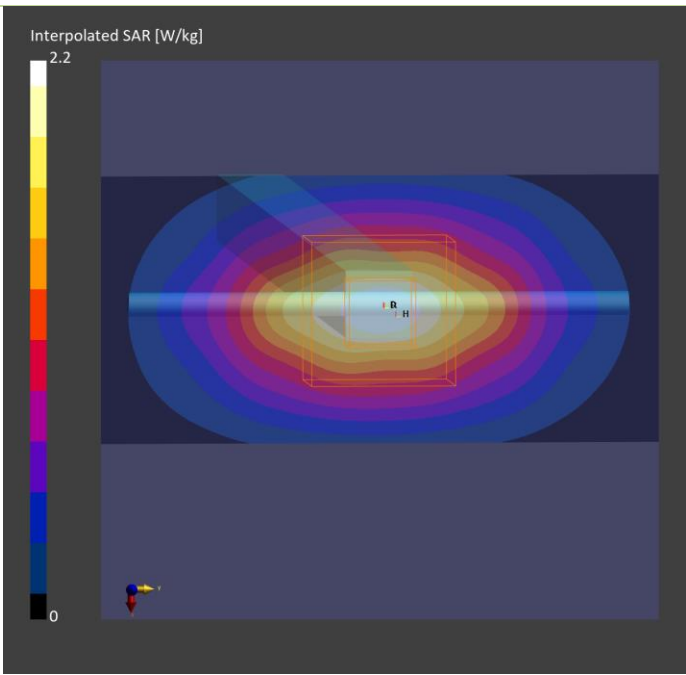
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-18	2024-04-18
psSAR1g [W/kg]	1.75	1.75
psSAR10g [W/kg]	0.925	0.928
Power Drift [dB]	-0.02	-0.05



Plots of System Verification

Measurement Report S08 System Check H835_240417

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		835

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.93	42.7

Hardware Setup

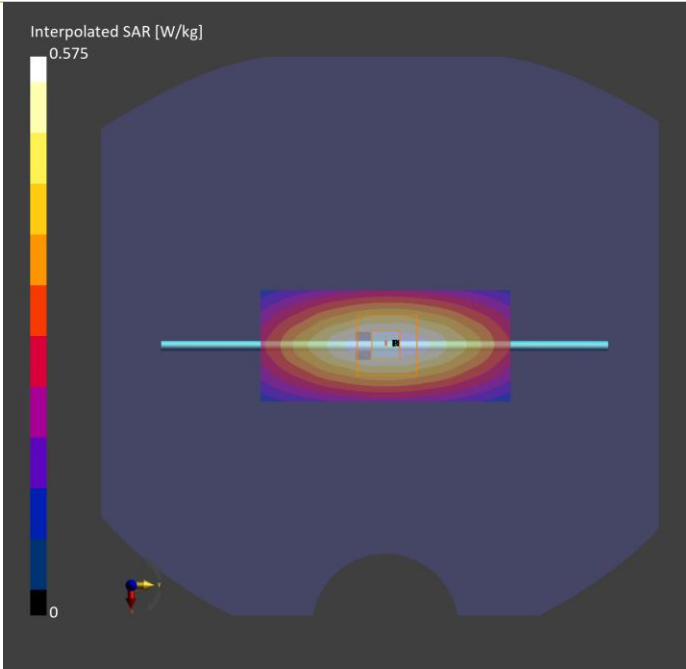
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.495	0.491
psSAR10g [W/kg]	0.324	0.319
Power Drift [dB]	-0.06	-0.05



Plots of System Verification

Measurement Report
S09 System Check H2600_240418
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.94	39.7

Hardware Setup

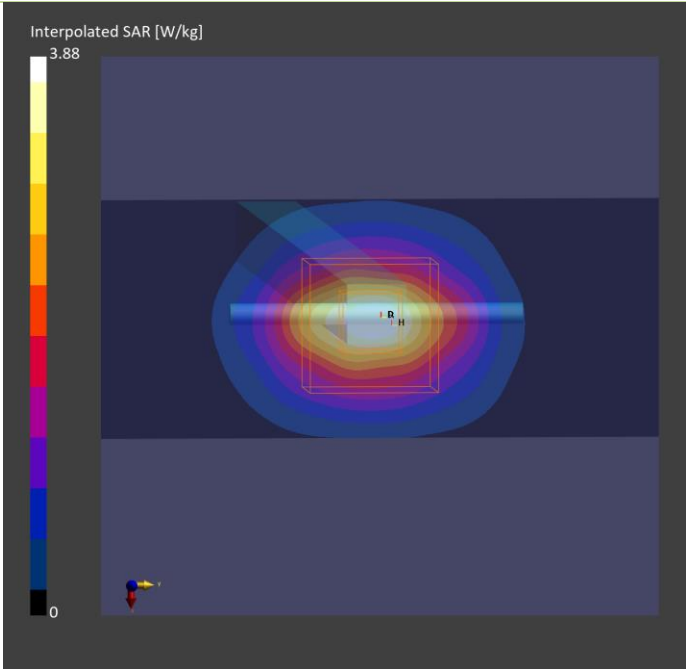
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-18	2024-04-18
psSAR1g [W/kg]	2.89	2.79
psSAR10g [W/kg]	1.28	1.24
Power Drift [dB]	-0.09	-0.19



Plots of System Verification

Measurement Report S10 System Check H750_240416 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.910	43.3

Hardware Setup

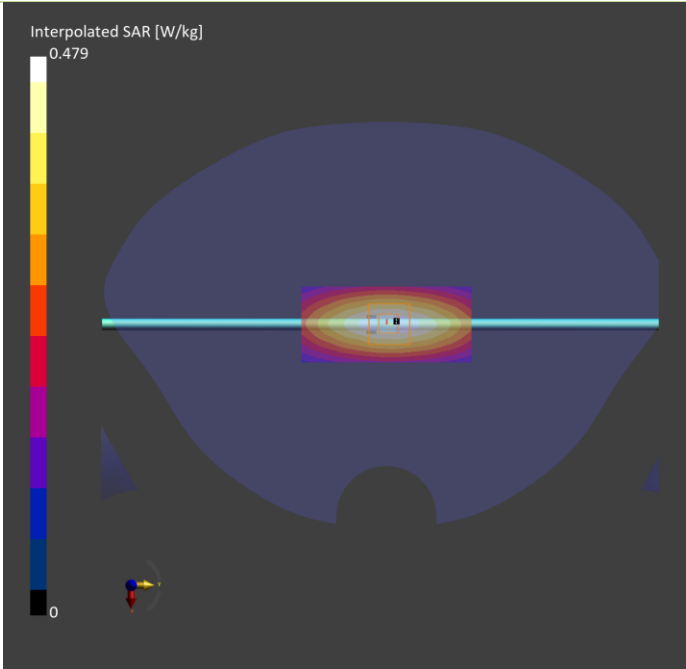
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.415	0.416
psSAR10g [W/kg]	0.275	0.274
Power Drift [dB]	-0.02	-0.11



Plots of System Verification

Measurement Report S11 System Check H750_240416

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.910	43.3

Hardware Setup

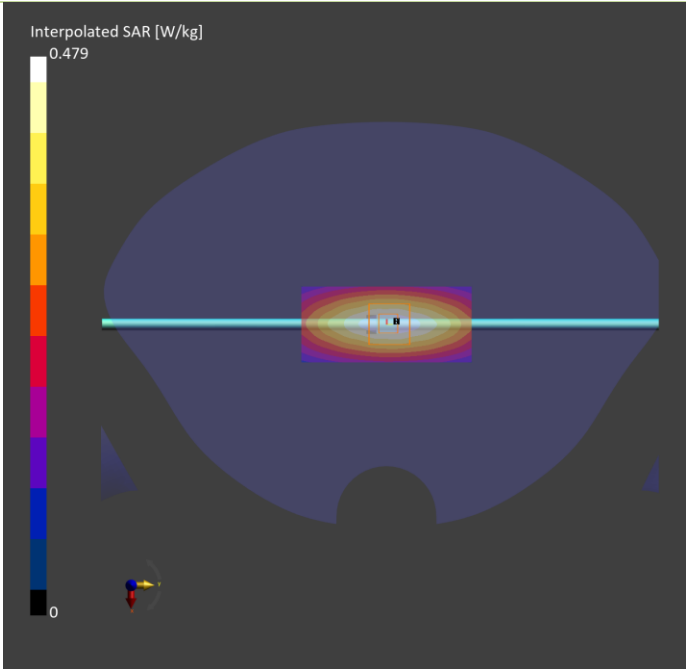
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.415	0.416
psSAR10g [W/kg]	0.275	0.274
Power Drift [dB]	-0.02	-0.11



Plots of System Verification

Measurement Report
S12 System Check H750_240416
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.910	43.3

Hardware Setup

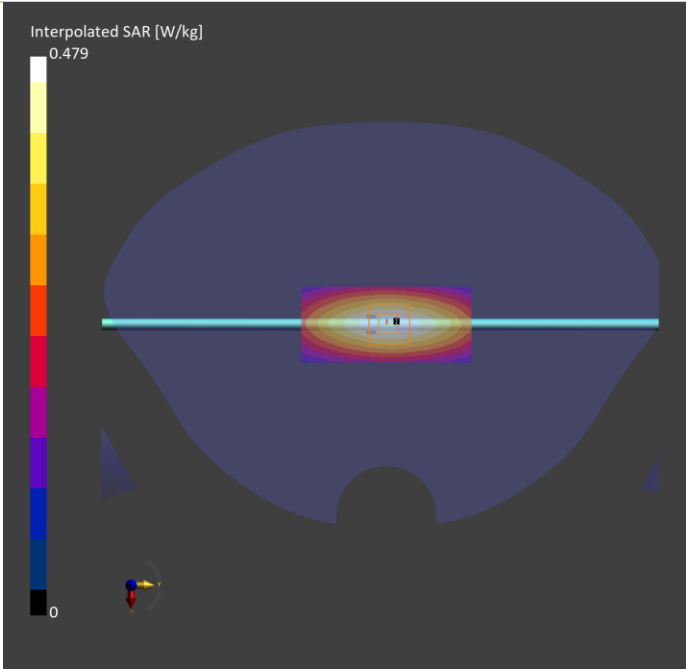
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.415	0.416
psSAR10g [W/kg]	0.275	0.274
Power Drift [dB]	-0.02	-0.11



Plots of System Verification

Measurement Report S13 System Check H750_240416 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.910	43.3

Hardware Setup

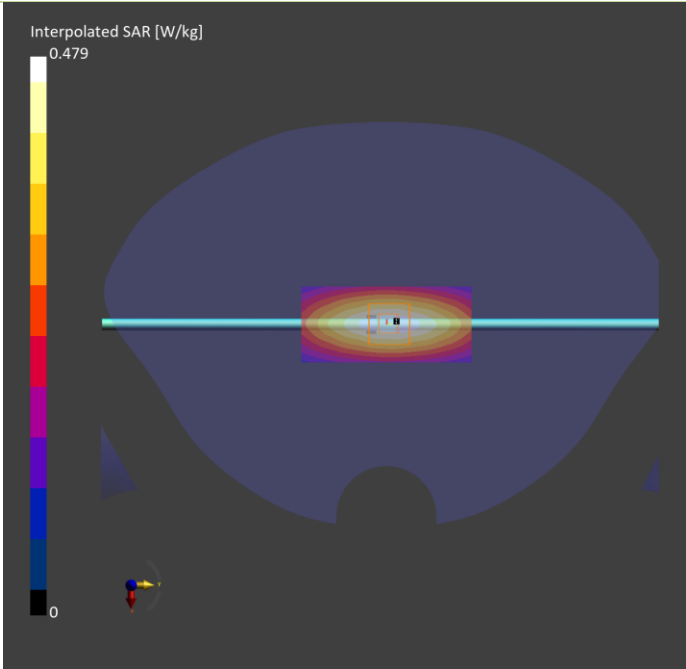
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.415	0.416
psSAR10g [W/kg]	0.275	0.274
Power Drift [dB]	-0.02	-0.11



Plots of System Verification

Measurement Report S14 System Check H1900_240518 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1900

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.34	40.0

Hardware Setup

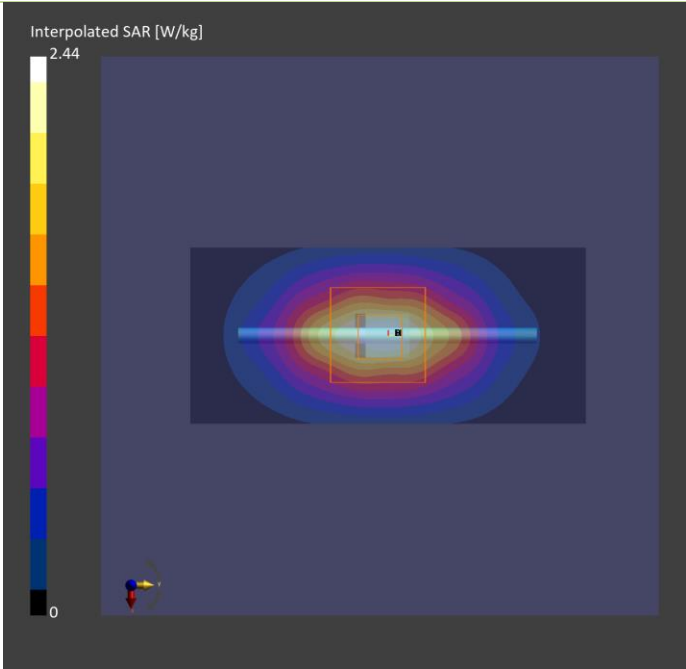
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-18	2024-05-18
psSAR1g [W/kg]	1.94	1.93
psSAR10g [W/kg]	0.998	1.02
Power Drift [dB]	0.01	0.01



Plots of System Verification

Measurement Report S15 System Check H835_240417

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		835

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.93	42.7

Hardware Setup

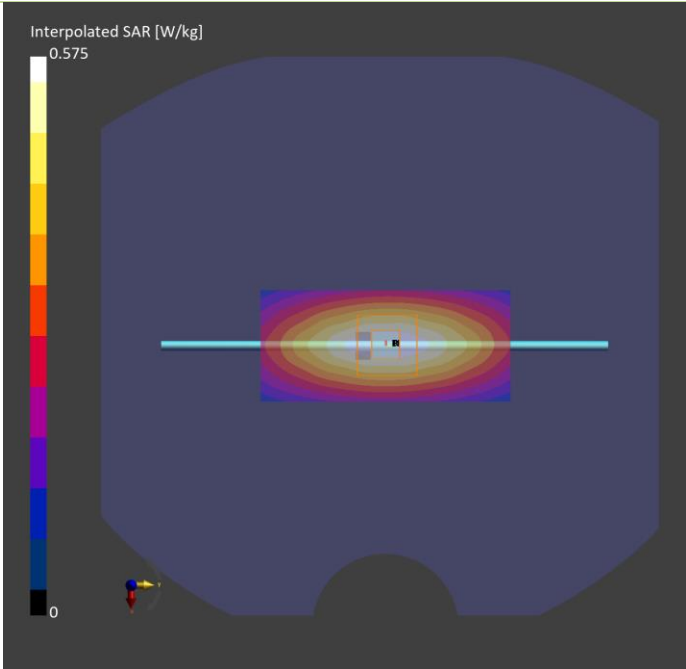
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.495	0.491
psSAR10g [W/kg]	0.324	0.319
Power Drift [dB]	-0.06	-0.05



Plots of System Verification

Measurement Report
S16 System Check_H2300_240424
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2300

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2300.000, 0	8.12	1.72	39.0

Hardware Setup

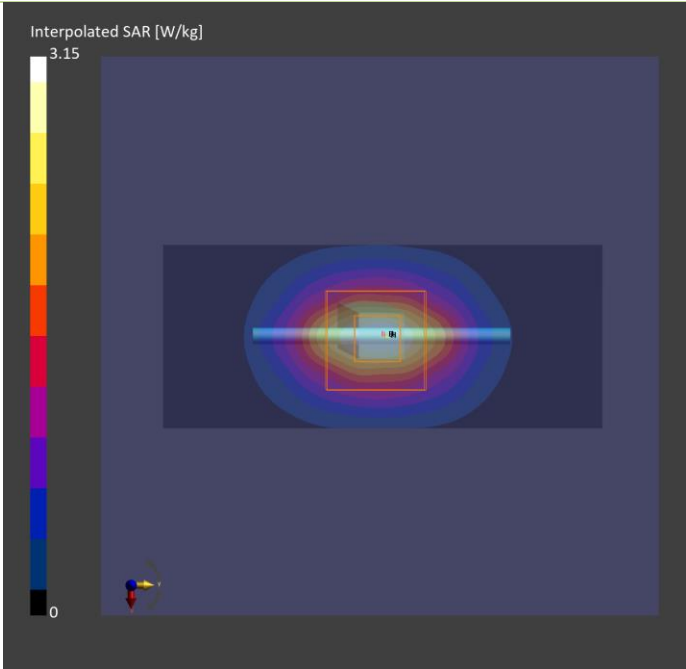
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-24	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-24	2024-04-24
psSAR1g [W/kg]	2.40	2.39
psSAR10g [W/kg]	1.13	1.14
Power Drift [dB]	0.01	0.02



Plots of System Verification

Measurement Report
S17 System Check H2600_240419
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.92	37.5

Hardware Setup

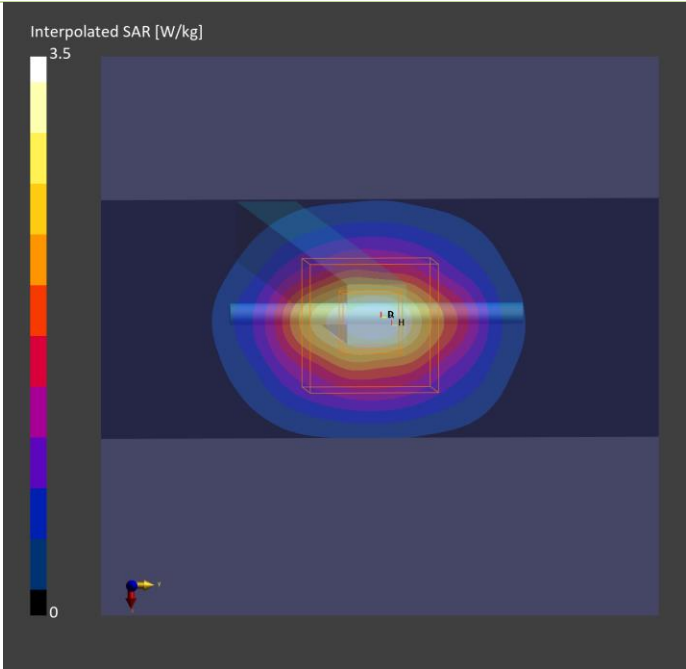
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-19	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-19	2024-04-19
psSAR1g [W/kg]	2.61	2.65
psSAR10g [W/kg]	1.15	1.17
Power Drift [dB]	-0.00	0.01



Plots of System Verification

Measurement Report S18 System Check H2600_240503 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2600

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.97	40.2

Hardware Setup

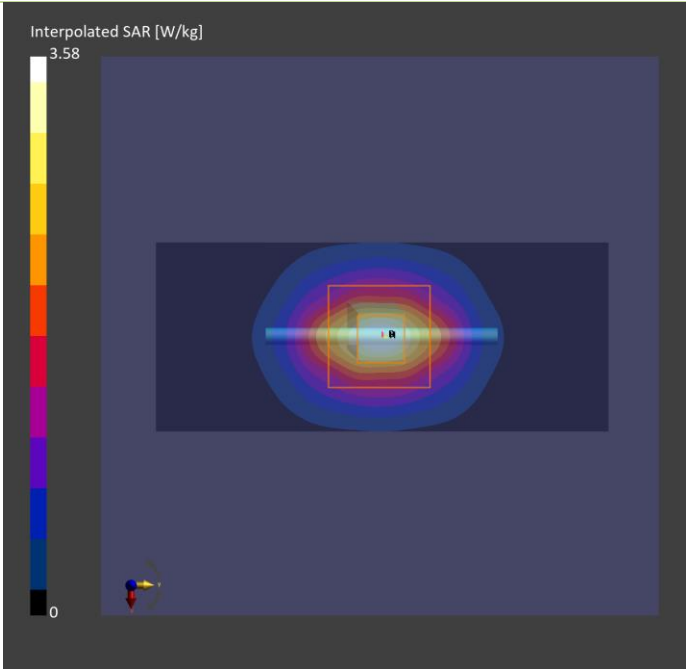
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-03	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-03	2024-05-03
psSAR1g [W/kg]	2.64	2.69
psSAR10g [W/kg]	1.16	1.19
Power Drift [dB]	0.01	-0.11



Plots of System Verification

Measurement Report
S19 System Check H3500_240503
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.79	38.5

Hardware Setup

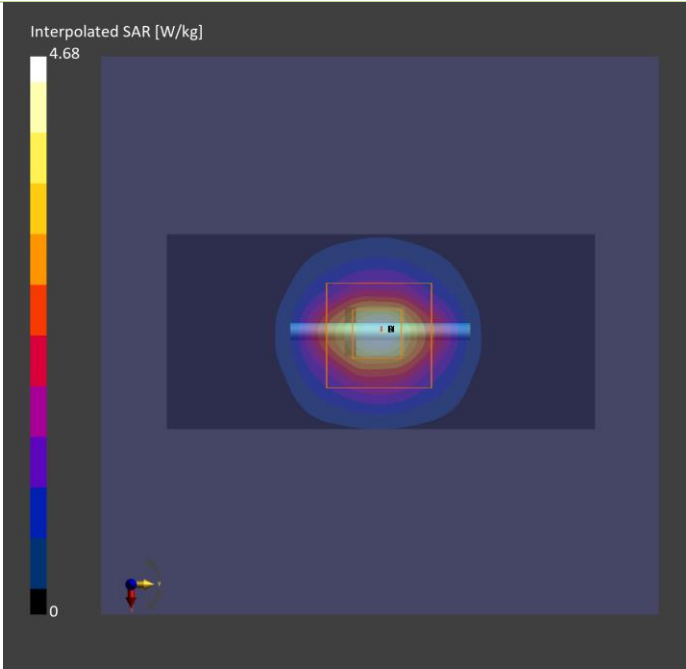
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-03	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-03	2024-05-03
psSAR1g [W/kg]	3.25	3.30
psSAR10g [W/kg]	1.22	1.27
Power Drift [dB]	-0.01	-0.13



Plots of System Verification

Measurement Report S20 System Check H3700_240503 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.97	38.2

Hardware Setup

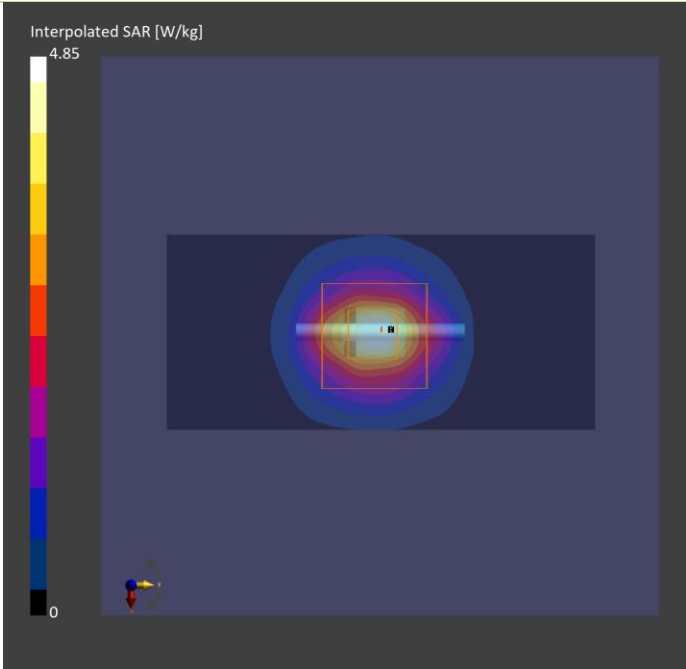
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-03	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-03	2024-05-03
psSAR1g [W/kg]	3.33	3.33
psSAR10g [W/kg]	1.22	1.25
Power Drift [dB]	0.01	-0.03



Plots of System Verification

Measurement Report S21a System Check H3500_240505 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.80	38.9

Hardware Setup

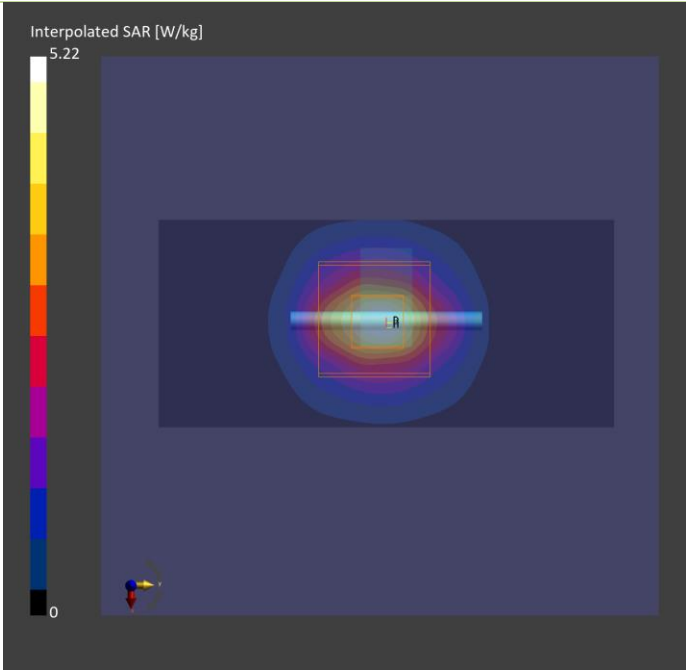
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	3.53	3.57
psSAR10g [W/kg]	1.37	1.45
Power Drift [dB]	0.02	-0.01



Plots of System Verification

Measurement Report
S21b System Check H3700_240505
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.98	38.6

Hardware Setup

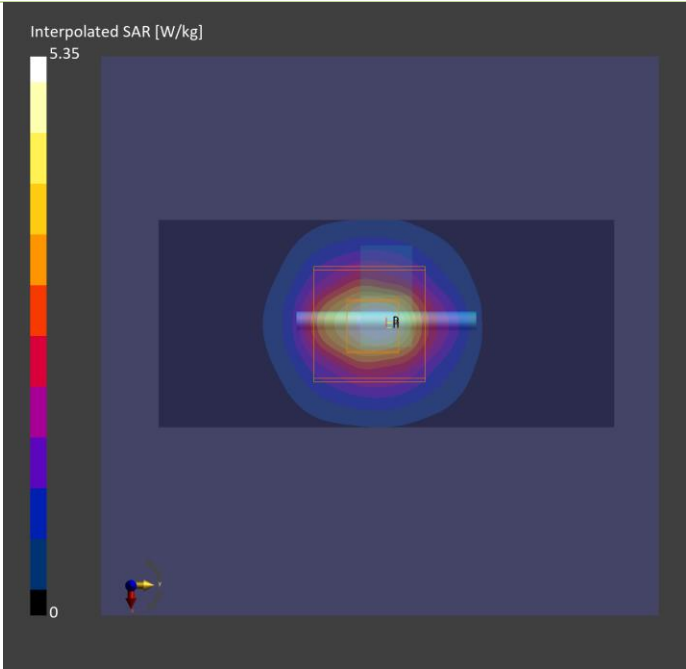
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	3.71	3.56
psSAR10g [W/kg]	1.38	1.35
Power Drift [dB]	0.02	0.01



Plots of System Verification

Measurement Report S22 System Check_H1750_240424 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	9.0	1.37	39.8

Hardware Setup

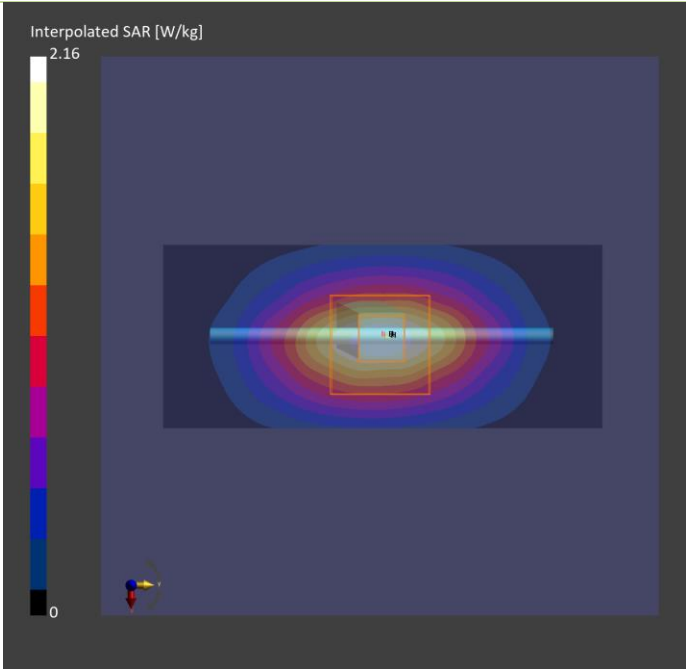
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-24	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-24	2024-04-24
psSAR1g [W/kg]	1.72	1.72
psSAR10g [W/kg]	0.917	0.913
Power Drift [dB]	0.01	0.01



Plots of System Verification

Measurement Report S23 System Check H750_240416

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.910	43.3

Hardware Setup

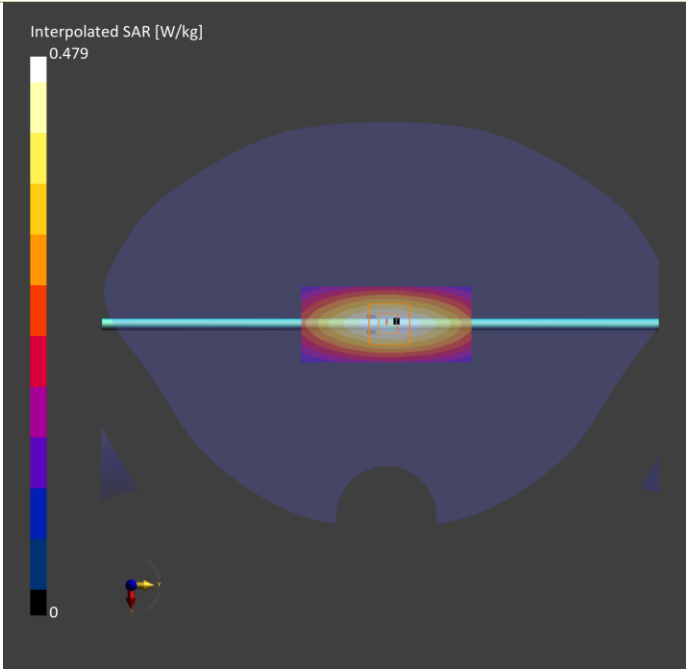
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.415	0.416
psSAR10g [W/kg]	0.275	0.274
Power Drift [dB]	-0.02	-0.11



Plots of System Verification

Measurement Report S24 System Check_H1900_240426

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1900

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.37	1.45	39.6

Hardware Setup

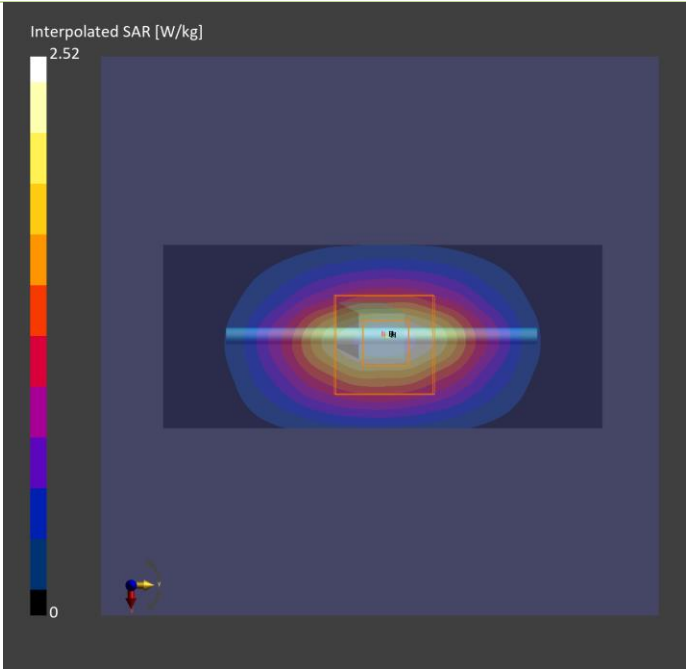
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-26	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-26	2024-04-26
psSAR1g [W/kg]	2.00	2.00
psSAR10g [W/kg]	1.04	1.04
Power Drift [dB]	0.01	-0.01



Plots of System Verification

Measurement Report S25 System Check H835_240417

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		835

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.93	42.7

Hardware Setup

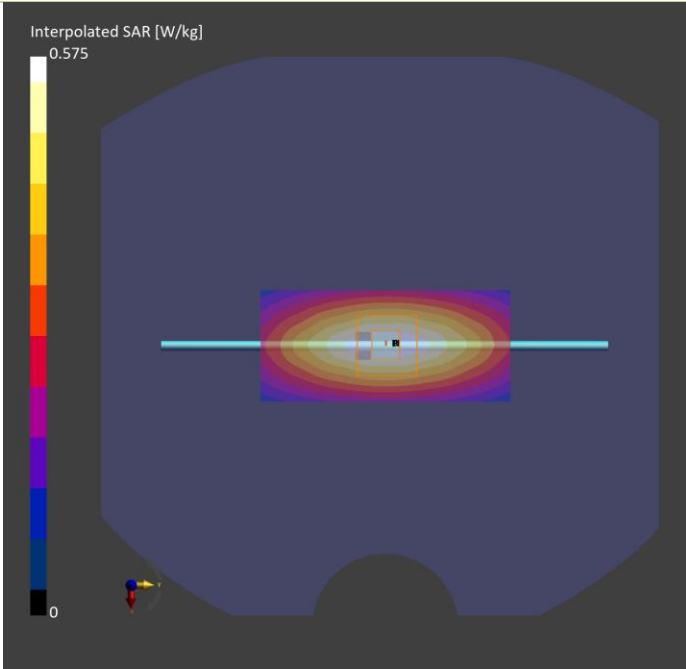
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.495	0.491
psSAR10g [W/kg]	0.324	0.319
Power Drift [dB]	-0.06	-0.05



Plots of System Verification

Measurement Report S26 System Check H2600_240505

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.95	39.9

Hardware Setup

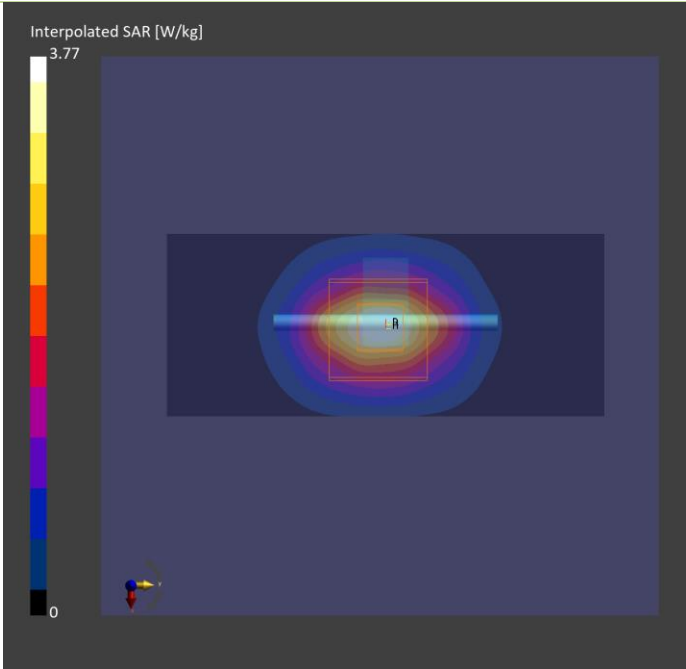
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	2.82	2.90
psSAR10g [W/kg]	1.26	1.32
Power Drift [dB]	0.03	-0.02



Plots of System Verification

Measurement Report
S27 System Check_H750_240425
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.35	0.891	40.2

Hardware Setup

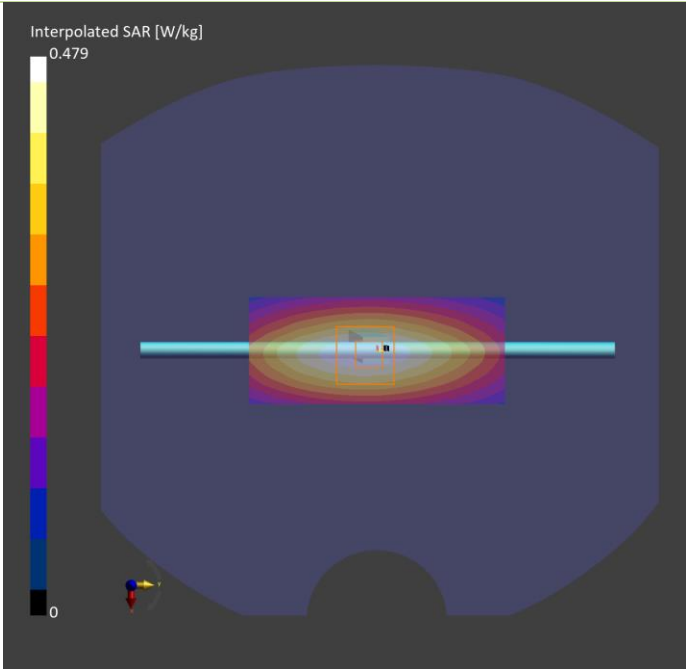
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-25	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-25	2024-04-25
psSAR1g [W/kg]	0.415	0.415
psSAR10g [W/kg]	0.277	0.275
Power Drift [dB]	0.01	0.02



Plots of System Verification

Measurement Report
S28 System Check_H750_240425
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.35	0.891	40.2

Hardware Setup

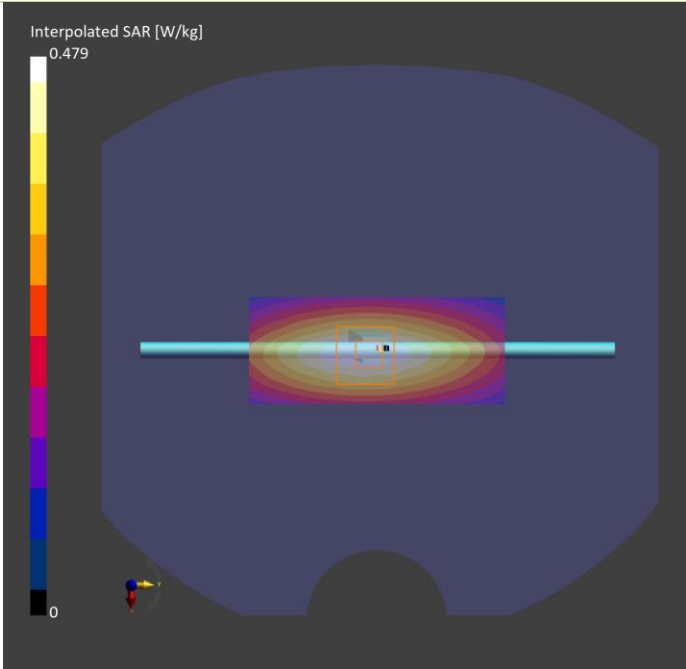
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-25	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-25	2024-04-25
psSAR1g [W/kg]	0.415	0.415
psSAR10g [W/kg]	0.277	0.275
Power Drift [dB]	0.01	0.02



Plots of System Verification

Measurement Report
S29 System Check_H1900_240426
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1900

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.37	1.45	39.6

Hardware Setup

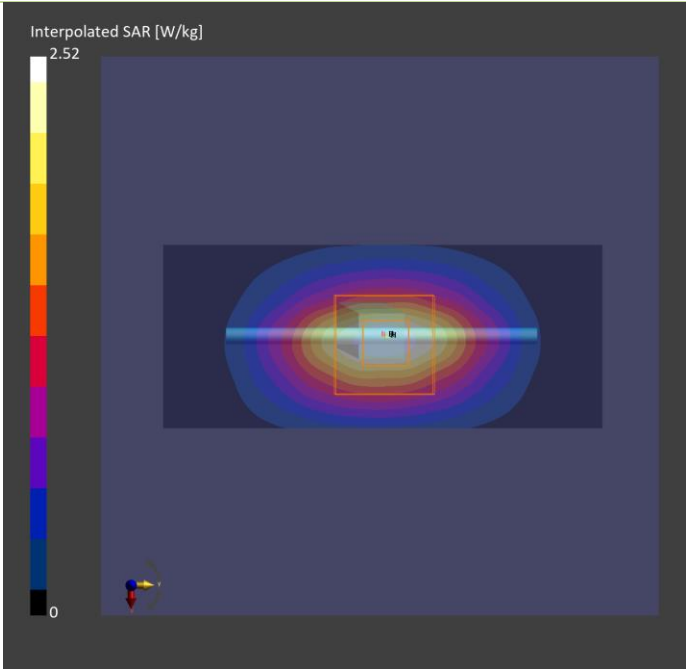
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-26	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-26	2024-04-26
psSAR1g [W/kg]	2.00	2.00
psSAR10g [W/kg]	1.04	1.04
Power Drift [dB]	0.01	-0.01



Plots of System Verification

Measurement Report S30 System Check H835_240417

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		835

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.93	42.7

Hardware Setup

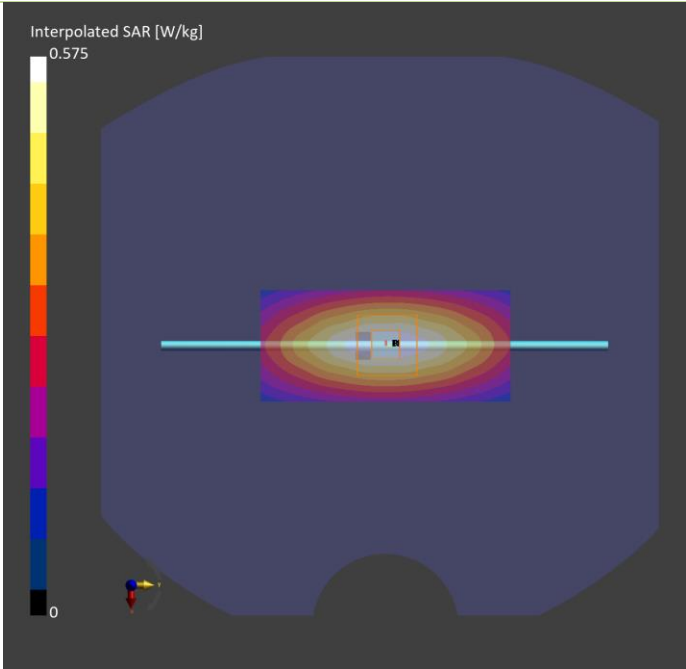
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.495	0.491
psSAR10g [W/kg]	0.324	0.319
Power Drift [dB]	-0.06	-0.05



Plots of System Verification

Measurement Report
S31 System Check H2600_240507
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2600

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.93	40.2

Hardware Setup

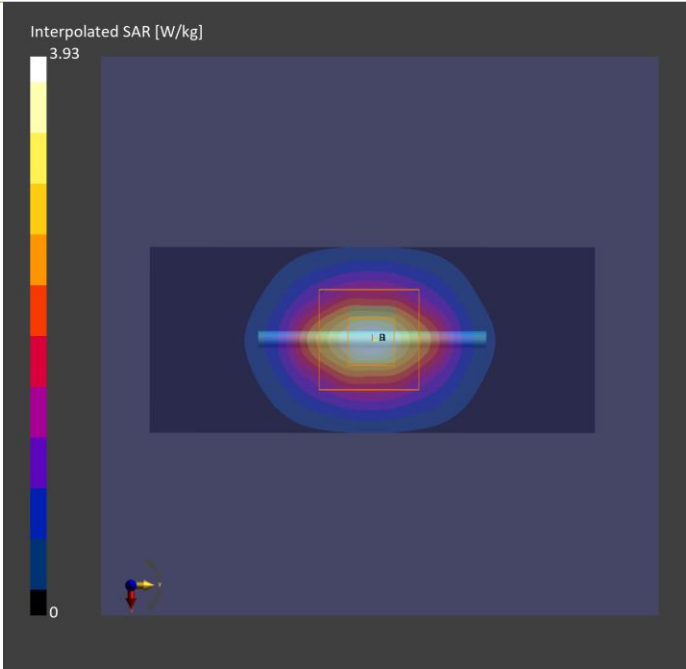
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	2.92	2.97
psSAR10g [W/kg]	1.30	1.36
Power Drift [dB]	0.02	-0.02



Plots of System Verification

Measurement Report
S32 System Check H2600_240507
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2600

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.93	40.2

Hardware Setup

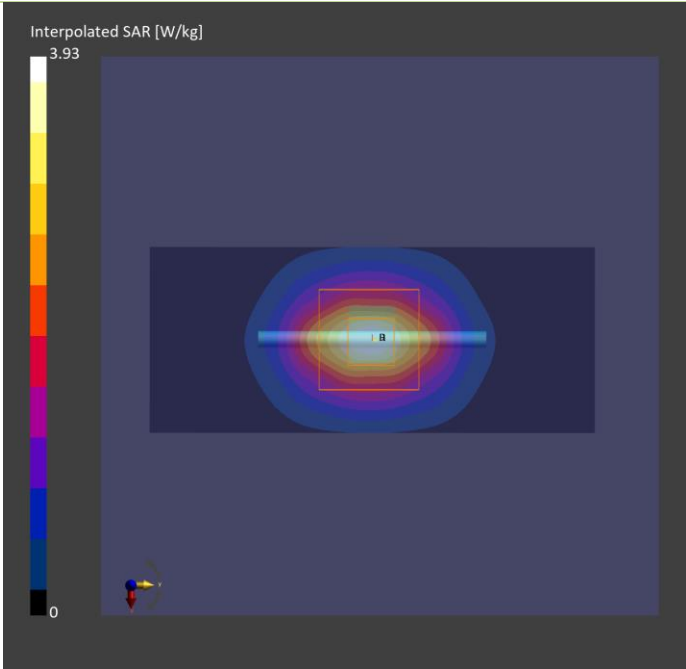
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	2.92	2.97
psSAR10g [W/kg]	1.30	1.36
Power Drift [dB]	0.02	-0.02



Plots of System Verification

Measurement Report
S33a System Check H3500_240505
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.80	38.9

Hardware Setup

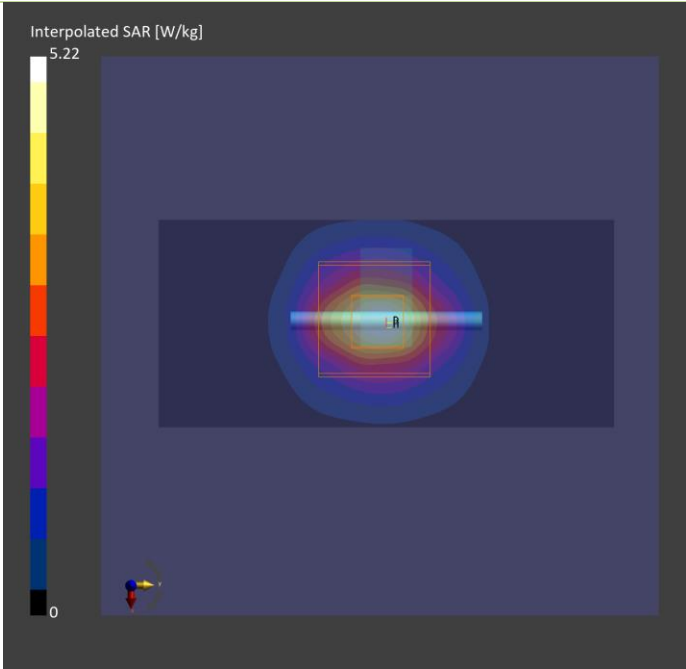
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	3.53	3.57
psSAR10g [W/kg]	1.37	1.45
Power Drift [dB]	0.02	-0.01



Plots of System Verification

Measurement Report S33b System Check H3700_240505 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.98	38.6

Hardware Setup

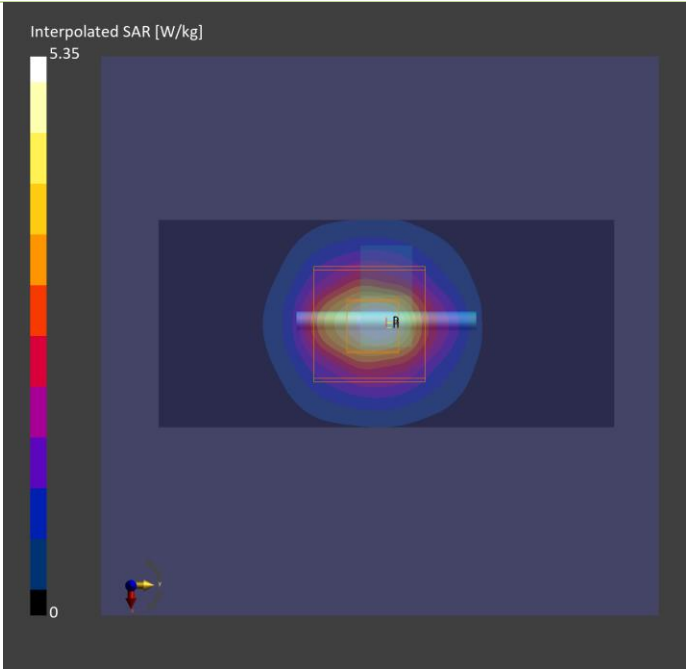
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	3.71	3.56
psSAR10g [W/kg]	1.38	1.35
Power Drift [dB]	0.02	0.01



Plots of System Verification

Measurement Report S34 System Check H1750_240514

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	8.74	1.38	41.3

Hardware Setup

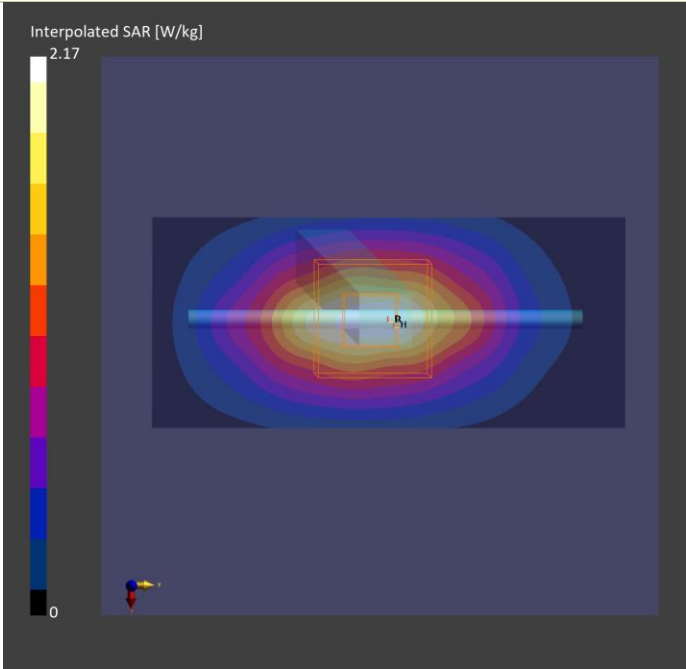
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-14	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-14	2024-05-14
psSAR1g [W/kg]	1.75	1.81
psSAR10g [W/kg]	0.933	0.977
Power Drift [dB]	-0.01	-0.18



Plots of System Verification

Measurement Report S35 System Check_H750_240425

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.35	0.891	40.2

Hardware Setup

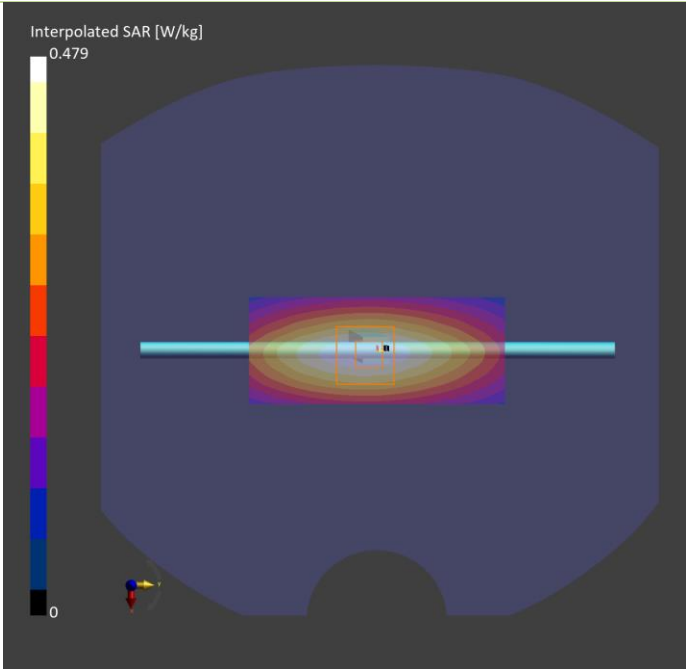
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-25	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-25	2024-04-25
psSAR1g [W/kg]	0.415	0.415
psSAR10g [W/kg]	0.277	0.275
Power Drift [dB]	0.01	0.02



Plots of System Verification

Measurement Report S36a System Check H3500_240509 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.83	39.2

Hardware Setup

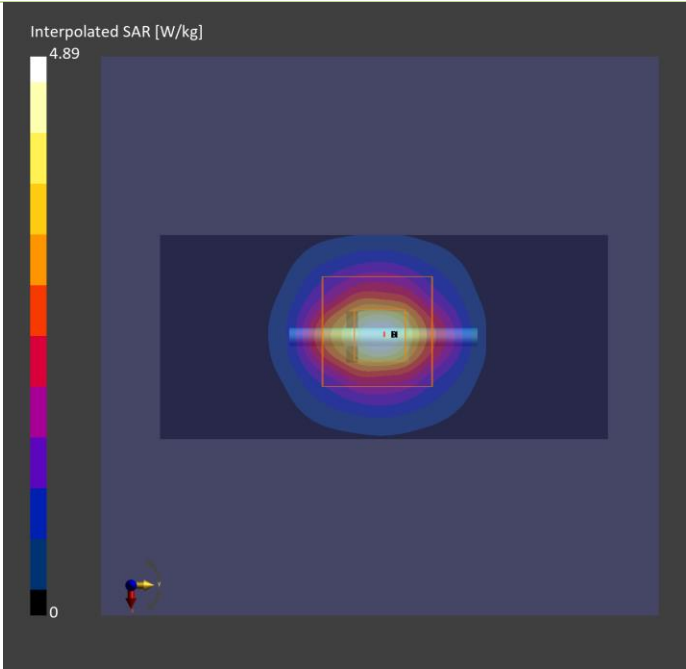
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-09	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-09	2024-05-09
psSAR1g [W/kg]	3.40	3.44
psSAR10g [W/kg]	1.28	1.35
Power Drift [dB]	0.01	-0.03



Plots of System Verification

Measurement Report S36b System Check H3700_240509 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	3.01	39.0

Hardware Setup

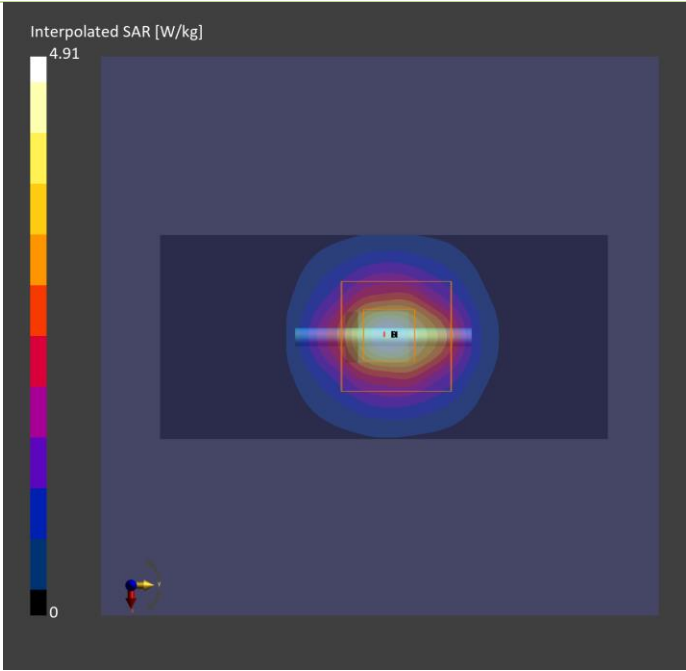
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-09	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-09	2024-05-09
psSAR1g [W/kg]	3.37	3.47
psSAR10g [W/kg]	1.25	1.34
Power Drift [dB]	0.02	0.01



Plots of System Verification

Measurement Report
S36c System Check H3900_240509
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3900

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3900.000, 0	6.53	3.20	38.7

Hardware Setup

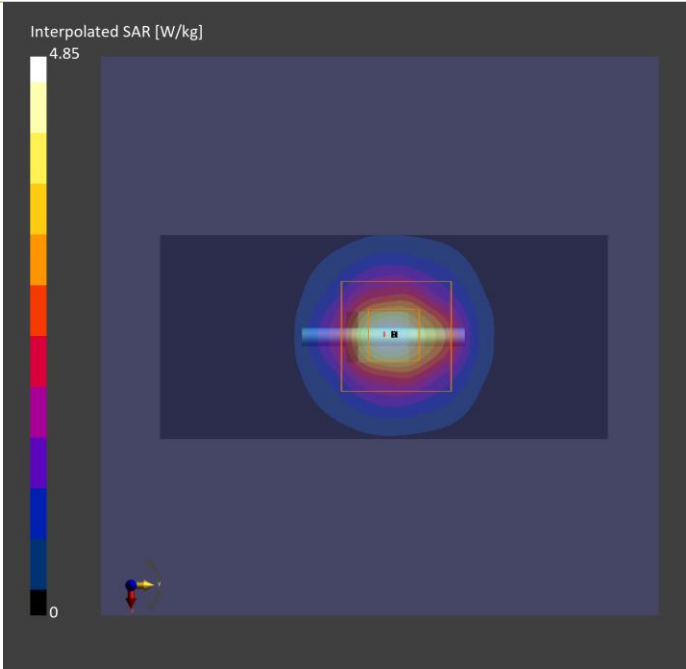
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-09	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-09	2024-05-09
psSAR1g [W/kg]	3.27	3.38
psSAR10g [W/kg]	1.15	1.24
Power Drift [dB]	0.01	0.03



Plots of System Verification

Measurement Report
S38a System Check H3500_240510
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.79	39.4

Hardware Setup

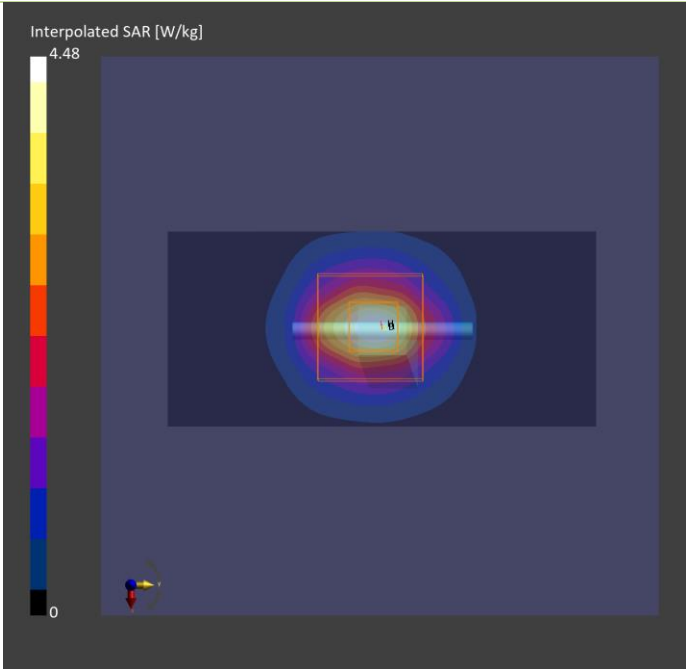
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-10	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-10	2024-05-10
psSAR1g [W/kg]	3.13	3.21
psSAR10g [W/kg]	1.18	1.26
Power Drift [dB]	0.03	0.02



Plots of System Verification

Measurement Report S38b System Check H3700_240510

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.97	39.2

Hardware Setup

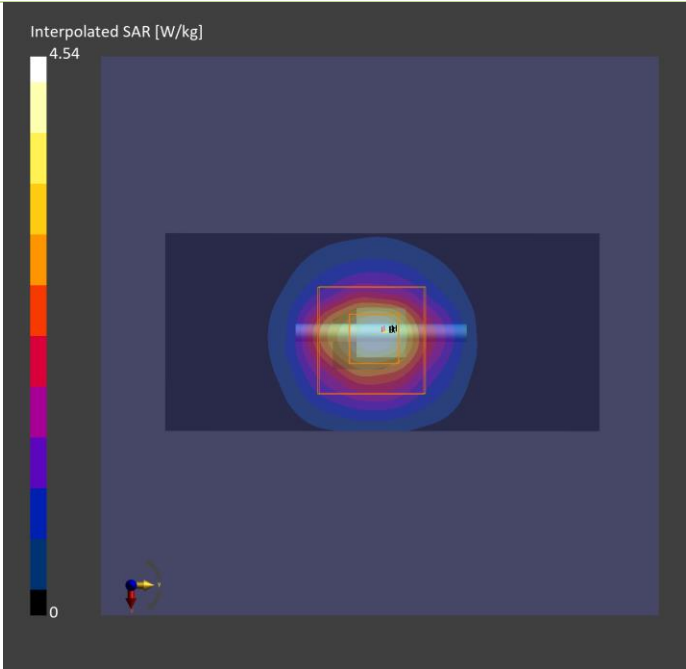
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-10	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-10	2024-05-10
psSAR1g [W/kg]	3.14	3.22
psSAR10g [W/kg]	1.17	1.23
Power Drift [dB]	0.03	0.01



Plots of System Verification

Measurement Report
S40 System Check H2450_240428
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2450

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2450.000, 0	7.65	1.83	39.7

Hardware Setup

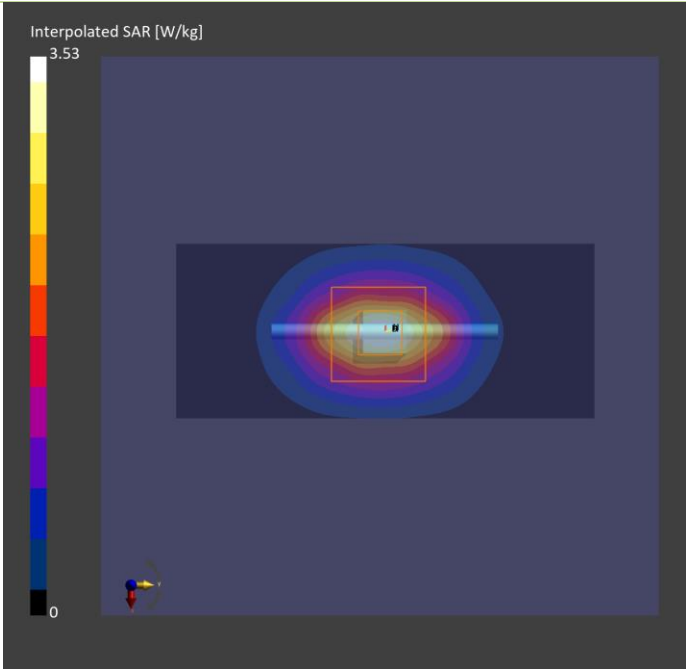
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-28	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-28	2024-04-28
psSAR1g [W/kg]	2.67	2.66
psSAR10g [W/kg]	1.22	1.22
Power Drift [dB]	-0.02	-0.11



Plots of System Verification

Measurement Report
S41 System Check H5250_240427
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		5250

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5250.000, 0	5.52	4.64	37.3

Hardware Setup

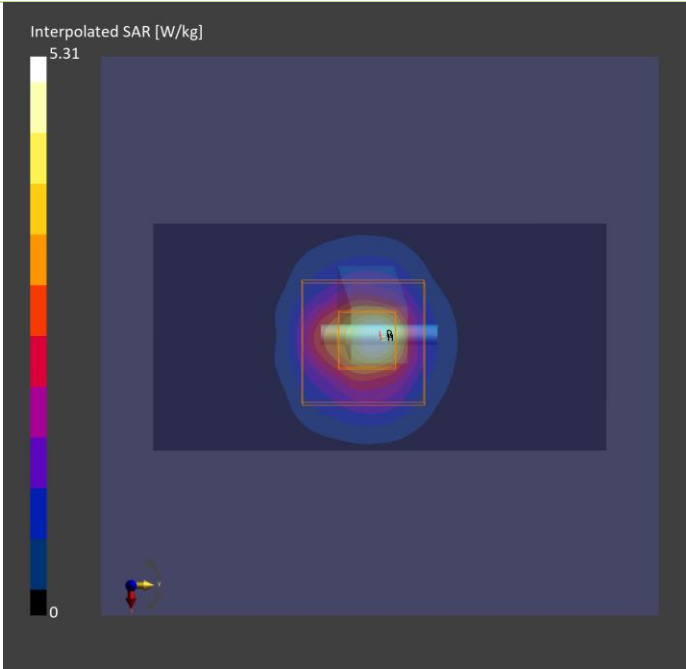
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-27	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-27	2024-04-27
psSAR1g [W/kg]	3.36	3.62
psSAR10g [W/kg]	0.978	1.06
Power Drift [dB]	-0.01	-0.11



Plots of System Verification

Measurement Report S42 System Check H5600_240427 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		5600

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5600.000, 0	4.8	4.97	35.2

Hardware Setup

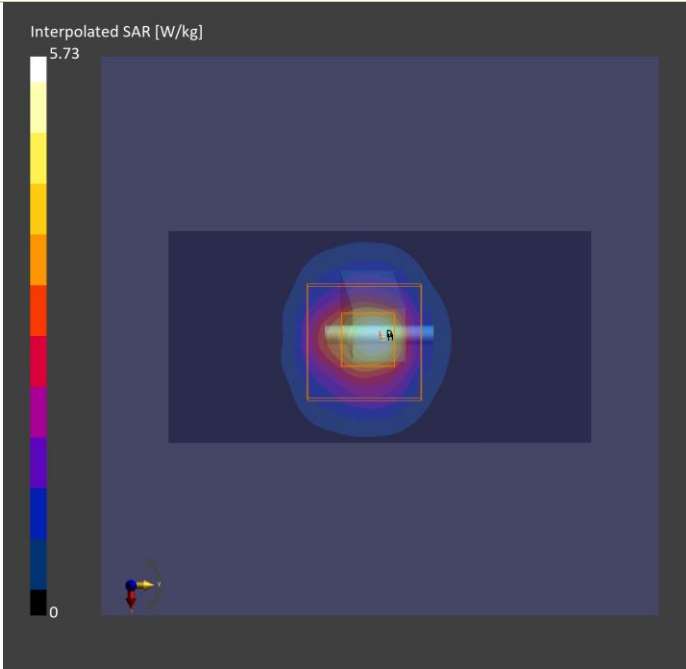
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-27	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-27	2024-04-27
psSAR1g [W/kg]	3.68	3.93
psSAR10g [W/kg]	1.06	1.10
Power Drift [dB]	-0.00	-0.11



Plots of System Verification

Measurement Report
S43 System Check H5750_240427
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		5750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5750.000, 0	4.96	5.14	35.0

Hardware Setup

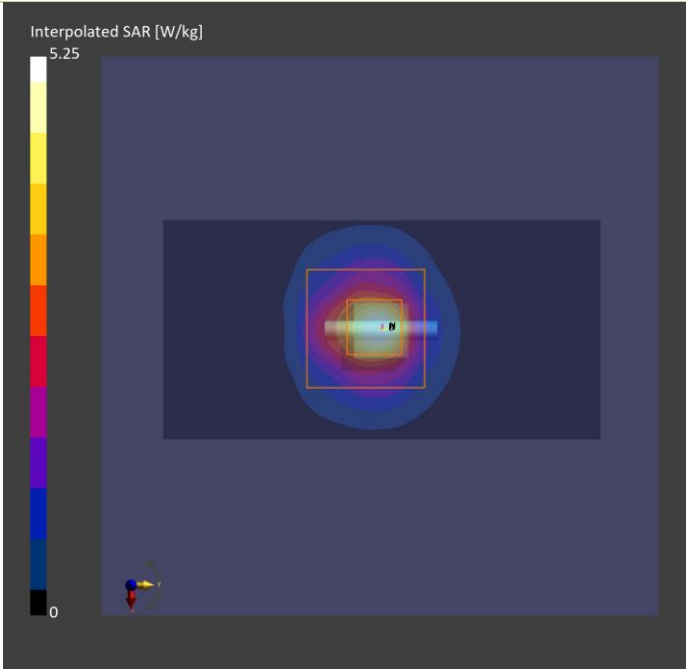
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-27	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-27	2024-04-27
psSAR1g [W/kg]	3.32	3.60
psSAR10g [W/kg]	0.945	1.01
Power Drift [dB]	-0.03	-0.12



Plots of System Verification

Measurement Report S44 System Check H2450_240428 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2450

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2450.000, 0	7.65	1.83	39.7

Hardware Setup

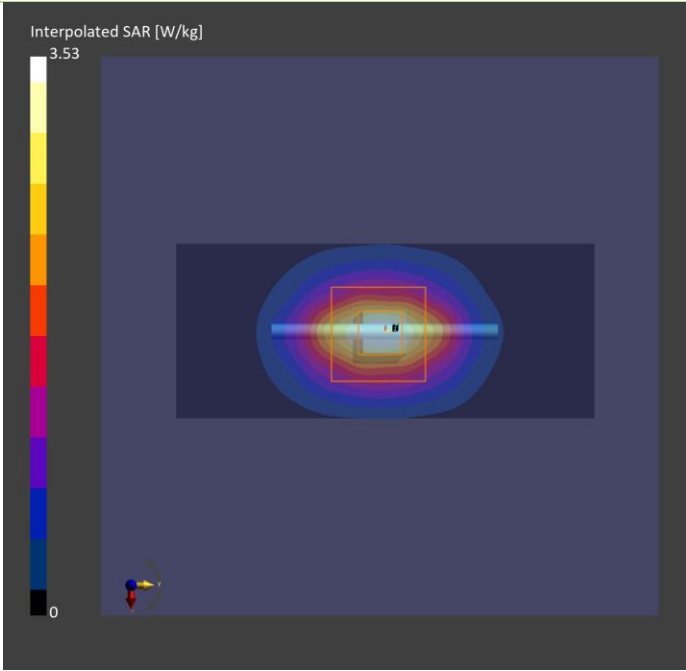
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-28	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-28	2024-04-28
psSAR1g [W/kg]	2.67	2.66
psSAR10g [W/kg]	1.22	1.22
Power Drift [dB]	-0.02	-0.11



Plots of System Verification

Measurement Report

S137 System Check H6.5GHz_240429

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		6500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	,		, 0--	6500.0, 0	5.4	5.95	35.2

Hardware Setup

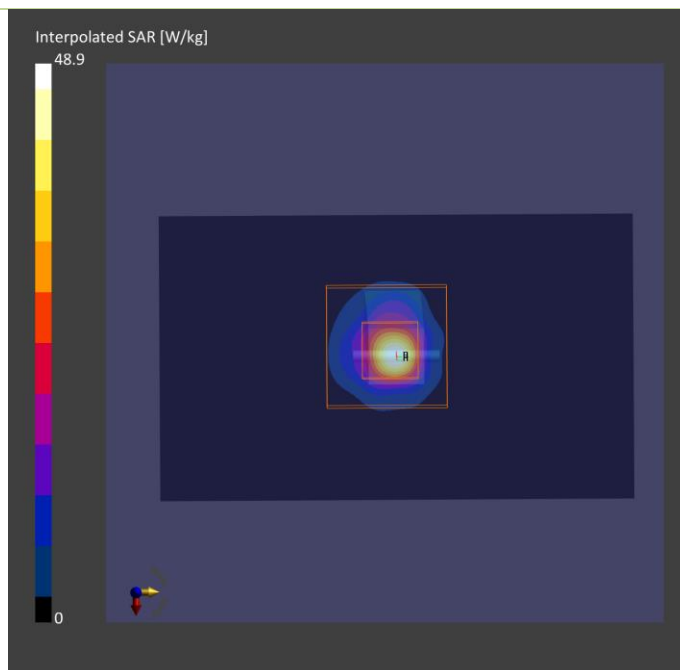
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-29	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	7.5 x 7.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2023-04-29	2023-04-29
psSAR1g [W/kg]	25.5	29.9
psSAR10g [W/kg]	5.03	5.48
psPDab (1.0cm2, sq) [W/m2]		299
psPDab (4.0cm2, sq) [W/m2]		134
Power Drift [dB]	0.01	-0.03



Plots of System Verification

Measurement Report

S137 PD_System Check_10 GHz_240515

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
SPEAG, 5G Verification Source 10 GHz	100.0 x 100.0 x 170.0	SN: 1025	

Exposure Conditions

Phantom Section	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor
5G Air	Front Face 10.00	Validation band	CW, 0--	10000.0, 10000	1.0

Hardware Setup

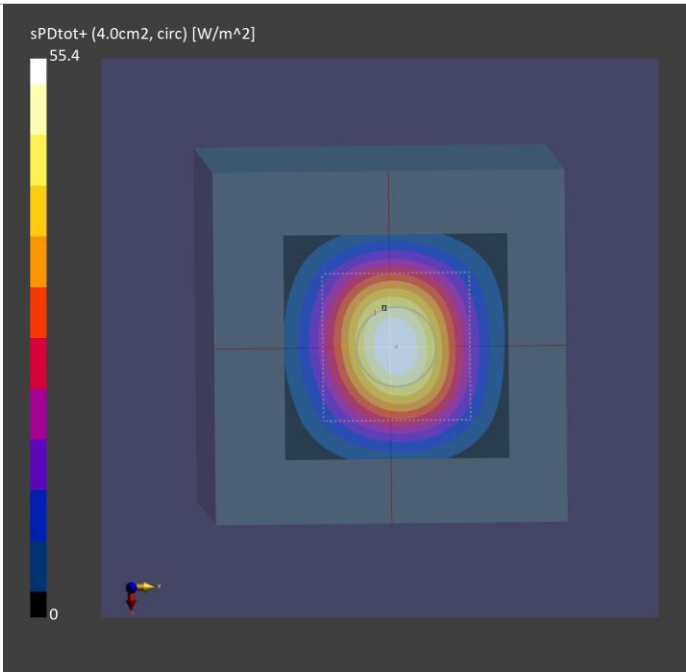
Phantom	Medium	Probe, Calibration Date	DAE, Calibration Date
mmWave- 1029	---Air	EUmmWV4 - SN9615_F1-55GHz, 2023-07-10	DAE4 Sn1431, 2023-08-24

Scan Setup

	5G Scan
Grid Extents [mm]	60.0 x 60.0
Grid Steps [lambda]	0.125 x 0.125
Sensor Surface [mm]	10.0

Measurement Results

	5G Scan
Date	2024-05-15
Avg. Area [cm ²]	4.00
psPDn+ [W/m ²]	55.0
psPDtot+ [W/m ²]	55.4
psPDmod+ [W/m ²]	55.5
E _{max} [V/m]	151
Power Drift [dB]	-0.08





Plots of System Verification

Measurement Report S45 System Check H835_240506

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.86	42.6

Hardware Setup

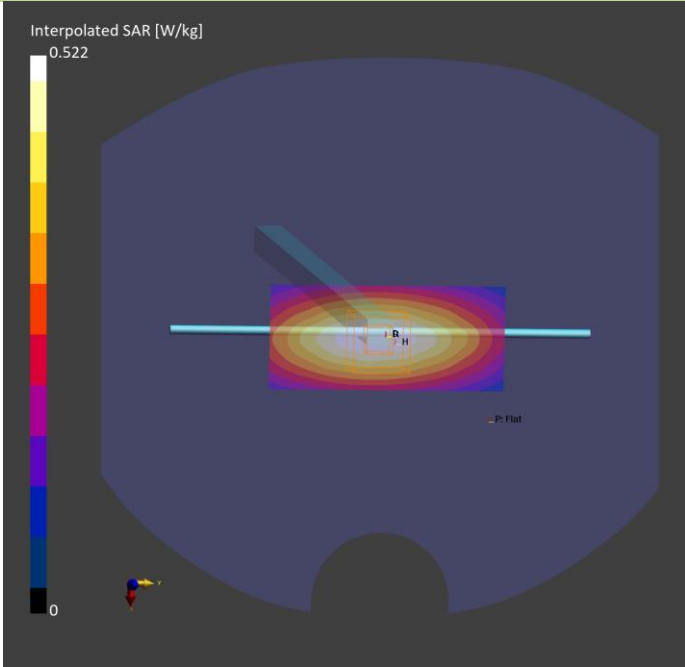
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-06	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-06	2024-05-06
psSAR1g [W/kg]	0.453	0.456
psSAR10g [W/kg]	0.299	0.300
Power Drift [dB]	-0.02	0.03



Plots of System Verification

Measurement Report S46 System Check H1900_240506 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.35	40.8

Hardware Setup

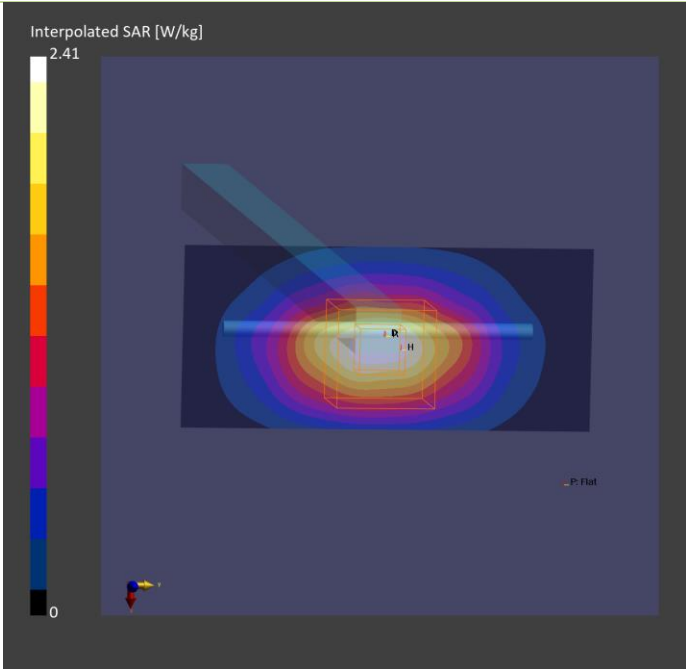
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-06	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-06	2024-05-06
psSAR1g [W/kg]	1.94	1.96
psSAR10g [W/kg]	1.02	1.04
Power Drift [dB]	0.01	0.02



Plots of System Verification

Measurement Report
S47 System Check H1900_240508
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.42	41.1

Hardware Setup

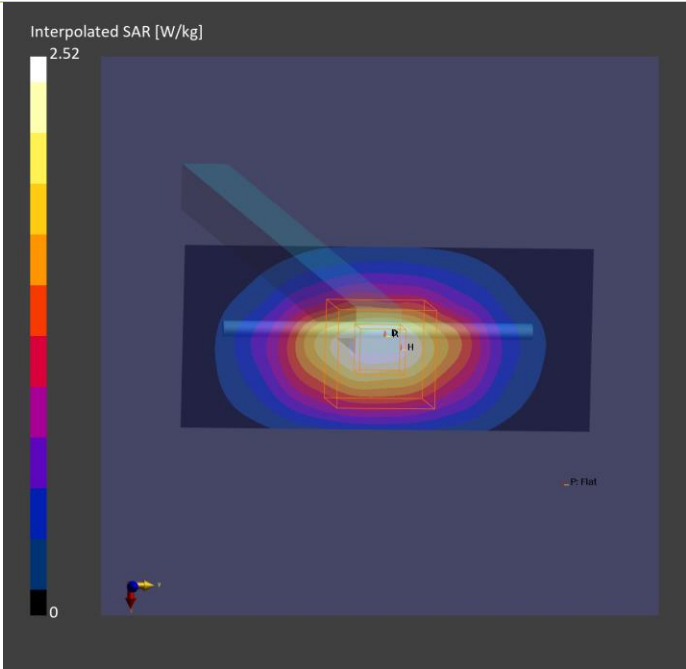
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-08	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-08	2024-05-08
psSAR1g [W/kg]	2.03	2.06
psSAR10g [W/kg]	1.07	1.09
Power Drift [dB]	0.02	0.02



Plots of System Verification

Measurement Report
S48 System Check H1750_240508
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	8.74	1.34	41.3

Hardware Setup

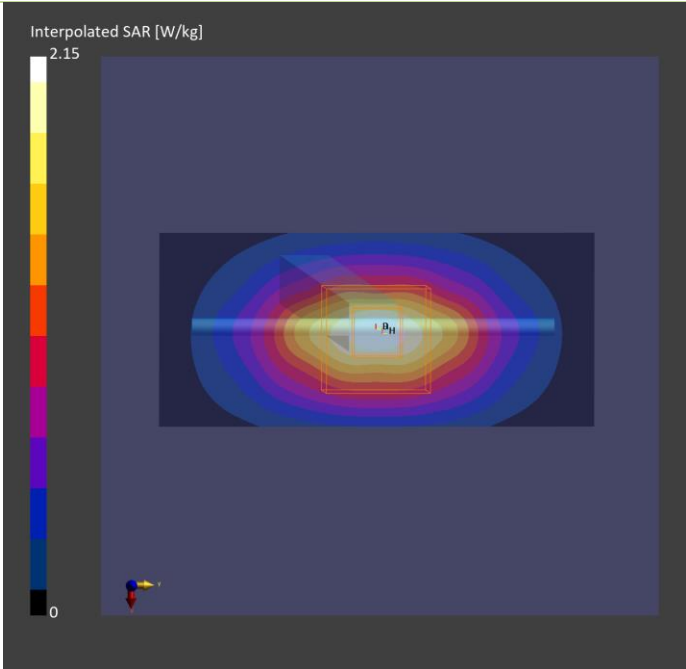
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-08	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-08	2024-05-08
psSAR1g [W/kg]	1.72	1.80
psSAR10g [W/kg]	0.913	0.979
Power Drift [dB]	0.10	0.13



Plots of System Verification

Measurement Report S49 System Check H835_240508

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.93	43.1

Hardware Setup

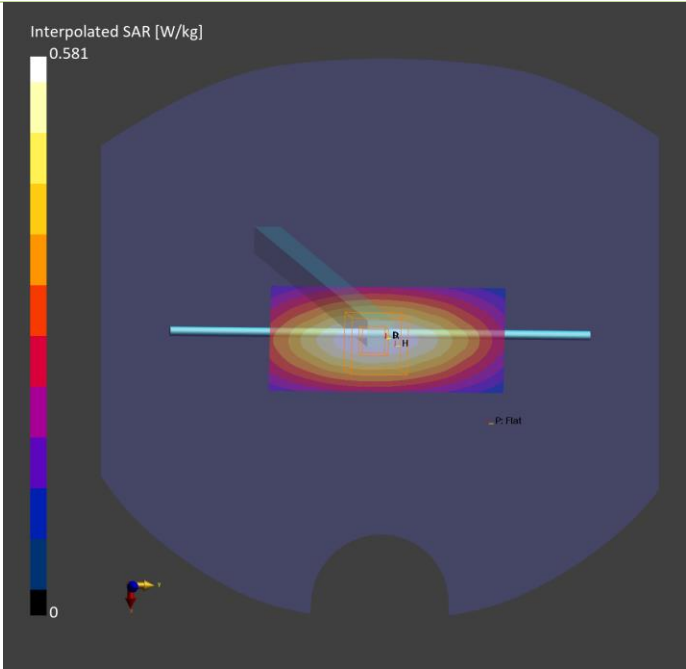
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-08	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-08	2024-05-08
psSAR1g [W/kg]	0.506	0.500
psSAR10g [W/kg]	0.334	0.330
Power Drift [dB]	-0.02	-0.05



Plots of System Verification

Measurement Report
S50 System Check H1900_240511
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.45	38.2

Hardware Setup

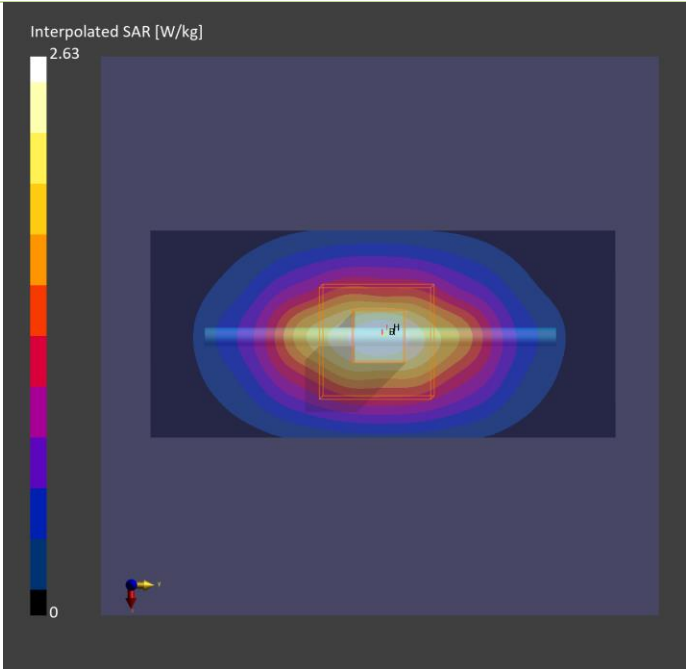
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-11	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-11	2024-05-11
psSAR1g [W/kg]	2.08	2.10
psSAR10g [W/kg]	1.08	1.11
Power Drift [dB]	0.02	0.01



Plots of System Verification

Measurement Report
S51 System Check H1750_240511
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	8.74	1.38	38.4

Hardware Setup

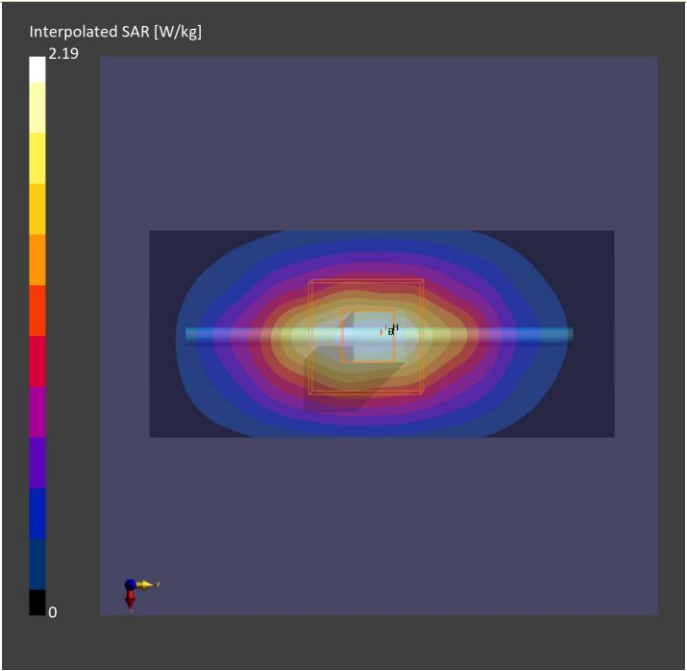
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-11	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-11	2024-05-11
psSAR1g [W/kg]	1.77	1.78
psSAR10g [W/kg]	0.940	0.959
Power Drift [dB]	0.04	0.06



Plots of System Verification

Measurement Report
S52 System Check H835_240512
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		835

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.94	43.3

Hardware Setup

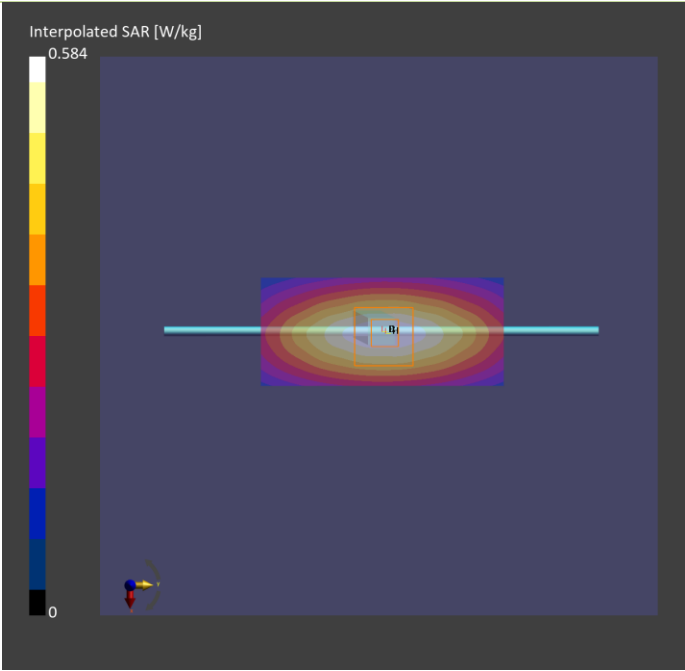
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.507	0.506
psSAR10g [W/kg]	0.334	0.333
Power Drift [dB]	-0.01	0.05



Plots of System Verification

Measurement Report
S53 System Check H2600_240516
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	2.01	37.1

Hardware Setup

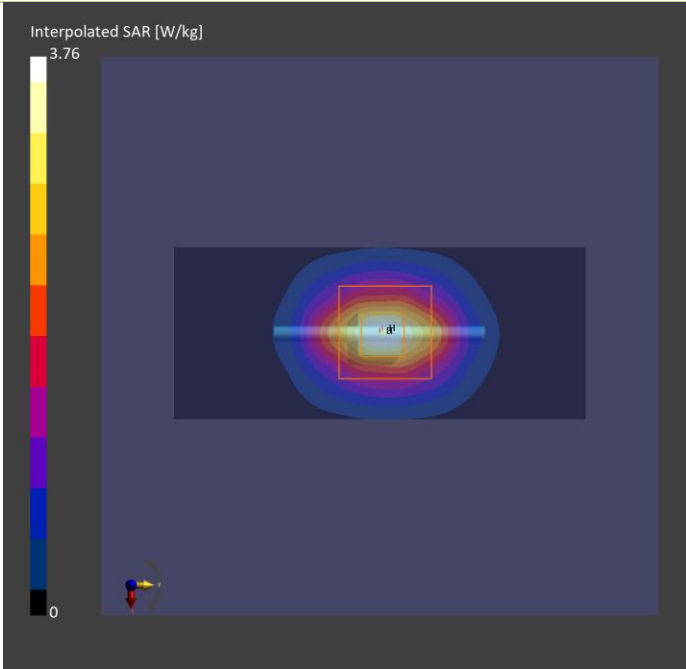
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	2.79	2.74
psSAR10g [W/kg]	1.23	1.23
Power Drift [dB]	0.01	0.01



Plots of System Verification

Measurement Report S54 System Check H750_240512 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.94	43.3

Hardware Setup

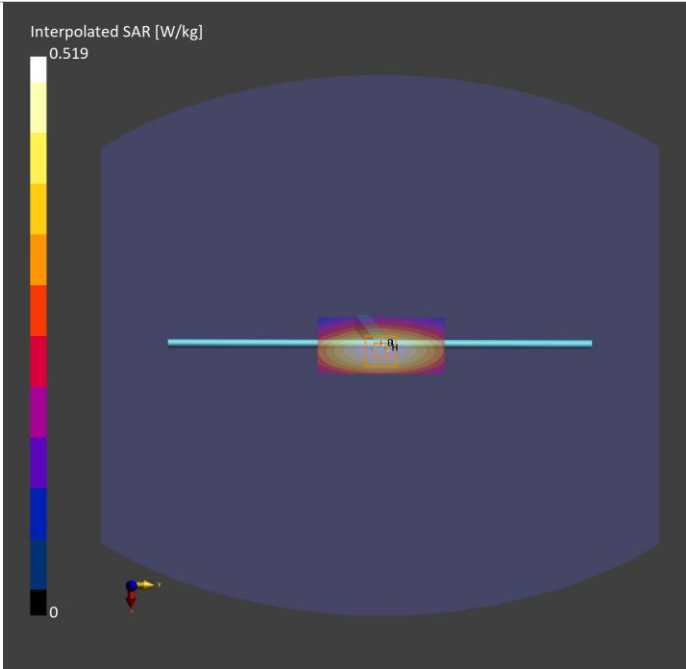
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.455	0.454
psSAR10g [W/kg]	0.307	0.301
Power Drift [dB]	-0.02	-0.01



Plots of System Verification

Measurement Report S55 System Check H750_240512

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.94	43.3

Hardware Setup

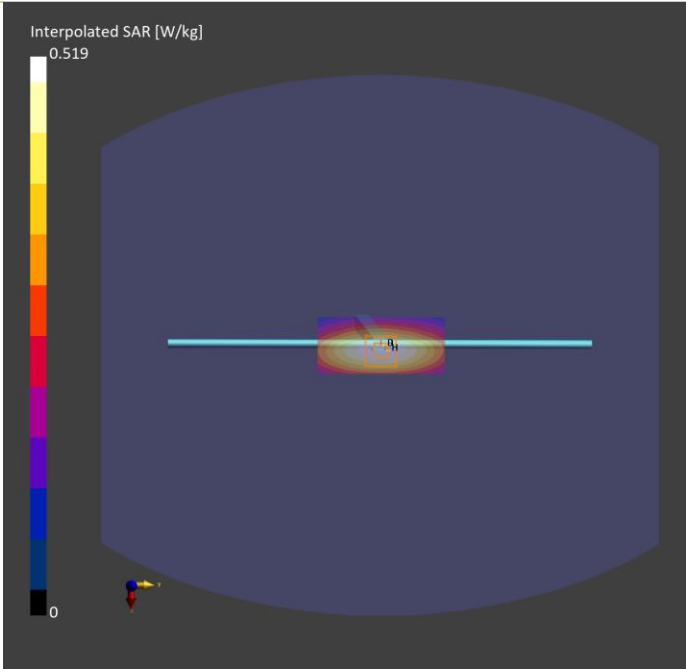
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.455	0.454
psSAR10g [W/kg]	0.307	0.301
Power Drift [dB]	-0.02	-0.01



Plots of System Verification

Measurement Report S56 System Check H750_240512

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.94	43.3

Hardware Setup

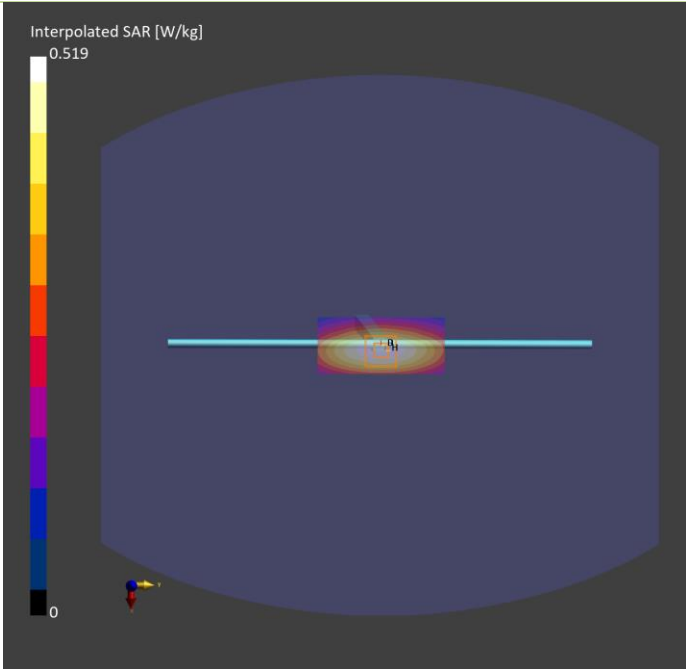
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.455	0.454
psSAR10g [W/kg]	0.307	0.301
Power Drift [dB]	-0.02	-0.01



Plots of System Verification

Measurement Report S57 System Check H750_240512

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.94	43.3

Hardware Setup

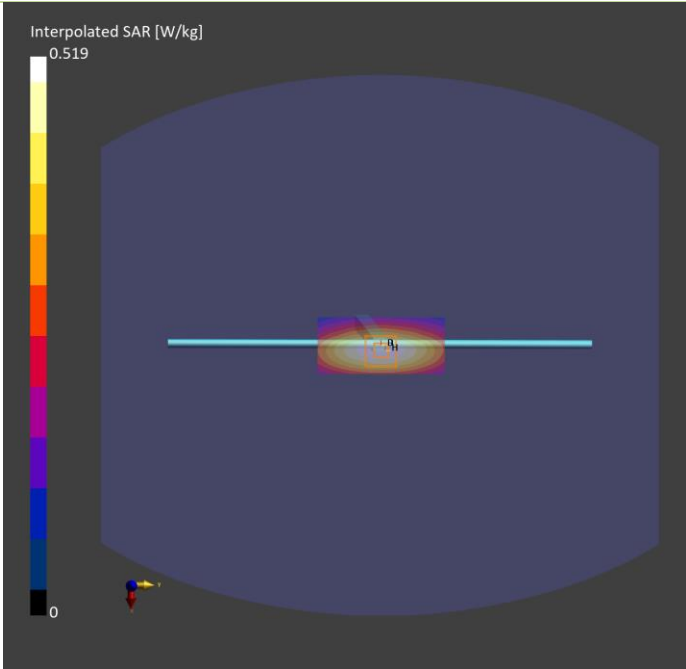
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.455	0.454
psSAR10g [W/kg]	0.307	0.301
Power Drift [dB]	-0.02	-0.01



Plots of System Verification

Measurement Report
S58 System Check H1900_240511
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.45	38.2

Hardware Setup

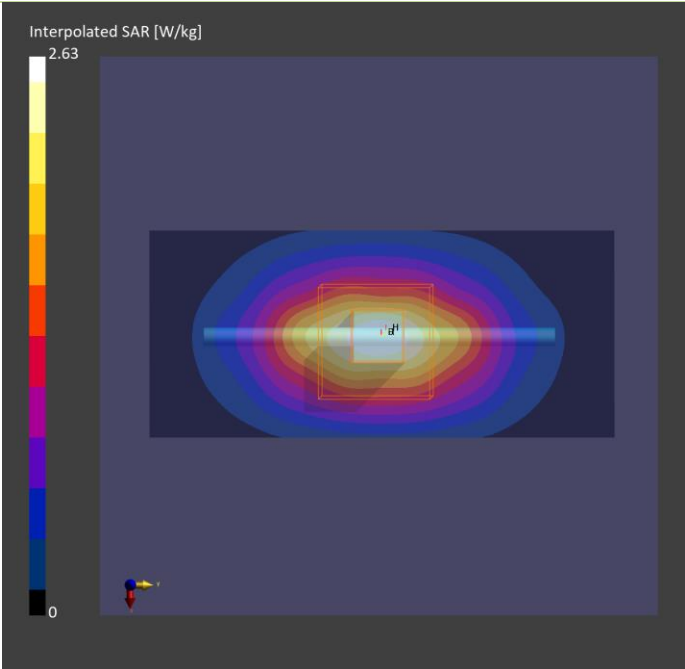
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-11	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-11	2024-05-11
psSAR1g [W/kg]	2.08	2.10
psSAR10g [W/kg]	1.08	1.11
Power Drift [dB]	0.02	0.01





Plots of System Verification

Measurement Report S59 System Check H835_240513

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.87	42.8

Hardware Setup

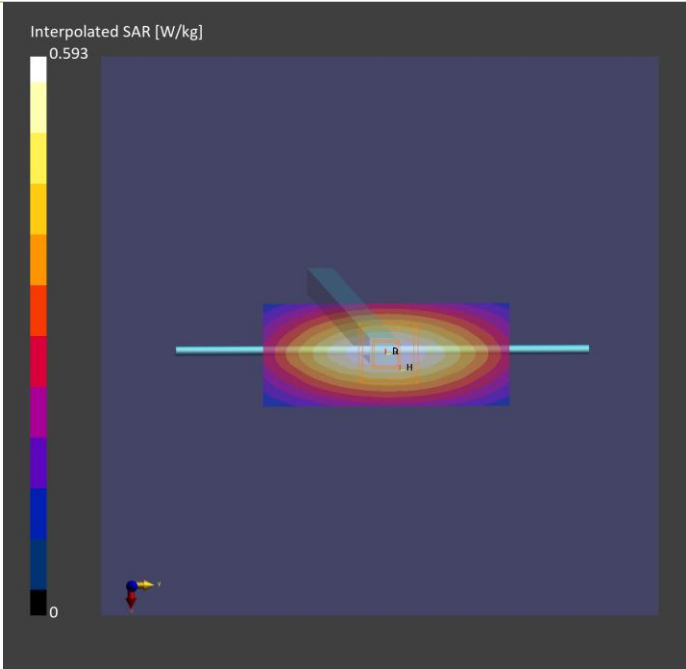
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-13	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-13	2024-05-13
psSAR1g [W/kg]	0.511	0.508
psSAR10g [W/kg]	0.333	0.335
Power Drift [dB]	0.01	0.05



Plots of System Verification

Measurement Report
S60 System Check H2300_240516
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2300.000, 0	7.95	1.75	37.6

Hardware Setup

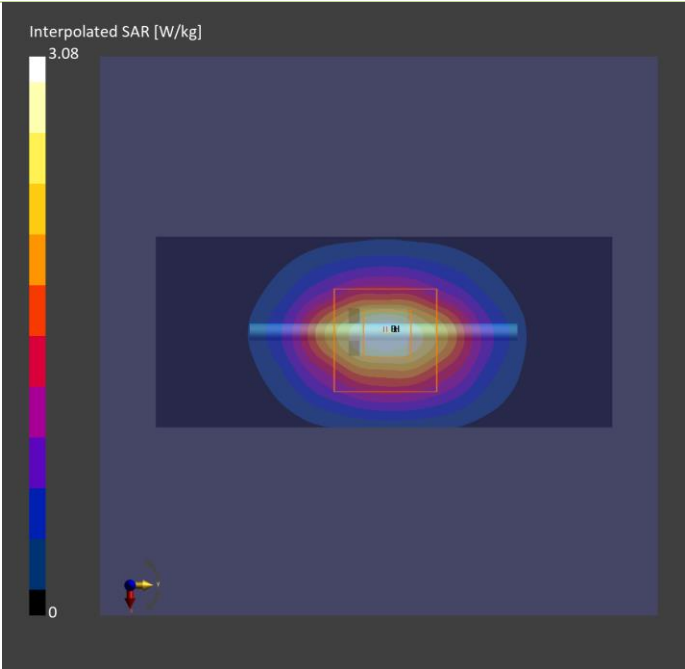
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	2.35	2.33
psSAR10g [W/kg]	1.12	1.11
Power Drift [dB]	0.02	0.01



Plots of System Verification

Measurement Report
S61 System Check H2600_240516
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	2.01	37.1

Hardware Setup

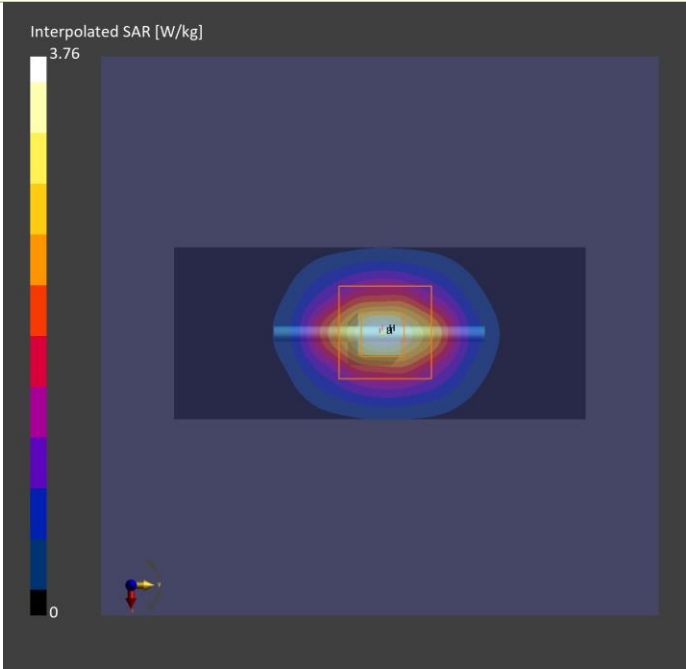
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	2.79	2.74
psSAR10g [W/kg]	1.23	1.23
Power Drift [dB]	0.01	0.01



Plots of System Verification

Measurement Report S62 System Check H2600_240516 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	2.01	37.1

Hardware Setup

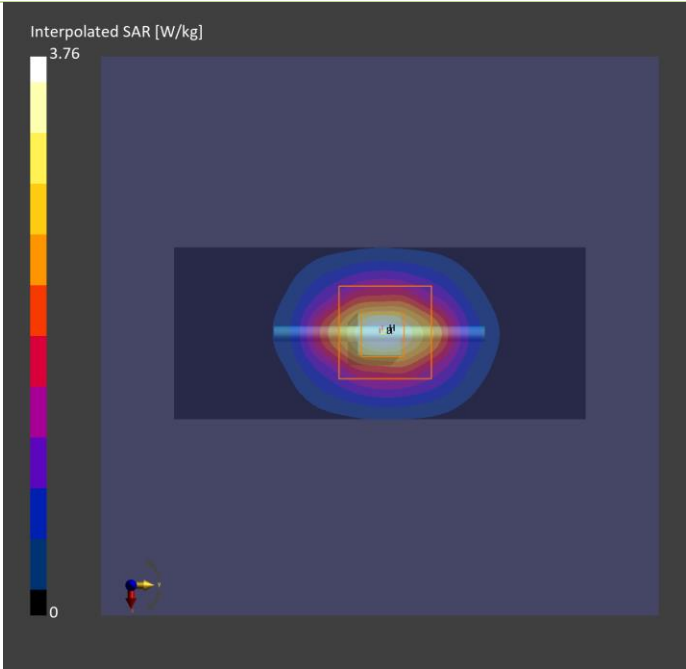
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	2.79	2.74
psSAR10g [W/kg]	1.23	1.23
Power Drift [dB]	0.01	0.01





Plots of System Verification

Measurement Report
S63 System Check H3500_2400513
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.79	39.4

Hardware Setup

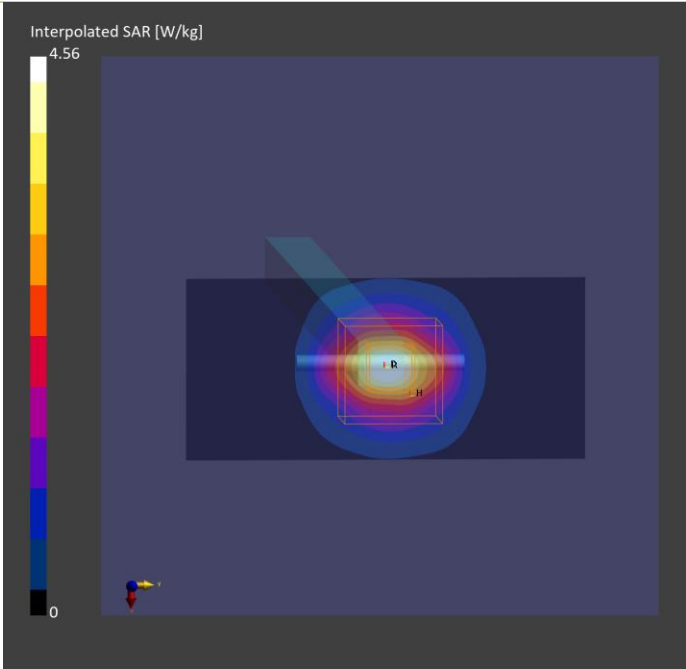
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-13	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-13	2024-05-13
psSAR1g [W/kg]	3.15	3.12
psSAR10g [W/kg]	1.19	1.20
Power Drift [dB]	-0.01	-0.01



Plots of System Verification

Measurement Report
S64 System Check H3700_2400513
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.97	39.1

Hardware Setup

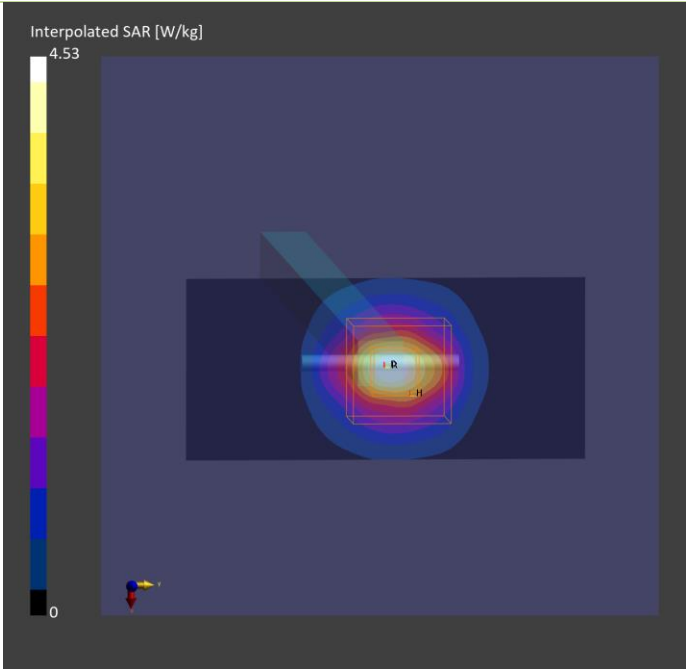
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-13	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-13	2024-05-13
psSAR1g [W/kg]	3.11	3.11
psSAR10g [W/kg]	1.15	1.16
Power Drift [dB]	-0.02	-0.00



Plots of System Verification

Measurement Report
S65a System Check H3500_240515
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.83	39.4

Hardware Setup

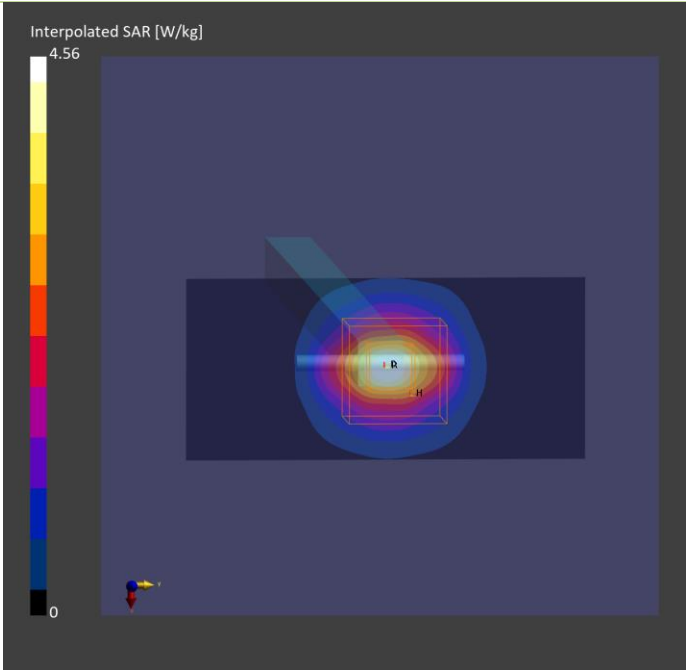
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-15	2024-05-15
psSAR1g [W/kg]	3.16	3.15
psSAR10g [W/kg]	1.19	1.22
Power Drift [dB]	0.01	-0.01



Plots of System Verification

Measurement Report
S65b System Check H3700_240515
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	3.01	39.3

Hardware Setup

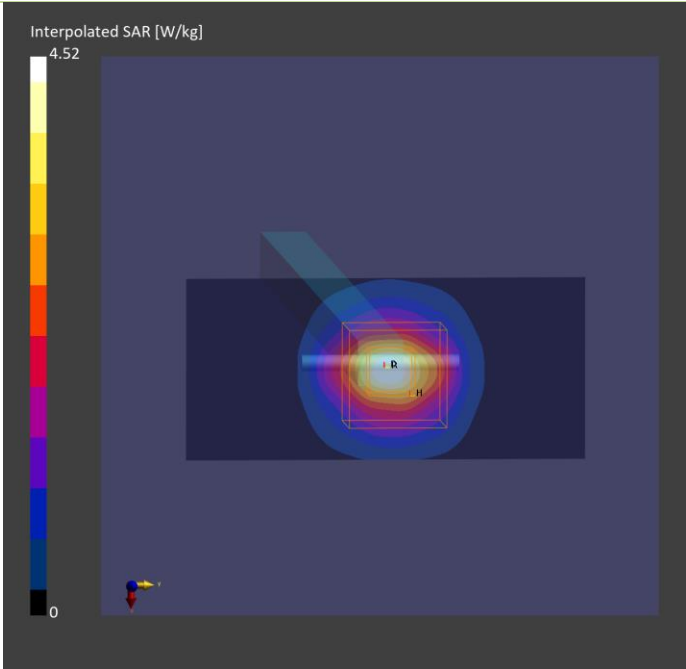
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-15	2024-05-15
psSAR1g [W/kg]	3.11	3.10
psSAR10g [W/kg]	1.15	1.15
Power Drift [dB]	0.01	0.00



Plots of System Verification

Measurement Report
S66 System Check H1750_240515
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	8.74	1.41	42.1

Hardware Setup

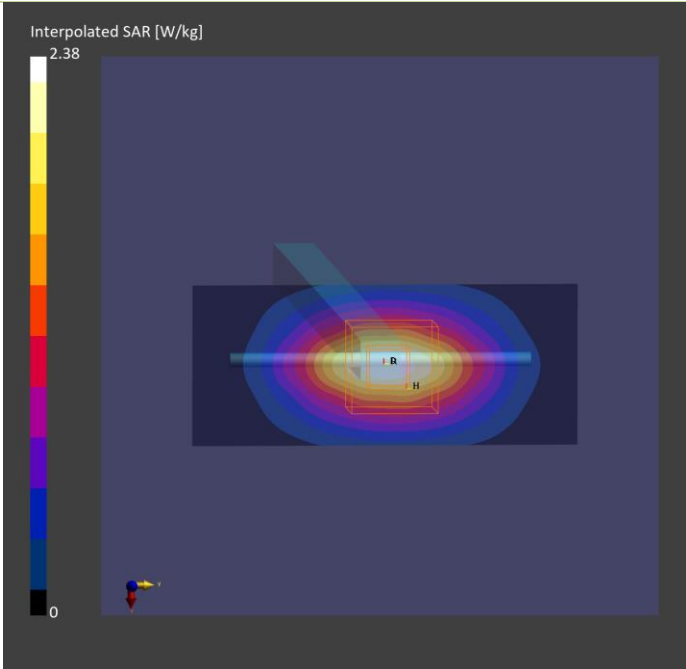
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-15	2024-05-15
psSAR1g [W/kg]	1.83	1.84
psSAR10g [W/kg]	0.97	0.962
Power Drift [dB]	0.00	0.01



Plots of System Verification

Measurement Report S67 System Check H750_240515

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.89	43.9

Hardware Setup

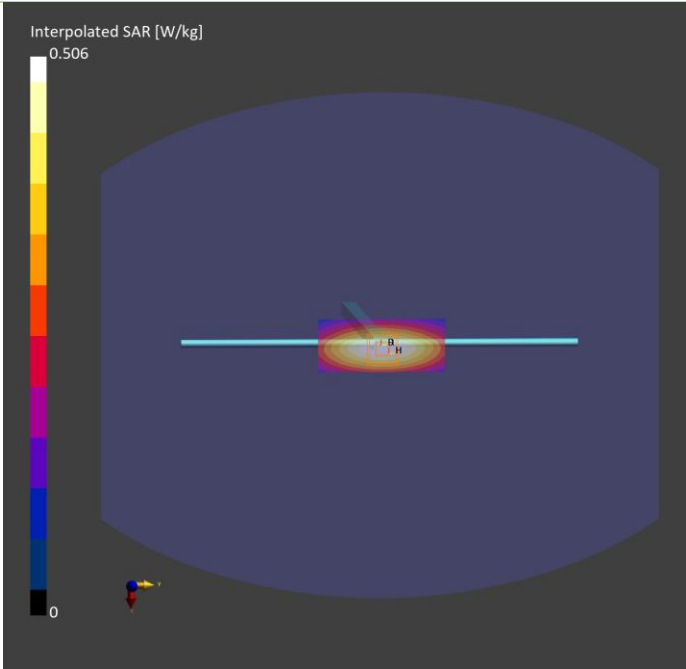
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-15	2024-05-15
psSAR1g [W/kg]	0.441	0.438
psSAR10g [W/kg]	0.298	0.291
Power Drift [dB]	0.00	0.05



Plots of System Verification

Measurement Report
S68 System Check H1900_240519
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.45	38.5

Hardware Setup

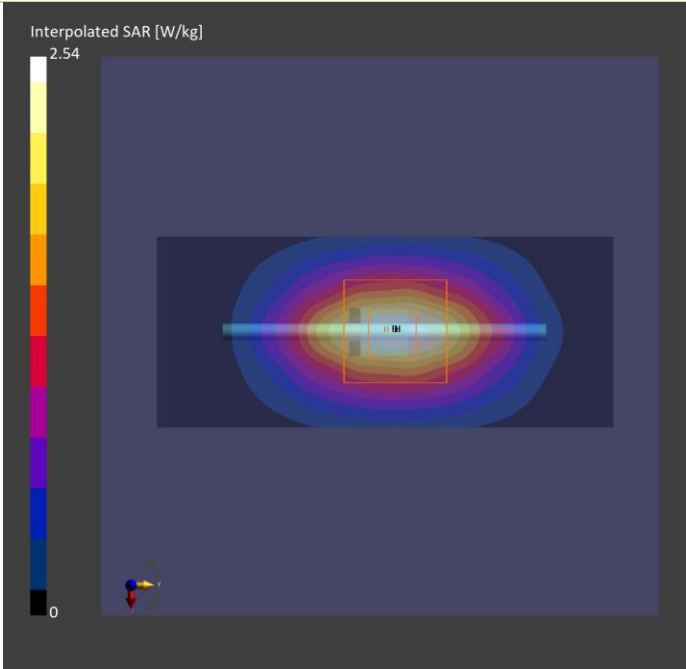
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-19	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-19	2024-05-19
psSAR1g [W/kg]	2.02	1.98
psSAR10g [W/kg]	1.04	1.03
Power Drift [dB]	-0.01	0.02



Plots of System Verification

Measurement Report S69 System Check H835_240519

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.000, 0	10.39	0.93	42.9

Hardware Setup

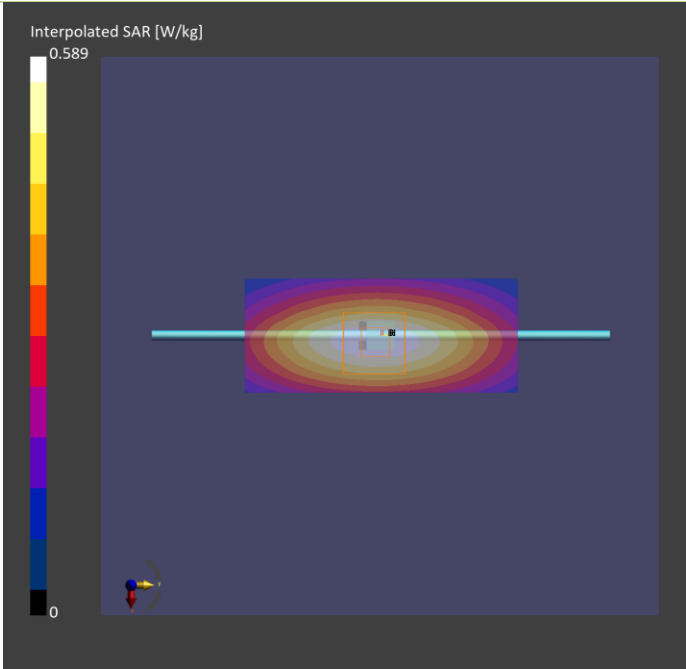
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-19	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-19	2024-05-19
psSAR1g [W/kg]	0.510	0.508
psSAR10g [W/kg]	0.337	0.334
Power Drift [dB]	0.02	-0.01



Plots of System Verification

Measurement Report S70 System Check H2600_240520 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2600

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.96	37.5

Hardware Setup

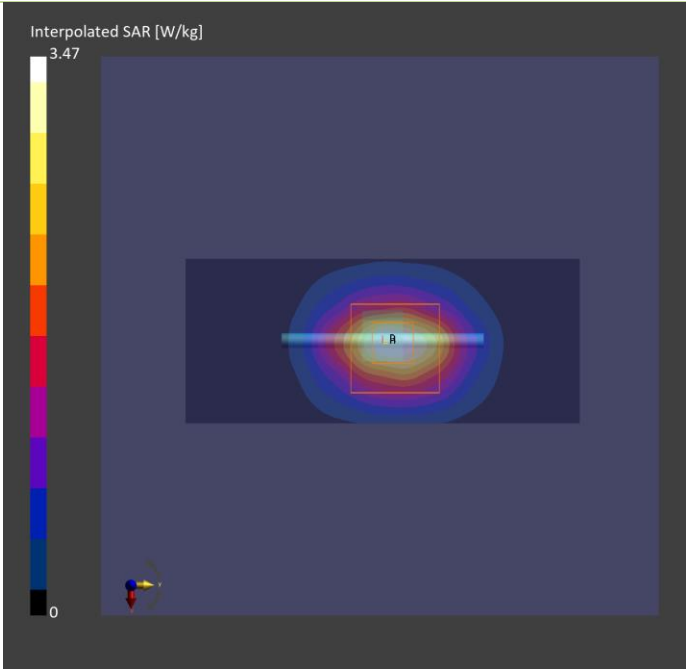
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-20	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-20	2024-05-20
psSAR1g [W/kg]	2.61	2.60
psSAR10g [W/kg]	1.17	1.16
Power Drift [dB]	-0.00	-0.01





Plots of System Verification

Measurement Report S71 System Check H750_240519

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.89	43.2

Hardware Setup

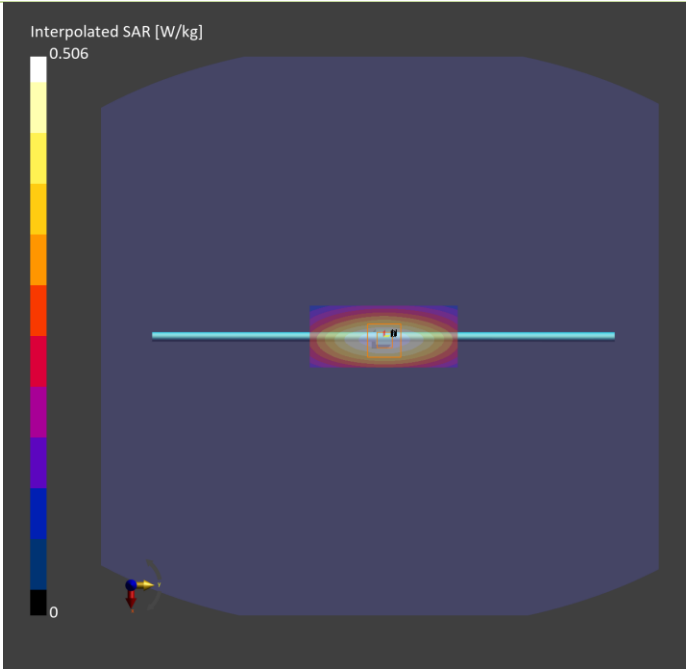
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-19	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-19	2024-05-19
psSAR1g [W/kg]	0.439	0.436
psSAR10g [W/kg]	0.294	0.289
Power Drift [dB]	0.02	0.01





Plots of System Verification

Measurement Report S72 System Check H750_240519

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.89	43.2

Hardware Setup

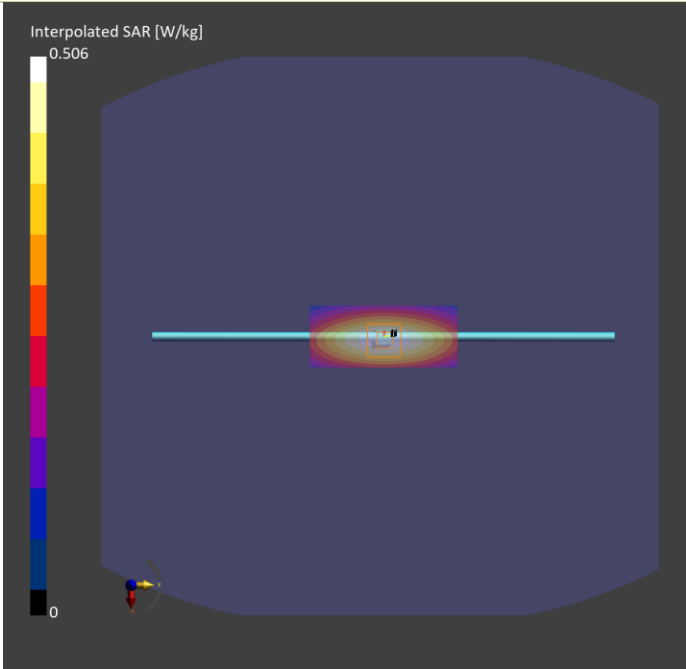
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-19	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-19	2024-05-19
psSAR1g [W/kg]	0.439	0.436
psSAR10g [W/kg]	0.294	0.289
Power Drift [dB]	0.02	0.01



Plots of System Verification

Measurement Report
S73 System Check H1900_240521
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1900

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.45	38.2

Hardware Setup

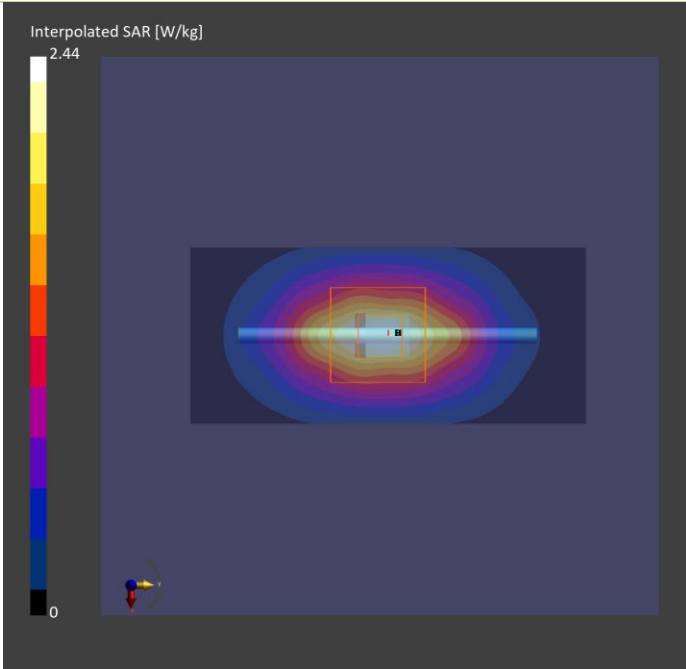
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-21	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-21	2024-05-21
psSAR1g [W/kg]	1.94	1.93
psSAR10g [W/kg]	0.998	1.02
Power Drift [dB]	0.01	0.01



Plots of System Verification

Measurement Report
S74 System Check_H835_240520
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Dipole,	10.0 x 10.0 x 300.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	835.0, 0	10.39	0.93	40.7

Hardware Setup

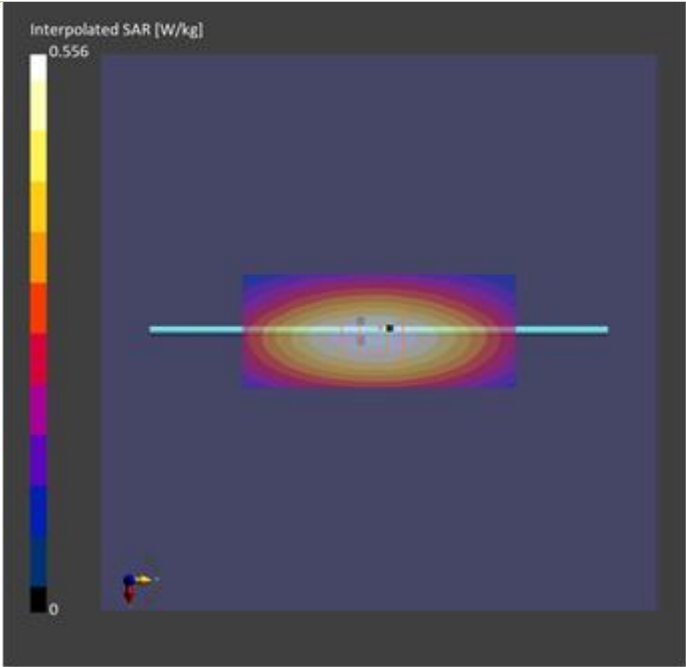
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-20	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-20	2024-05-20
psSAR1g [W/kg]	0.480	0.477
psSAR10g [W/kg]	0.316	0.313
Power Drift [dB]	0.01	0.07



Plots of System Verification

Measurement Report
S75 System Check_H2600_240522
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	10.0 x 10.0 x 300.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.93	37.1

Hardware Setup

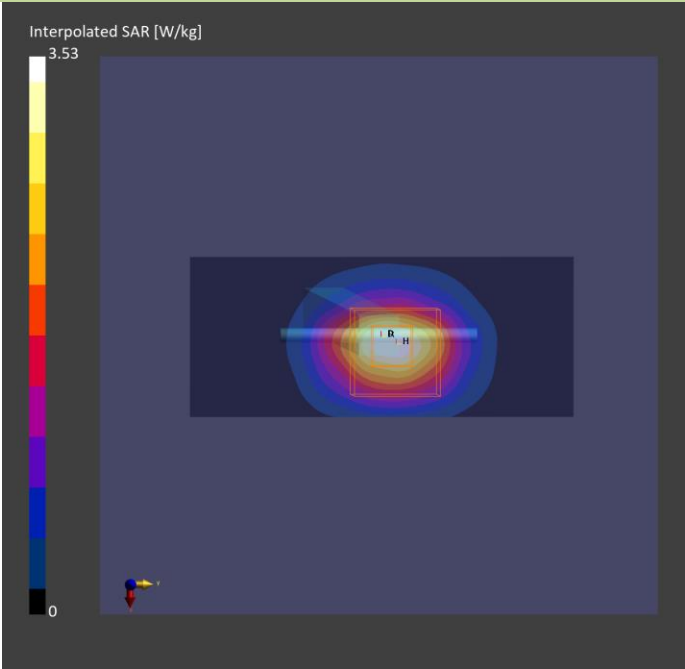
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	2.68	2.72
psSAR10g [W/kg]	1.22	1.22
Power Drift [dB]	0.00	-0.00



Plots of System Verification

Measurement Report

S76 System Check_H2600_240521

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Dipole	10.0 x 10.0 x 300.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat	,			2600.000,	7.58	1.93	37.1

Hardware Setup

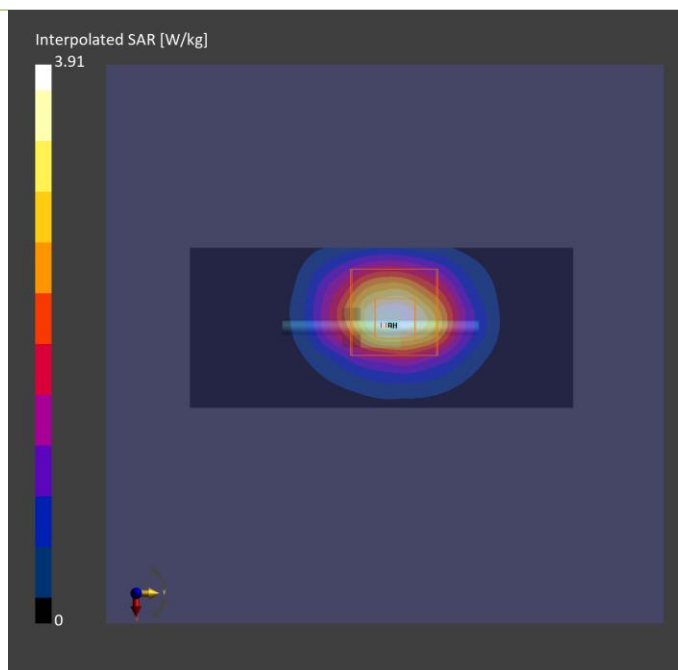
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-21	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-21	2024-05-21
psSAR1g [W/kg]	1.99	2.61
psSAR10g [W/kg]	1.38	1.36
Power Drift [dB]	-0.02	0.01



Plots of System Verification

Measurement Report
S77a System Check H3500_240522
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.80	39.5

Hardware Setup

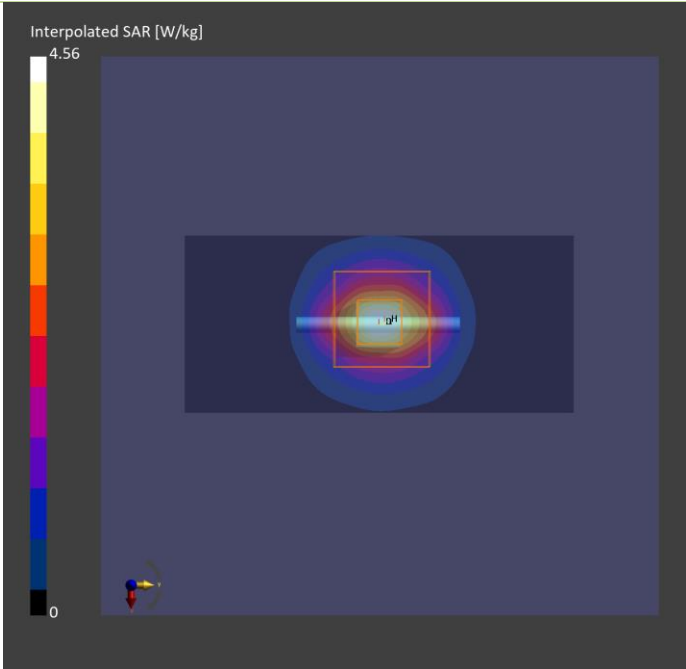
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	3.12	3.01
psSAR10g [W/kg]	1.17	1.12
Power Drift [dB]	0.01	-0.01





Plots of System Verification

Measurement Report
S77b System Check H3700_240522
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.99	39.2

Hardware Setup

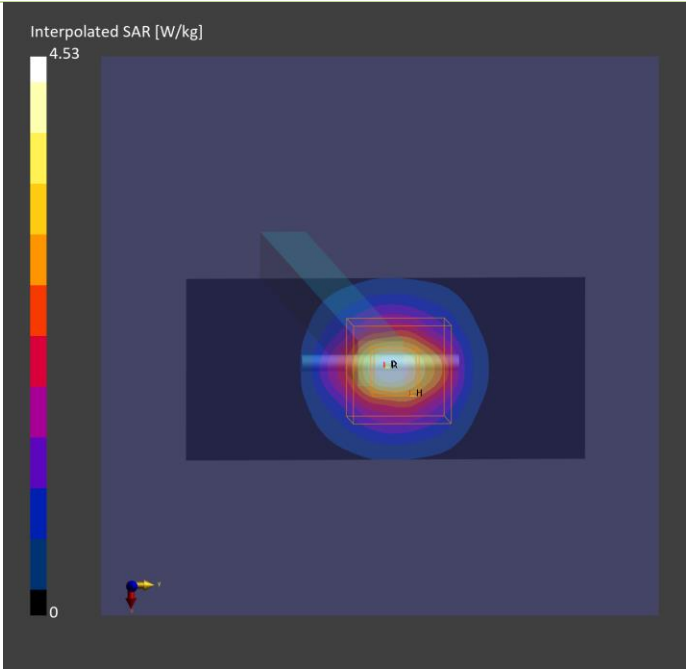
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	3.13	3.08
psSAR10g [W/kg]	1.11	1.14
Power Drift [dB]	-0.02	-0.01



Plots of System Verification

Measurement Report
S78 System Check H1750_240520
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1750.000, 0	8.74	1.37	38.8

Hardware Setup

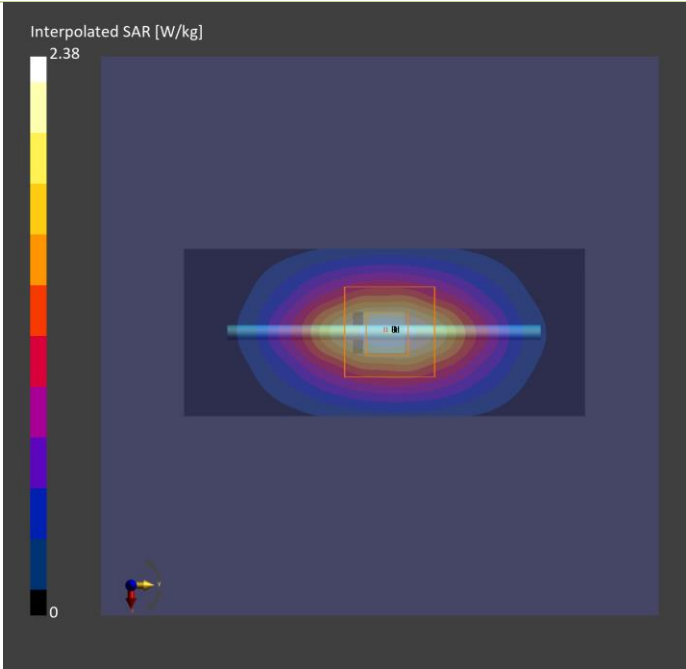
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-20	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-20	2024-05-20
psSAR1g [W/kg]	1.89	1.86
psSAR10g [W/kg]	1.00	0.985
Power Drift [dB]	0.00	0.00



Plots of System Verification

Measurement Report S79 System Check H750_240522

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.93	41.4

Hardware Setup

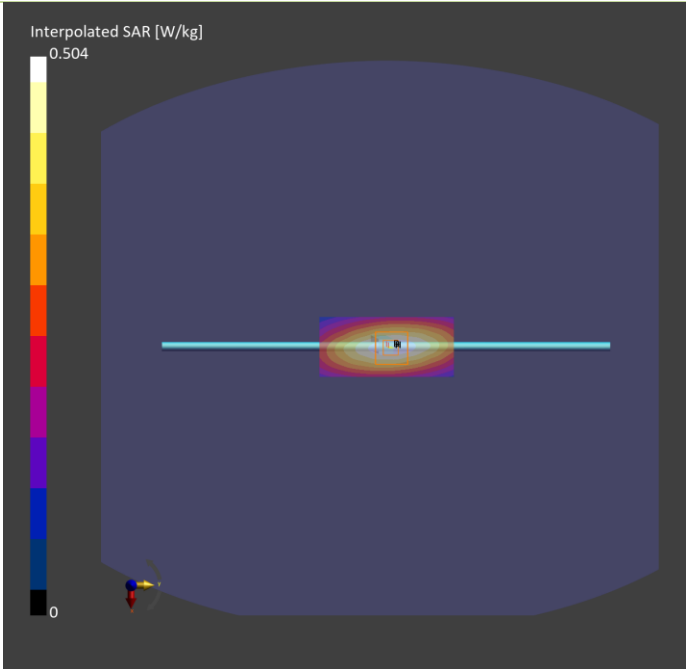
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	0.437	0.433
psSAR10g [W/kg]	0.290	0.286
Power Drift [dB]	-0.00	0.02



Plots of System Verification

Measurement Report
S80a System Check H3500_240524
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.79	39.4

Hardware Setup

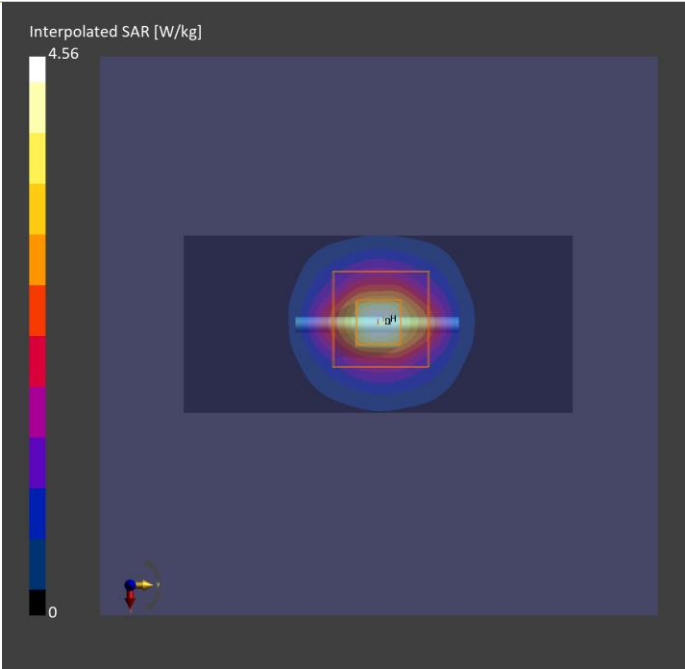
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-24	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-24	2024-05-24
psSAR1g [W/kg]	3.14	3.08
psSAR10g [W/kg]	1.17	1.16
Power Drift [dB]	0.01	-0.01



Plots of System Verification

Measurement Report
S80b System Check H3700_240524
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.97	39.1

Hardware Setup

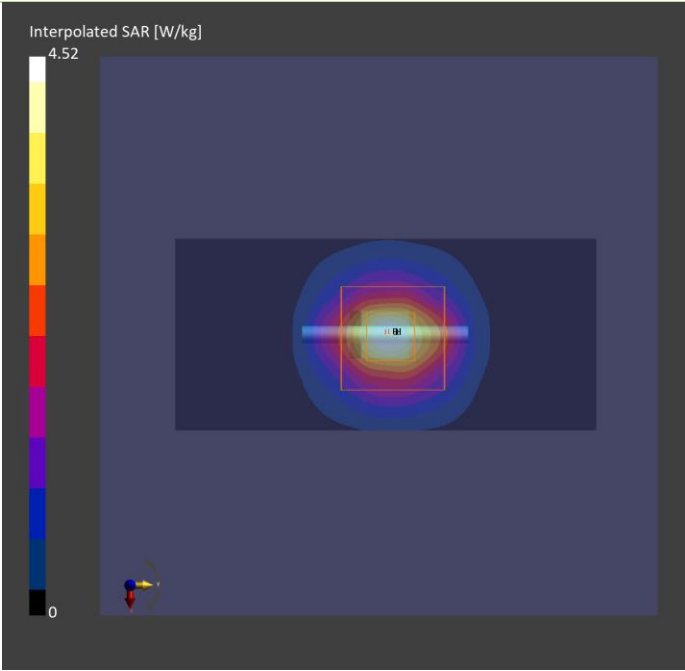
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-24	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-24	2024-05-24
psSAR1g [W/kg]	3.06	3.08
psSAR10g [W/kg]	1.14	1.14
Power Drift [dB]	0.01	0.00



Plots of System Verification

Measurement Report
S80c System Check H3900_240524
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	n/a x n/a x n/a		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	,		CW, 0--	3900.0, 0	6.53	3.17	38.8

Hardware Setup

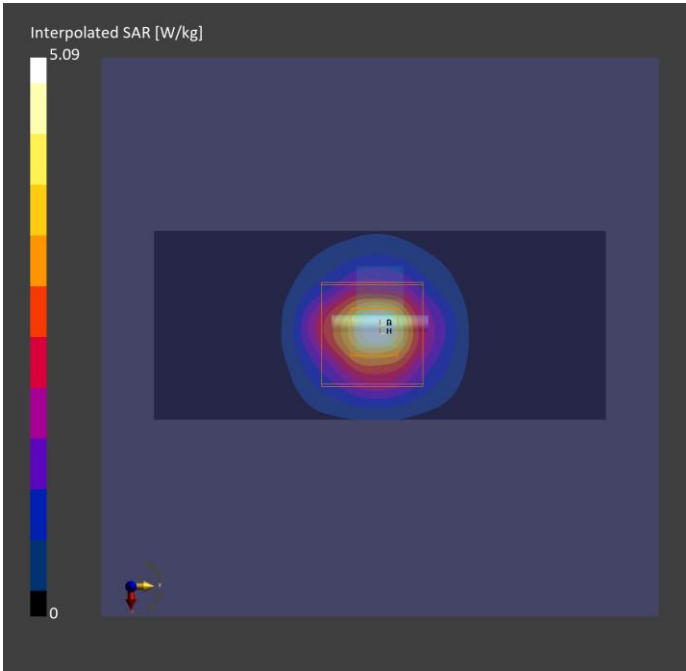
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-24	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-24	2024-05-24
psSAR1g [W/kg]	3.34	3.38
psSAR10g [W/kg]	1.19	1.21
Power Drift [dB]	0.02	-0.02



Plots of System Verification

Measurement Report
S82a System Check H3500_240524
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.79	39.4

Hardware Setup

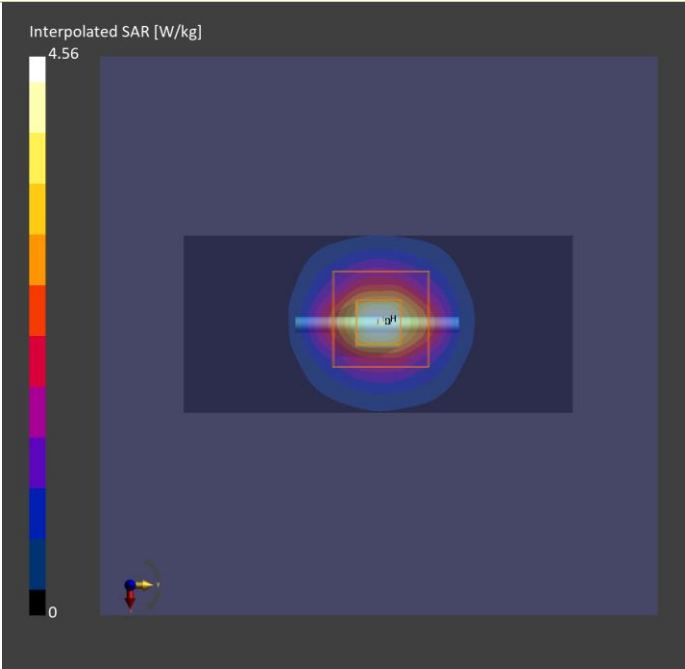
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-24	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-24	2024-05-24
psSAR1g [W/kg]	3.14	3.08
psSAR10g [W/kg]	1.17	1.16
Power Drift [dB]	0.01	-0.01



Plots of System Verification

Measurement Report

S82b System Check H3700_240524

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.97	39.1

Hardware Setup

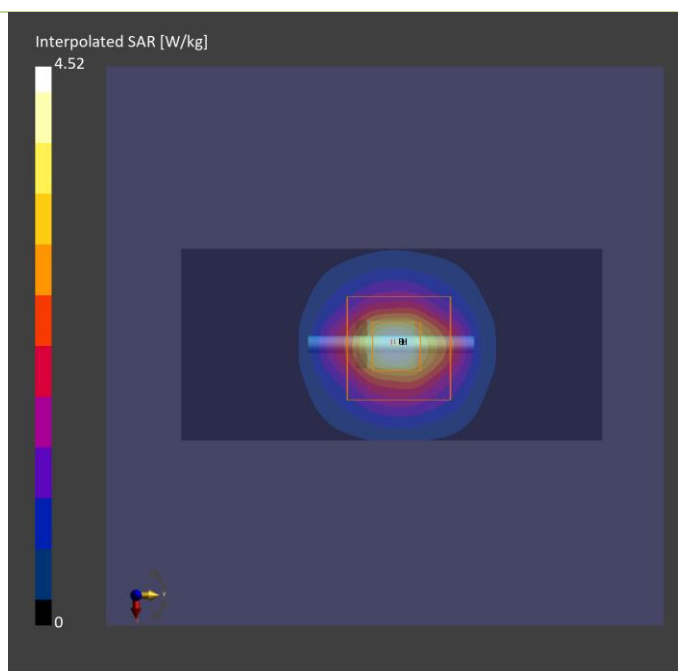
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-24	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-24	2024-05-24
psSAR1g [W/kg]	3.06	3.08
psSAR10g [W/kg]	1.14	1.14
Power Drift [dB]	0.01	0.00



Plots of System Verification

Measurement Report S84 System Check H2450_240430 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2450

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2450.0, 0	7.65	1.83	40.1

Hardware Setup

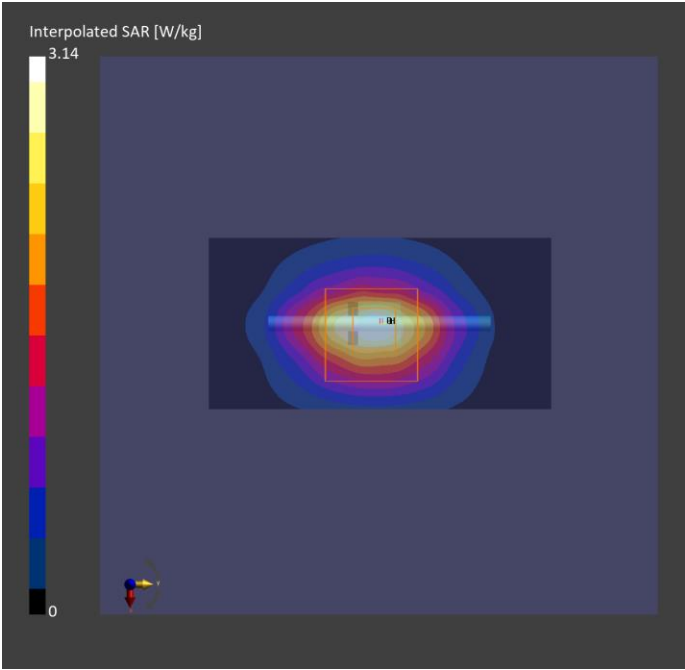
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-30	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 84.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-30	2024-04-30
psSAR1g [W/kg]	2.37	2.39
psSAR10g [W/kg]	1.09	1.14
Power Drift [dB]	-0.06	-0.05



Plots of System Verification

Measurement Report
S85 System Check_H5250_240430
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		5250

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5250.000, 0	5.52	4.49	37.2

Hardware Setup

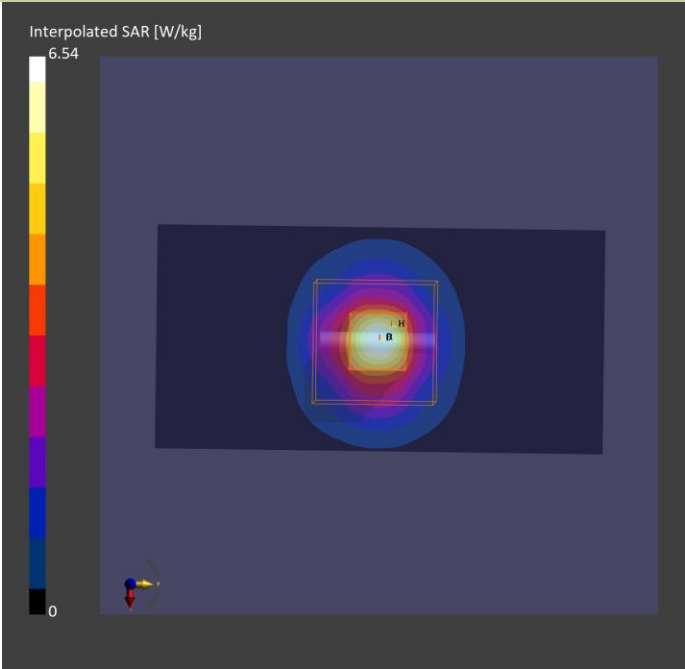
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-30	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-30	2024-04-30
psSAR1g [W/kg]	3.97	4.14
psSAR10g [W/kg]	1.11	1.16
Power Drift [dB]	-0.00	0.03





Plots of System Verification

Measurement Report S86 System Check_H5600_240502

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		5600

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5600.0, 0	4.8	4.88	34.7

Hardware Setup

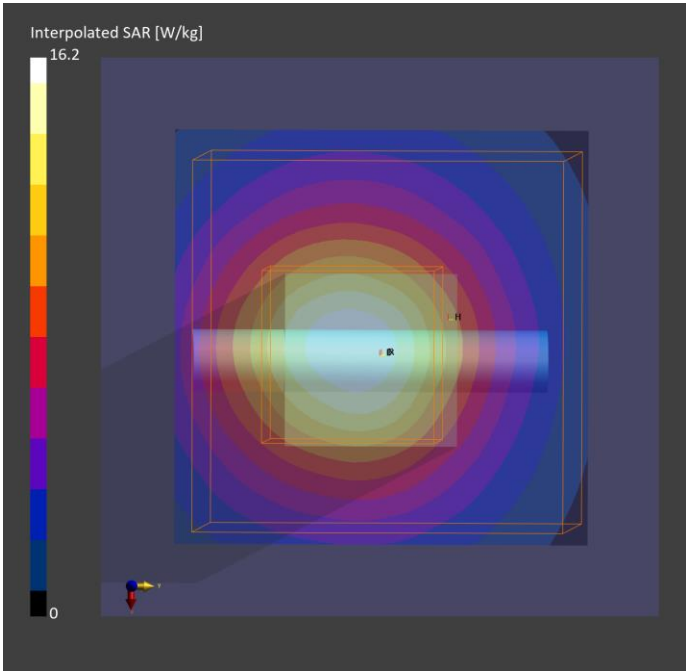
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-02	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-02	2024-05-02
psSAR1g [W/kg]	3.65	3.93
psSAR10g [W/kg]	1.07	1.17
Power Drift [dB]	0.03	-0.03



Plots of System Verification

Measurement Report

S87 System Check_H5750_240502

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		5800

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5750.000, 0	4.96	5.04	34.5

Hardware Setup

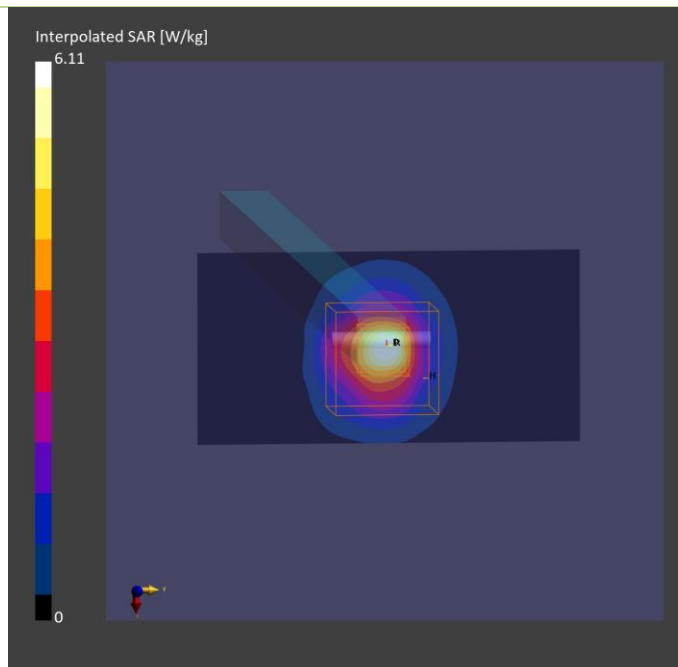
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-02	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-02	2024-05-02
psSAR1g [W/kg]	3.96	4.24
psSAR10g [W/kg]	1.17	1.23
Power Drift [dB]	0.01	-0.03



Plots of System Verification

Measurement Report
S88 System Check H2450_240430
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2450

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2450.0, 0	7.65	1.83	40.1

Hardware Setup

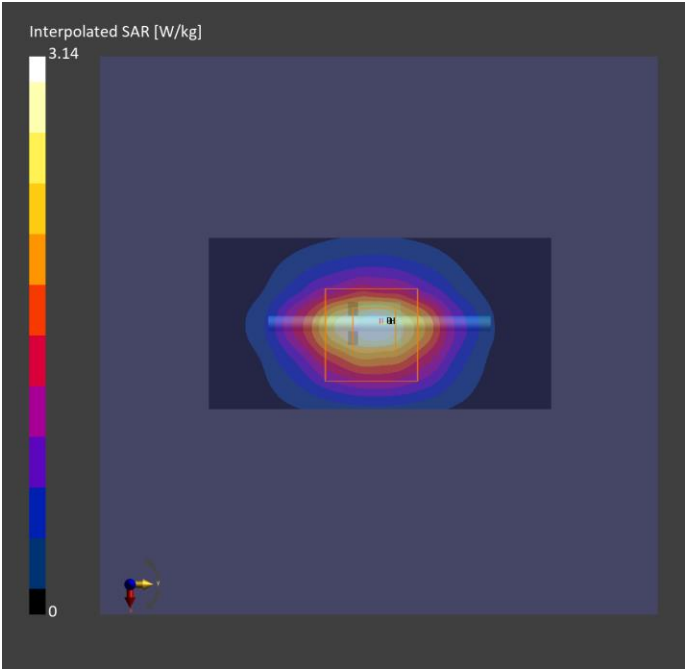
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-30	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 84.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-30	2024-04-30
psSAR1g [W/kg]	2.37	2.39
psSAR10g [W/kg]	1.09	1.14
Power Drift [dB]	-0.06	-0.05



Plots of System Verification

Test Laboratory: Bureau Veritas ADT SAR/HAC Testing Lab

Date: 2024/05/01

S89 System Check_H13MHz_240501

DUT: CLA-13 MHz ;Type: CLA-13 ;SN: 1018

Communication System: UID 10453 - AAD, Validation (Square, 10ms, 1ms); Frequency: 13 MHz; Duty Cycle: 1:10
Medium: H13_0501 Medium parameters used: $f = 13 \text{ MHz}$; $\sigma = 0.731 \text{ S/m}$; $\epsilon_r = 55.21$; $\rho = 1000 \text{ kg/m}^3$

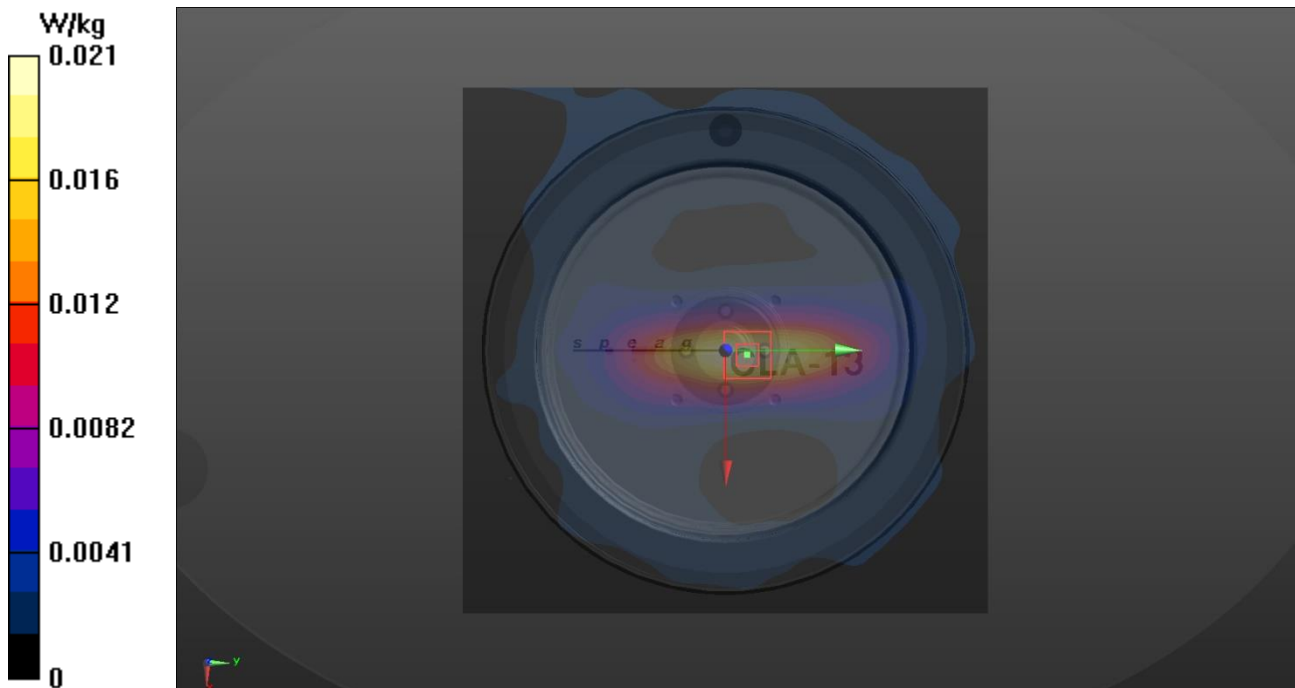
Ambient Temperature : $22.6 \text{ }^\circ\text{C}$; Liquid Temperature : $21.7 \text{ }^\circ\text{C}$

DASY5 Configuration:

- Probe: EX3DV4 – SN3650; ConvF(16.01, 16.01, 16.01) @ 13 MHz; Calibrated: 2024/03/19
- Sensor-Surface: 1.4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn1431; Calibrated: 2023/08/24
- Phantom: SAM Phantom_1987; Type: QD 000 P40 CD Ax; Serial: 1987
- Measurement SW: DASY52, Version 52.10 (4); SEMCAD X Version 14.6.14 (7501)

Pin=1W/Area Scan (241x241x1): Interpolated grid: $dx=1.000 \text{ mm}$, $dy=1.000 \text{ mm}$
Maximum value of SAR (interpolated) = 0.0205 W/kg

Pin=1W/Zoom Scan (7x7x16)/Cube 0: Measurement grid: $dx=4\text{mm}$, $dy=4\text{mm}$, $dz=1.4\text{mm}$
Reference Value = 5.167 V/m ; Power Drift = -0.03 dB
Peak SAR (extrapolated) = 0.0300 W/kg
SAR(1 g) = 0.025 W/kg ; SAR(10 g) = 0.017 W/kg (SAR corrected for target medium)
Maximum value of SAR (measured) = 0.0203 W/kg



Plots of System Verification

Measurement Report
S105 System Check H2300_240517
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2300

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2300.000, 0	7.95	1.75	37.6

Hardware Setup

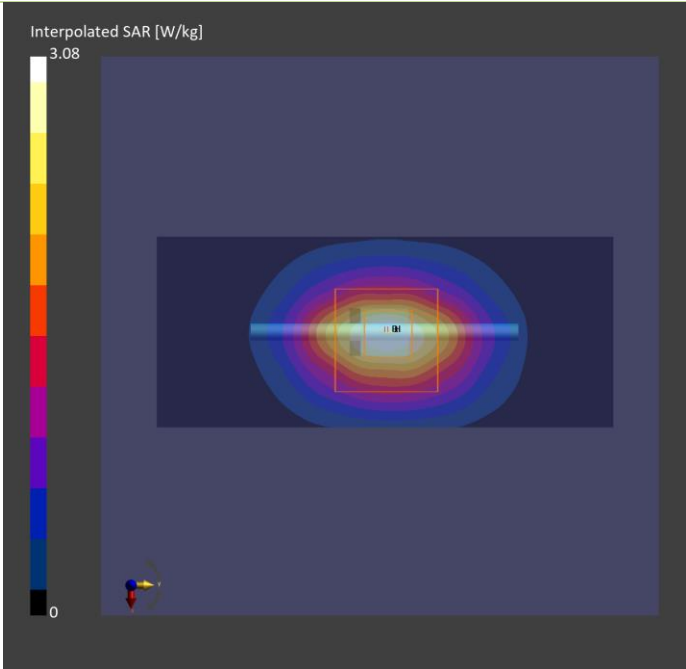
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-17	2024-05-17
psSAR1g [W/kg]	2.35	2.33
psSAR10g [W/kg]	1.12	1.11
Power Drift [dB]	0.02	0.01



Plots of System Verification

Measurement Report
S106 System Check_H2600_240517
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	10.0 x 10.0 x 300.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	2.01	37.1

Hardware Setup

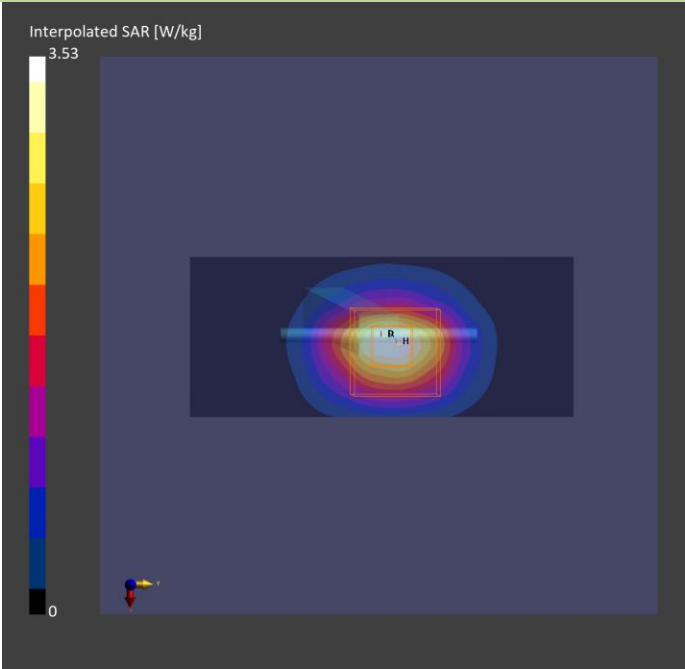
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-017	2024-05-17
psSAR1g [W/kg]	2.68	2.72
psSAR10g [W/kg]	1.22	1.22
Power Drift [dB]	0.00	-0.00



Plots of System Verification

Measurement Report
S109 System Check H3700_240517
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.97	39.1

Hardware Setup

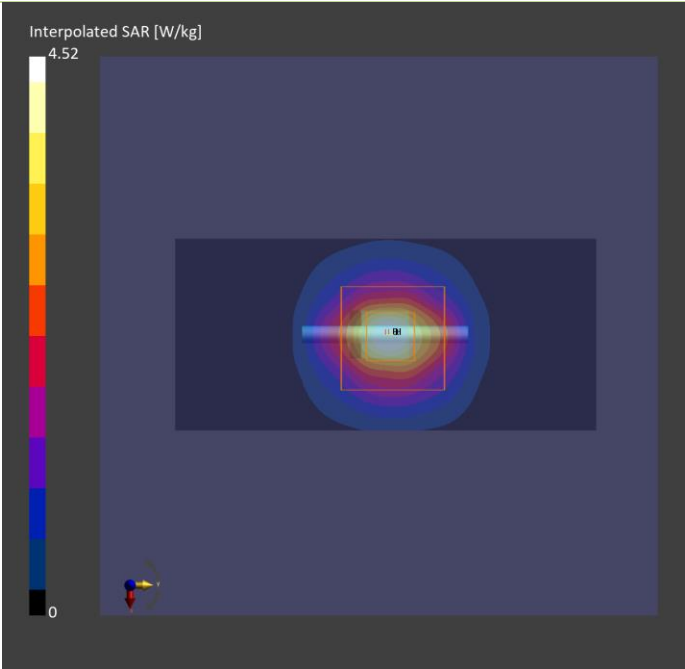
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-17	2024-05-17
psSAR1g [W/kg]	3.11	3.10
psSAR10g [W/kg]	1.15	1.15
Power Drift [dB]	0.01	0.00



Plots of System Verification

Measurement Report
S113 System Check H1900_240519
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.45	38.5

Hardware Setup

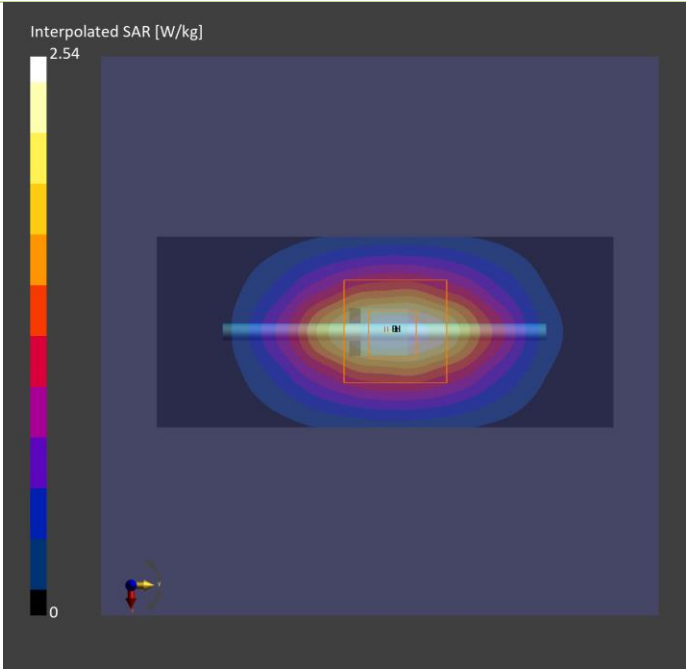
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-19	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-19	2024-05-19
psSAR1g [W/kg]	2.02	1.98
psSAR10g [W/kg]	1.04	1.03
Power Drift [dB]	-0.01	0.02



Plots of System Verification

Measurement Report S118 System Check H1900_240523 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		1900

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	1900.000, 0	8.31	1.40	39.7

Hardware Setup

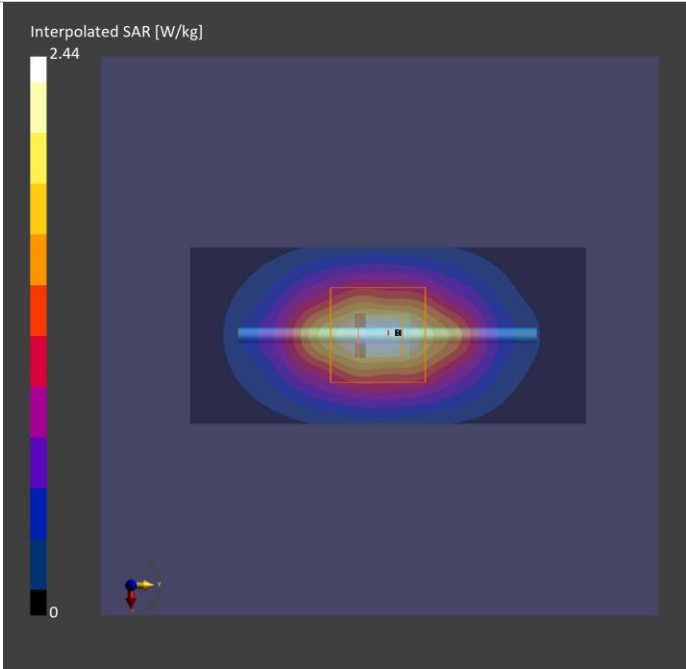
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-23	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-23	2024-05-23
psSAR1g [W/kg]	1.93	1.91
psSAR10g [W/kg]	0.996	1.00
Power Drift [dB]	0.01	0.01





Plots of System Verification

Measurement Report S120 System Check_H2600_240522

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	10.0 x 10.0 x 300.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2600.000, 0	7.58	1.93	37.1

Hardware Setup

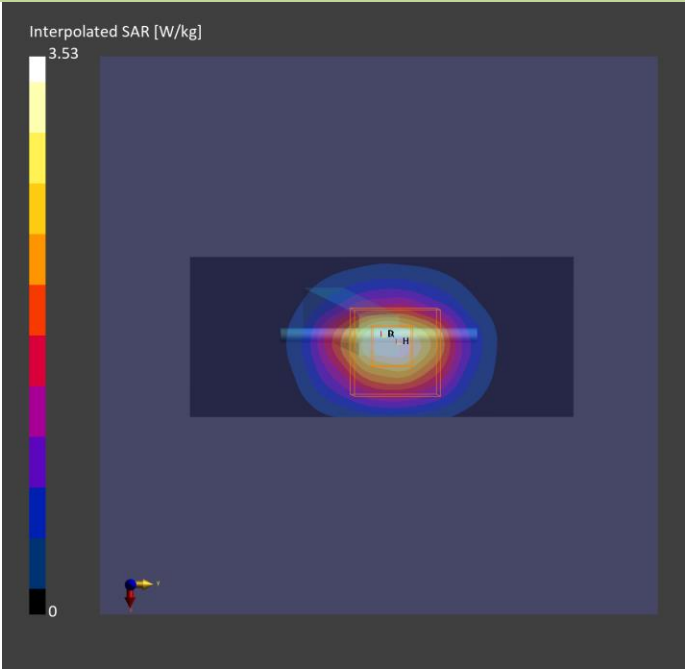
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	2.68	2.72
psSAR10g [W/kg]	1.22	1.22
Power Drift [dB]	0.00	-0.00



Plots of System Verification

Measurement Report S121 System Check_H2600_240521 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Dipole	10.0 x 10.0 x 300.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat	,			2600	7.58	1.93	37.1

Hardware Setup

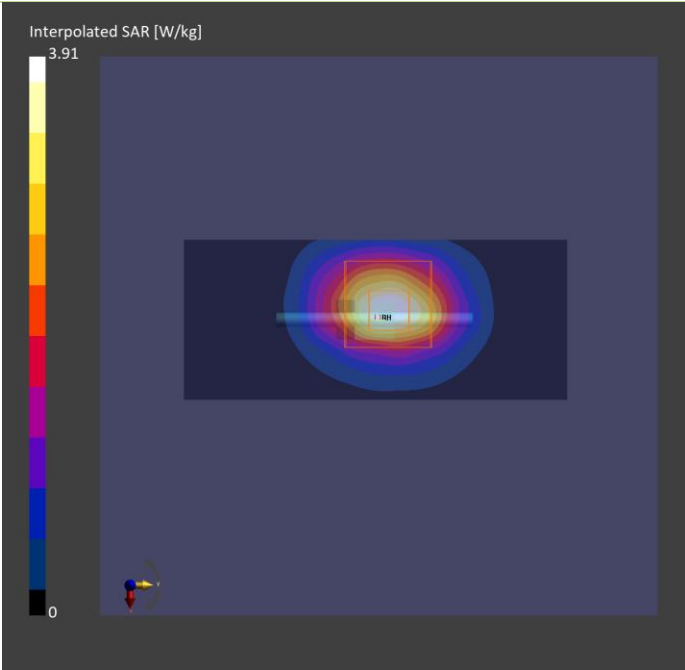
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-21	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-21	2024-05-21
psSAR1g [W/kg]	1.99	2.61
psSAR10g [W/kg]	1.38	1.36
Power Drift [dB]	-0.02	0.01



Plots of System Verification

Measurement Report
S122a System Check H3500_240522
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.80	39.5

Hardware Setup

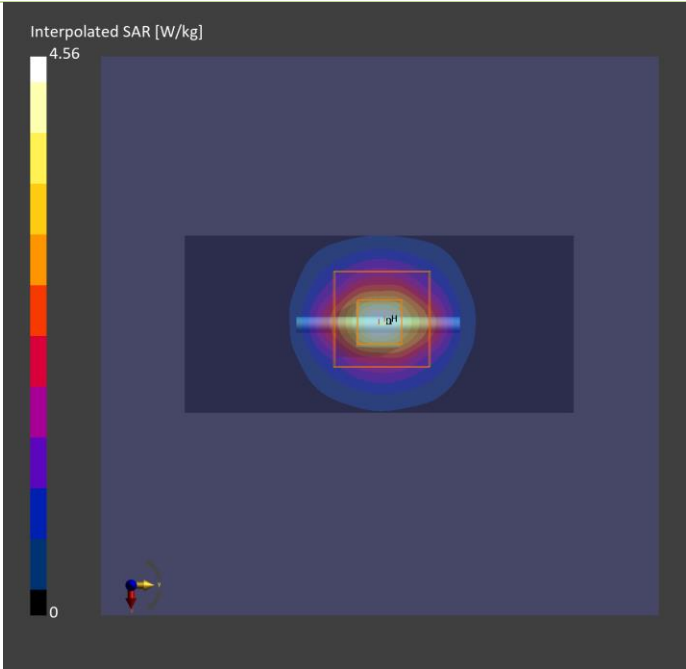
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	3.12	3.01
psSAR10g [W/kg]	1.17	1.12
Power Drift [dB]	0.01	-0.01



Plots of System Verification

Measurement Report
S122b System Check H3700_240522
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	2.99	39.2

Hardware Setup

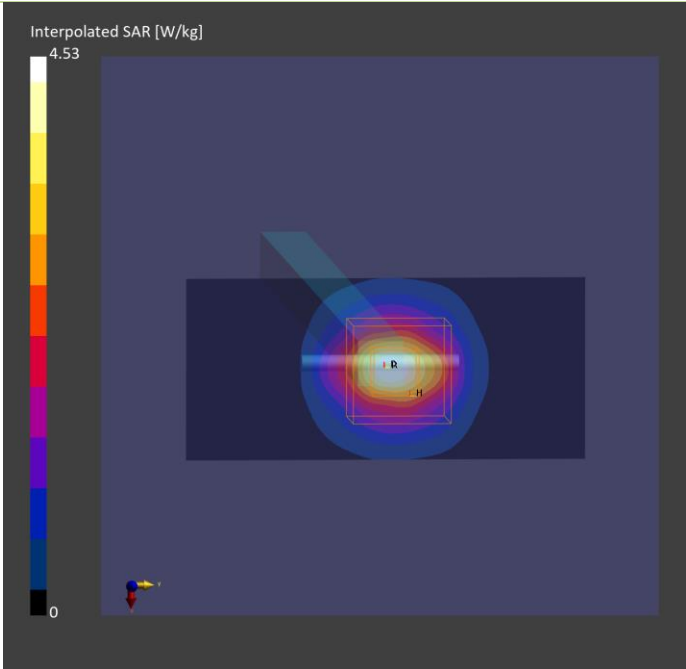
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 88.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	3.13	3.08
psSAR10g [W/kg]	1.11	1.14
Power Drift [dB]	-0.02	-0.01



Plots of System Verification

Measurement Report
S124 System Check H750_240522
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		750

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	750.000, 0	10.71	0.93	41.4

Hardware Setup

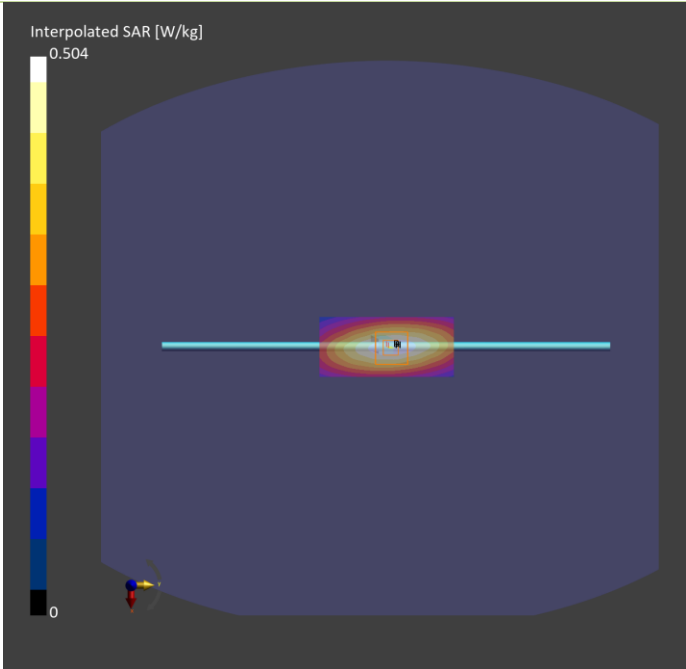
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-22	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	36.0 x 36.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-22	2024-05-22
psSAR1g [W/kg]	0.437	0.433
psSAR10g [W/kg]	0.290	0.286
Power Drift [dB]	-0.00	0.02



Plots of System Verification

Measurement Report
S125a System Check H3500_240523
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.85	38.4

Hardware Setup

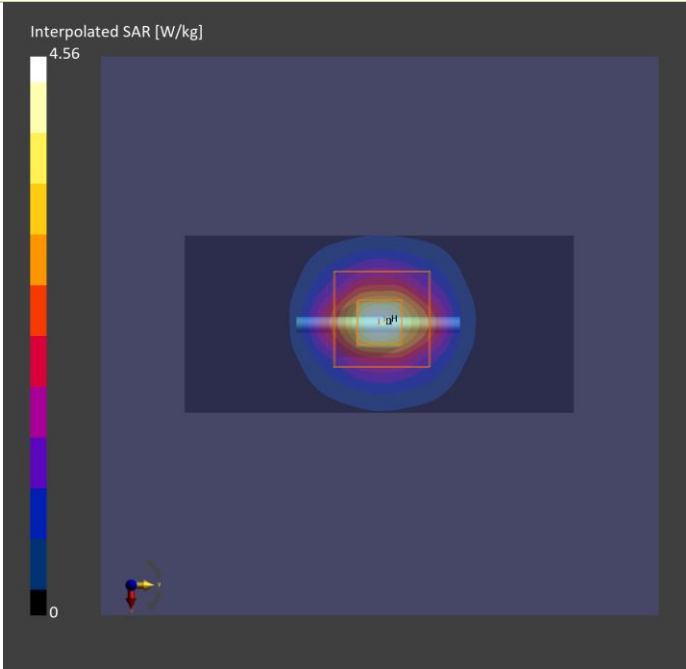
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-23	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-23	2024-05-23
psSAR1g [W/kg]	3.16	3.10
psSAR10g [W/kg]	1.19	1.18
Power Drift [dB]	0.01	-0.01



Plots of System Verification

Measurement Report
S125b System Check H3700_240523
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	3.03	38.1

Hardware Setup

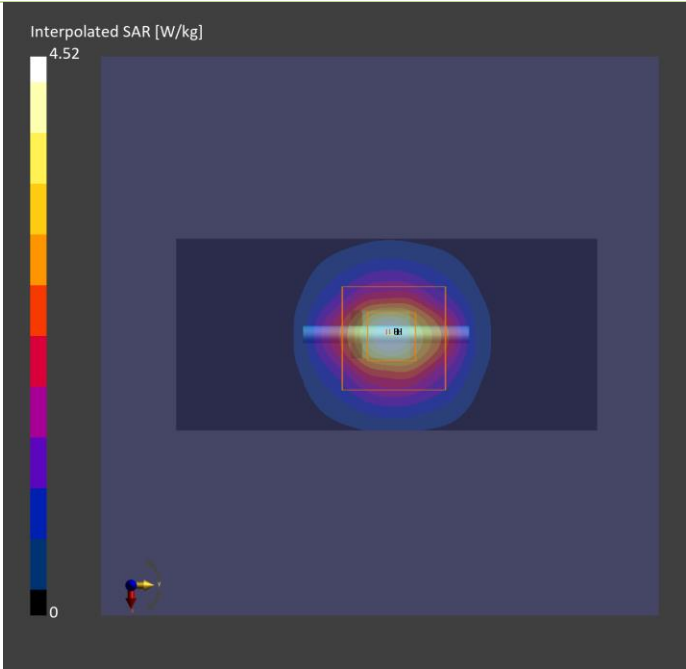
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-23	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-23	2024-05-23
psSAR1g [W/kg]	3.11	3.10
psSAR10g [W/kg]	1.15	1.15
Power Drift [dB]	0.01	0.00





Plots of System Verification

Measurement Report
S125c System Check H3900_240523
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	n/a x n/a x n/a		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	,		CW, 0--	3900.0, 0	6.53	3.23	37.8

Hardware Setup

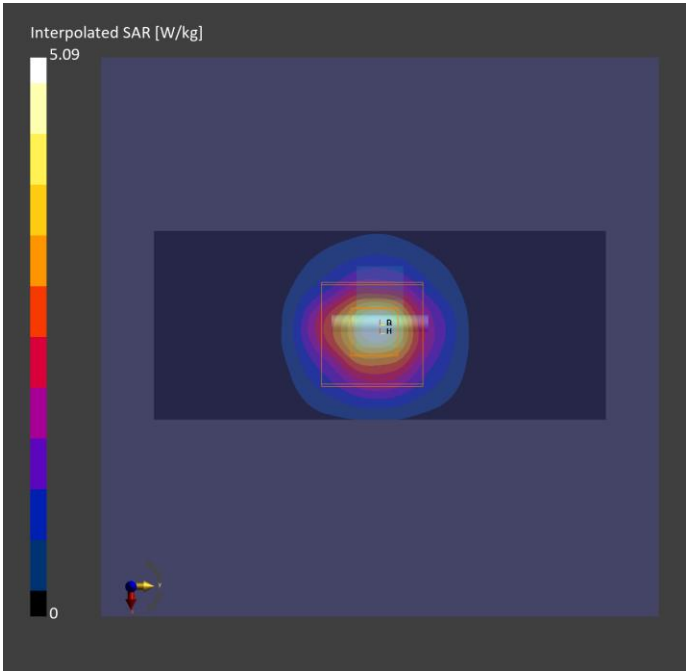
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-23	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 96.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	10.0 x 12.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-23	2024-05-23
psSAR1g [W/kg]	3.42	3.42
psSAR10g [W/kg]	1.21	1.23
Power Drift [dB]	0.02	-0.02



Plots of System Verification

Measurement Report
S127a System Check H3500_240523
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3500

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3500.000, 0	6.65	2.85	38.4

Hardware Setup

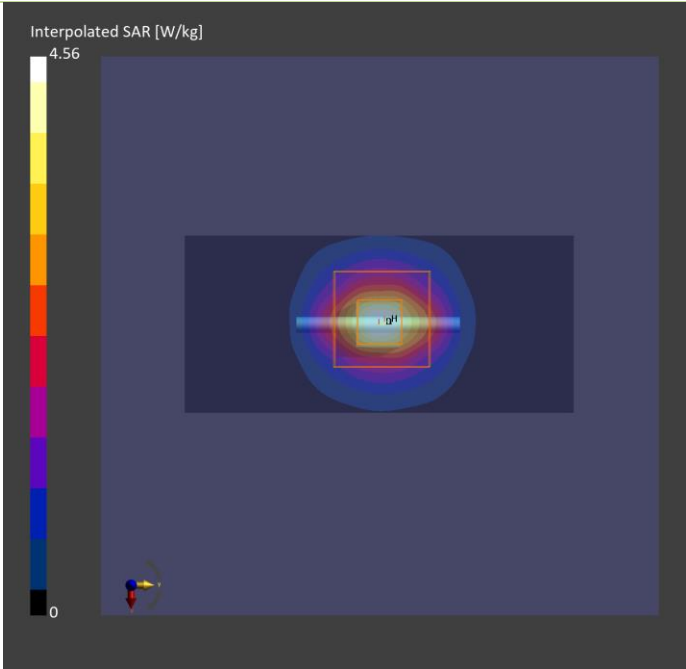
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-23	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-23	2024-05-23
psSAR1g [W/kg]	3.16	3.10
psSAR10g [W/kg]	1.19	1.18
Power Drift [dB]	0.01	-0.01





Plots of System Verification

Measurement Report
S127b System Check H3700_240523
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		3700

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	3700.000, 0	6.6	3.03	38.1

Hardware Setup

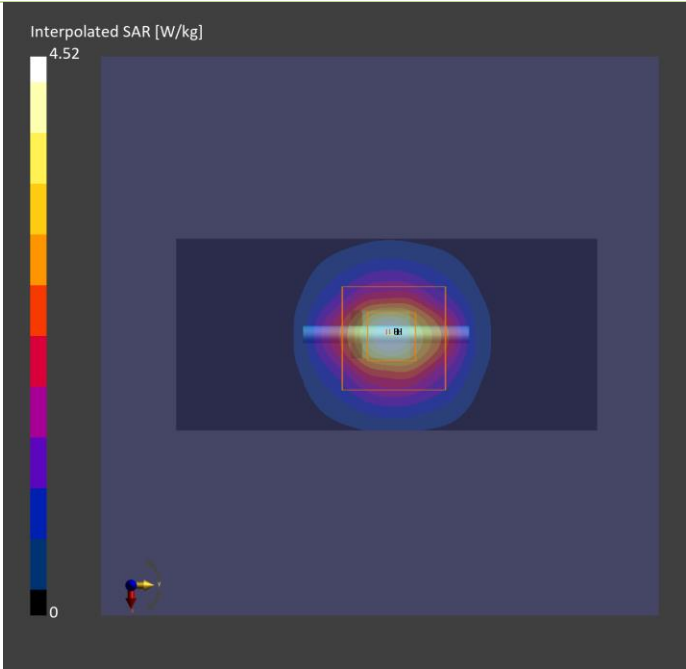
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-23	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 99.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	11.0 x 11.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-23	2024-05-23
psSAR1g [W/kg]	3.11	3.10
psSAR10g [W/kg]	1.15	1.15
Power Drift [dB]	0.01	0.00



Plots of System Verification

Measurement Report S129 System Check H2450_240502 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		2450

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	2450.0, 0	7.65	1.72	40.6

Hardware Setup

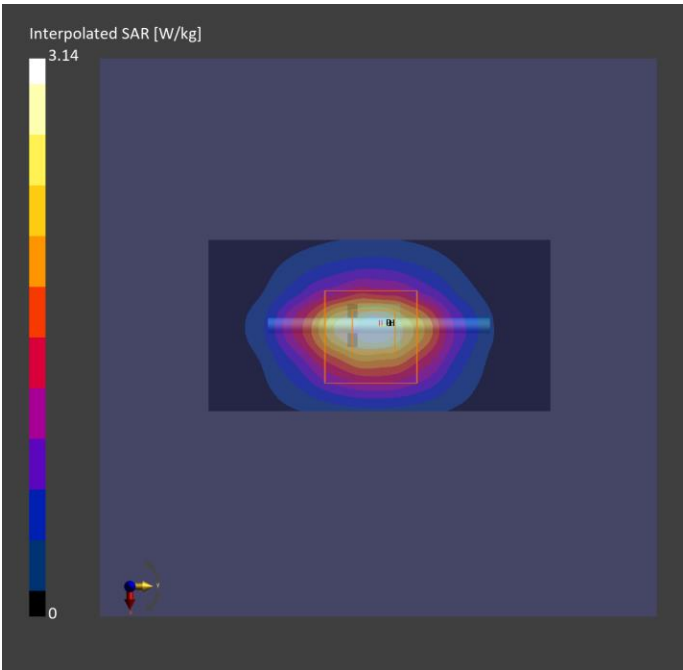
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-02	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 84.0	35.0 x 35.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-02	2024-05-02
psSAR1g [W/kg]	2.39	2.41
psSAR10g [W/kg]	1.10	1.12
Power Drift [dB]	-0.06	-0.05



Plots of System Verification

Measurement Report S135 System Check H6500_240506 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	6500.000, 0	5.4	6.07	34.5

Hardware Setup

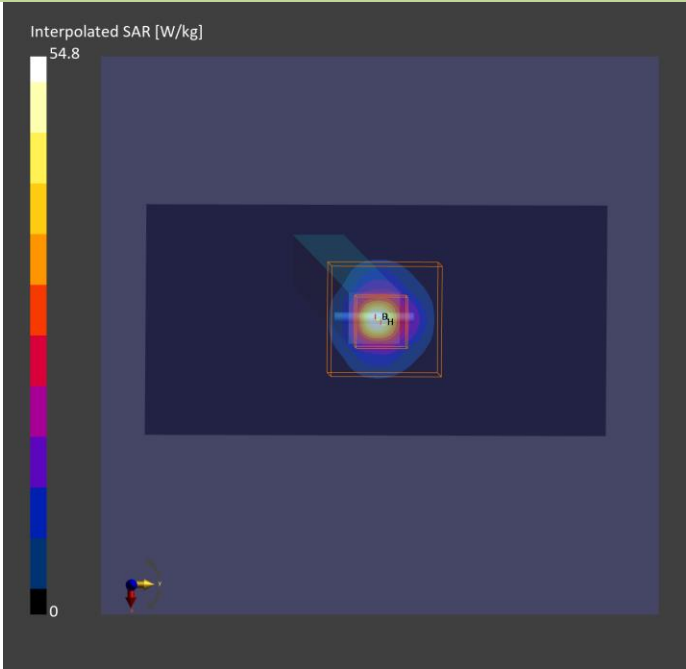
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-06	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	7.5 x 7.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-06	2024-05-06
psSAR1g [W/kg]	27.5	30.7
psSAR10g [W/kg]	5.29	5.63
psAPD (1.0cm2, sq) [W/m2]		307
psAPD (4.0cm2, sq) [W/m2]		137
Power Drift [dB]	0.02	-0.02
M2/M1 [%]		50.6
Dist 3dB Peak [mm]		4.4



Plots of System Verification

Measurement Report S130 System Check H5250_240504 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5250.000, 0	5.52	4.40	36.0

Hardware Setup

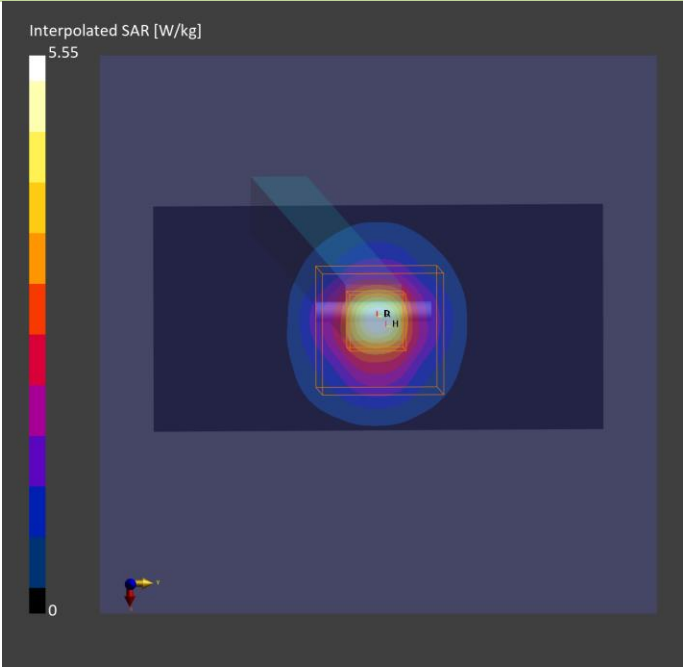
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-04	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-04	2024-05-04
psSAR1g [W/kg]	3.36	3.63
psSAR10g [W/kg]	0.950	1.05
Power Drift [dB]	-0.06	0.09



Plots of System Verification

Measurement Report S131 System Check H5600_240504 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5600.000, 0	4.8	4.94	35.9

Hardware Setup

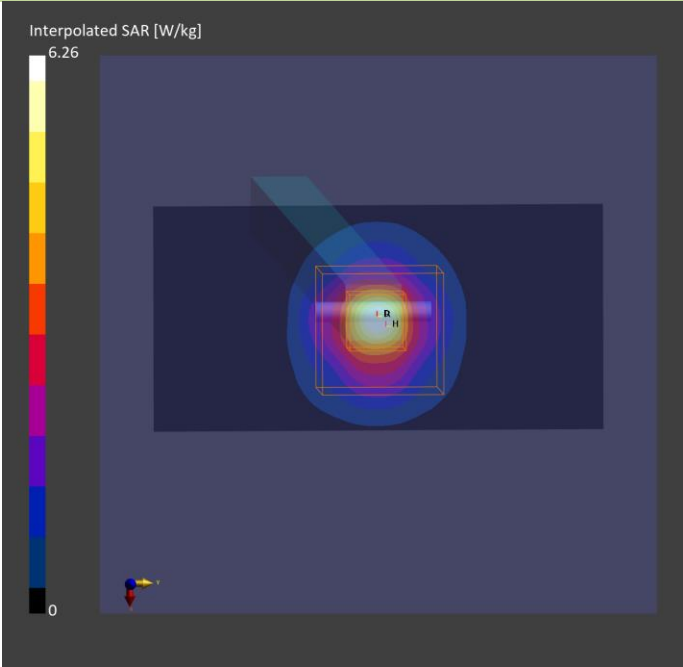
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-04	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-04	2024-05-04
psSAR1g [W/kg]	3.85	4.05
psSAR10g [W/kg]	1.08	1.15
Power Drift [dB]	0.01	0.06



Plots of System Verification

Measurement Report S132 System Check H5750_240504 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	5750.000, 0	4.96	5.12	35.7

Hardware Setup

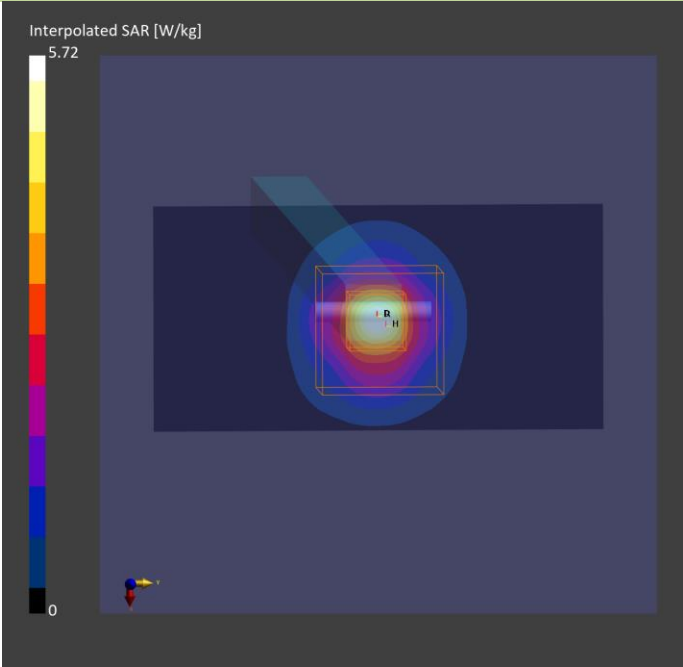
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-04	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-04	2024-05-04
psSAR1g [W/kg]	3.54	3.75
psSAR10g [W/kg]	0.987	1.06
Power Drift [dB]	-0.00	0.06



Plots of System Verification

Test Laboratory: Bureau Veritas ADT SAR/HAC Testing Lab

Date: 2024/05/01

S134 System Check_H13MHz_240501

DUT: CLA-13 MHz ;Type: CLA-13 ;SN: 1018

Communication System: UID 10453 - AAD, Validation (Square, 10ms, 1ms); Frequency: 13 MHz; Duty Cycle: 1:10
Medium: H13_0501 Medium parameters used: $f = 13 \text{ MHz}$; $\sigma = 0.731 \text{ S/m}$; $\epsilon_r = 55.21$; $\rho = 1000 \text{ kg/m}^3$

Ambient Temperature : 22.6 °C ; Liquid Temperature : 21.7 °C

DASY5 Configuration:

- Probe: EX3DV4 – SN3650; ConvF(16.01, 16.01, 16.01) @ 13 MHz; Calibrated: 2024/03/19
- Sensor-Surface: 1.4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn1431; Calibrated: 2023/08/24
- Phantom: SAM Phantom_1987; Type: QD 000 P40 CD Ax; Serial: 1987
- Measurement SW: DASY52, Version 52.10 (4); SEMCAD X Version 14.6.14 (7501)

Pin=1W/Area Scan (241x241x1): Interpolated grid: $dx=1.000 \text{ mm}$, $dy=1.000 \text{ mm}$
Maximum value of SAR (interpolated) = 0.0201 W/kg

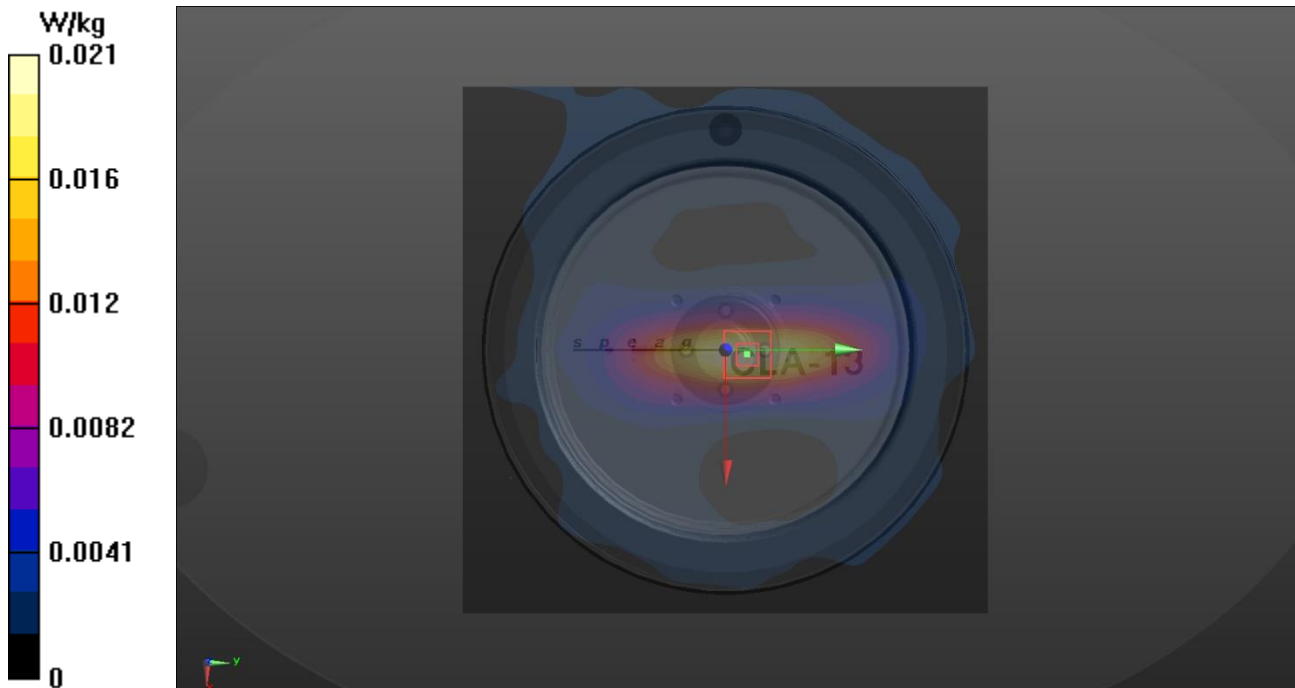
Pin=1W/Zoom Scan (7x7x16)/Cube 0: Measurement grid: $dx=4\text{mm}$, $dy=4\text{mm}$, $dz=1.4\text{mm}$

Reference Value = 5.167 V/m; Power Drift = -0.01 dB

Peak SAR (extrapolated) = 0.0300 W/kg

SAR(1 g) = 0.025 W/kg; SAR(10 g) = 0.017 W/kg (SAR corrected for target medium)

Maximum value of SAR (measured) = 0.0203 W/kg



Plots of System Verification

Measurement Report
S136 System Check H6500_240506
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW, 0--	6500.000, 0	5.4	6.07	34.5

Hardware Setup

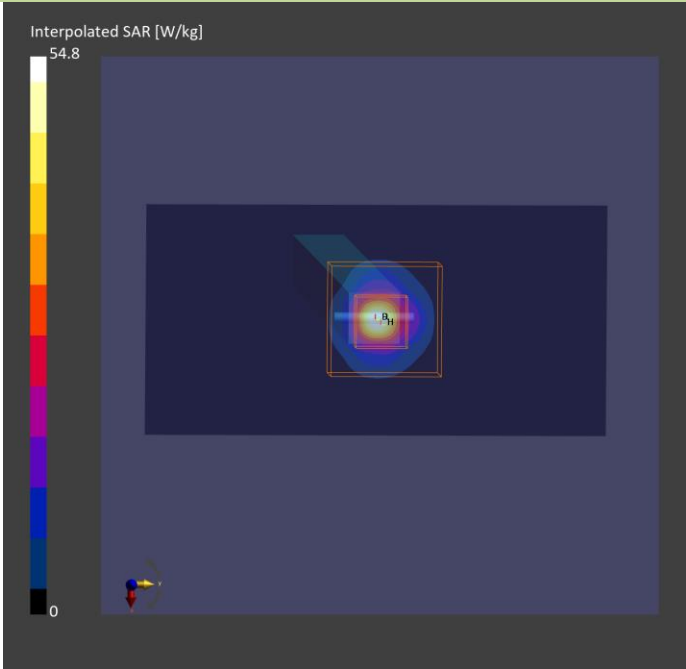
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-May-06	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	45.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	7.5 x 7.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-06	2024-05-06
psSAR1g [W/kg]	27.5	30.7
psSAR10g [W/kg]	5.29	5.63
psAPD (1.0cm2, sq) [W/m2]		307
psAPD (4.0cm2, sq) [W/m2]		137
Power Drift [dB]	0.02	-0.02
M2/M1 [%]		50.6
Dist 3dB Peak [mm]		4.4



Plots of System Verification

Measurement Report

S135 PD_System Check_10 GHz_2024.05.22

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
SPEAG, 5G Verification Source	100.0 x 100.0 x 170.0	SN: 1025	Phone
10 GHz			

Exposure Conditions

Phantom Section	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor
5G Air	FRONT, 10.00	Validation band	CW, 0--	10000.0, 10000	1.0

Hardware Setup

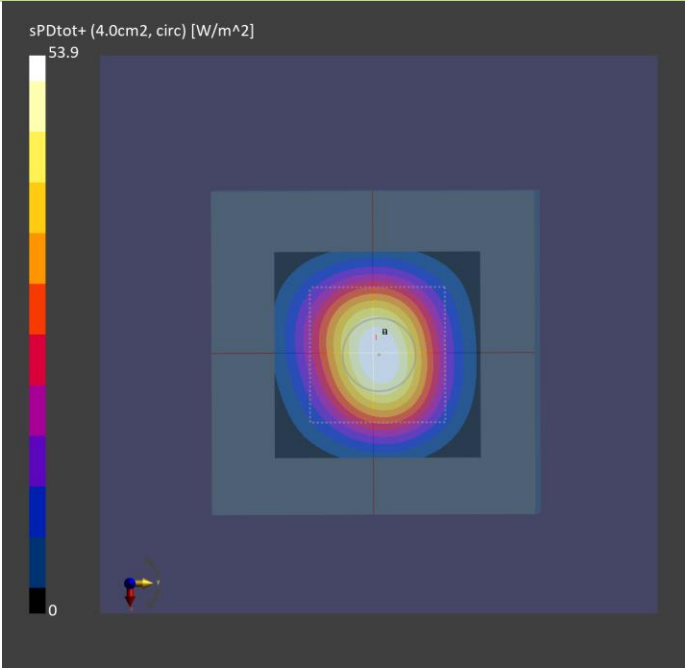
Phantom	Medium	Probe, Calibration Date	DAE, Calibration Date
mmWave- 1029	--Air--	EUmmWV4 - SN9615_F1-55GHz, 2023-07-10	DAE4 Sn1431, 2023-08-24

Scan Setup

	5G Scan
Grid Extents [mm]	60.0 x 60.0
Grid Steps [lambda]	0.125 x 0.125
Sensor Surface [mm]	10.0

Measurement Results

	5G Scan
Date	2024-05-22
Avg. Area [cm ²]	4.00
psPDn+ [W/m ²]	53.7
psPDtot+ [W/m ²]	53.9
psPDmod+ [W/m ²]	54.1
E _{max} [V/m]	149
Power Drift [dB]	-0.04



Plots of System Verification

Measurement Report S136 PD_System Check_10 GHz_2024.05.22 Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
SPEAG, 5G Verification Source 10 GHz	100.0 x 100.0 x 170.0	SN: 1025	Phone

Exposure Conditions

Phantom Section	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor
5G Air	FRONT, 10.00	Validation band	CW, 0--	10000.0, 10000	1.0

Hardware Setup

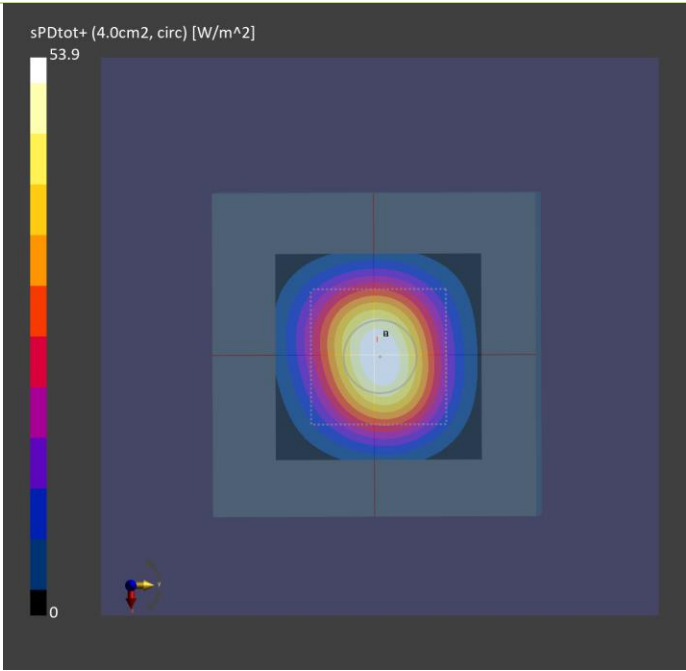
Phantom	Medium	Probe, Calibration Date	DAE, Calibration Date
mmWave- 1029	--Air--	EUmmWV4 - SN9615_F1-55GHz, 2023-07-10	DAE4 Sn1431, 2023-08-24

Scan Setup

	5G Scan
Grid Extents [mm]	60.0 x 60.0
Grid Steps [lambda]	0.125 x 0.125
Sensor Surface [mm]	10.0

Measurement Results

	5G Scan
Date	2024-05-22
Avg. Area [cm²]	4.00
psPDn+ [W/m²]	53.7
psPDtot+ [W/m²]	53.9
psPDmod+ [W/m²]	54.1
E _{max} [V/m]	149
Power Drift [dB]	-0.04



Plots of Measurement

Appendix B. Plots of Measurement

The SAR plots for highest measured SAR in each exposure configuration, wireless mode and frequency band combination are shown as follows.

Plots of Measurement

Measurement Report
P01 GSM850_GPRS 4Tx Slot_Left Cheek_Ch189_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	GSM 850	GSM, 10028-DAC	836.400, 189	10.39	0.92	42.5

Hardware Setup

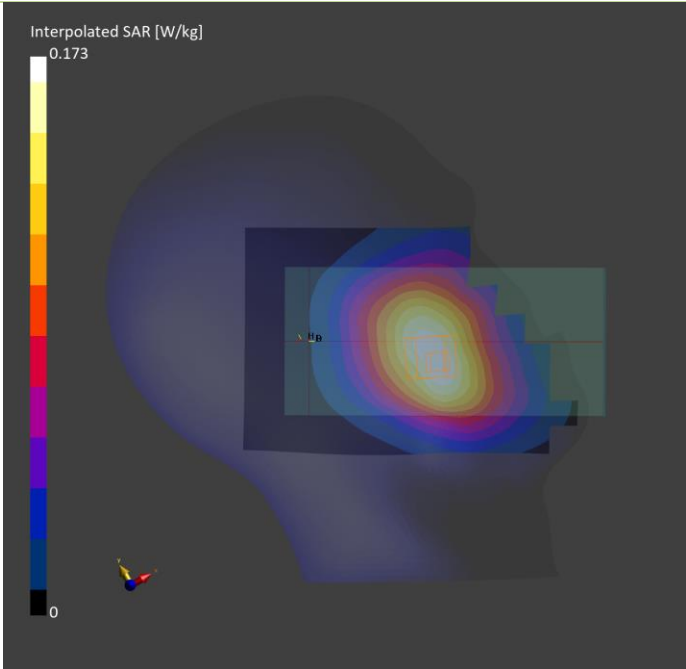
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	0.150	0.163
psSAR10g [W/kg]	0.104	0.128
Power Drift [dB]	-0.06	0.02
M2/M1 [%]		79.9
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P02 GSM1900_GPRS 4Tx Slot_Left Cheek_Ch512_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	PCS 1900	GSM, 10028-DAC	1850.200, 512	8.31	1.42	41.2

Hardware Setup

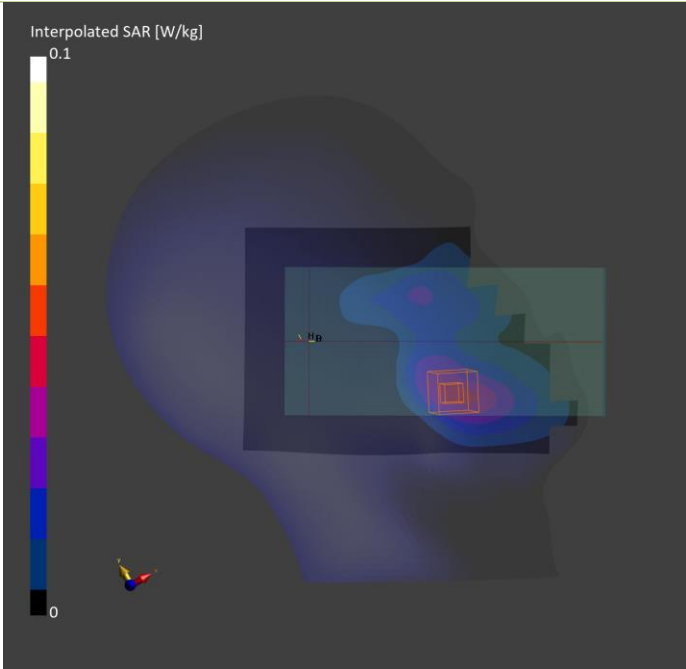
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	0.037	0.040
psSAR10g [W/kg]	0.021	0.025
Power Drift [dB]	0.18	0.06
M2/M1 [%]		64.8
Dist 3dB Peak [mm]		12.2



Plots of Measurement

Measurement Report
P03 WCDMA II_RMC12.2K_Left Cheek_0mm_Ch9262_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 2	WCDMA, 10011-CAC	1852.400, 9262	8.31	1.43	40.9

Hardware Setup

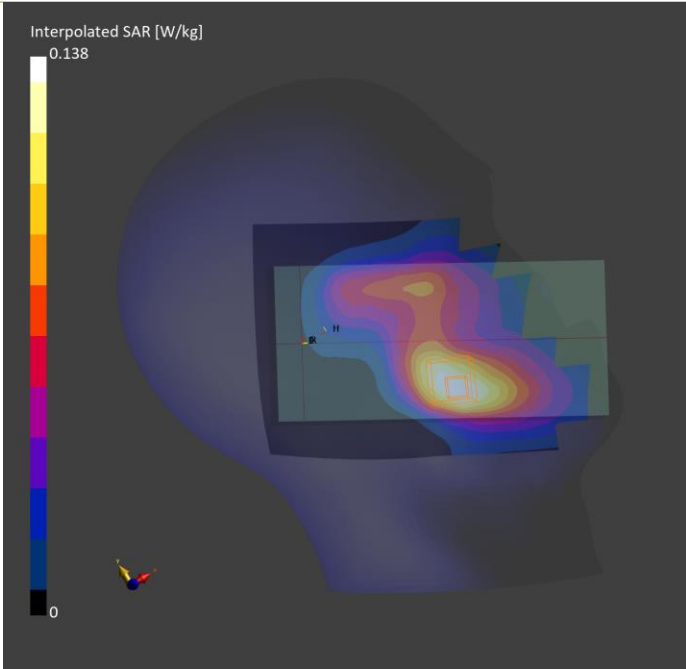
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-15	2024-04-15
psSAR1g [W/kg]	0.112	0.118
psSAR10g [W/kg]	0.067	0.074
Power Drift [dB]	0.00	0.03
M2/M1 [%]		84.8
Dist 3dB Peak [mm]		11.9



Plots of Measurement

Measurement Report
P04 WCDMA IV_RMC12.2K_Left Cheek_0mm_Ch1513_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 4	WCDMA, 10011-CAC	1752.600, 1513	8.74	1.37	41.0

Hardware Setup

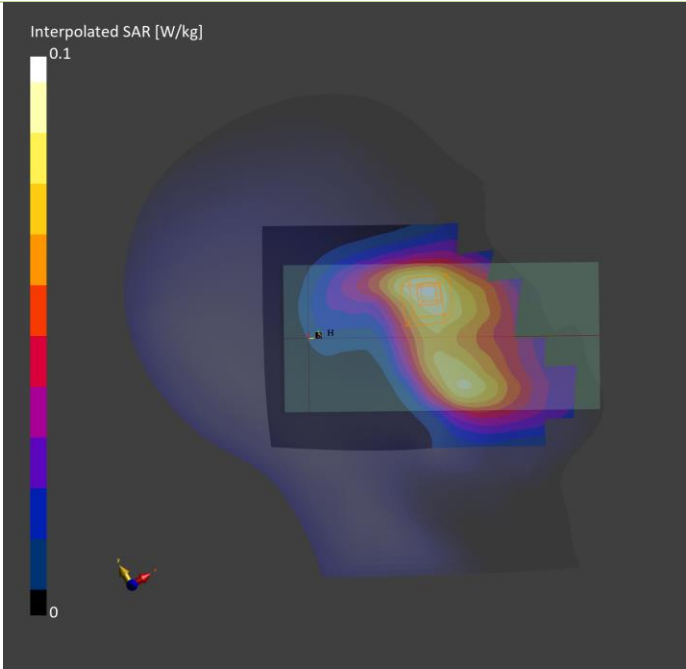
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-15	2024-04-15
psSAR1g [W/kg]	0.077	0.083
psSAR10g [W/kg]	0.048	0.057
Power Drift [dB]	-0.04	0.00
M2/M1 [%]		86.6
Dist 3dB Peak [mm]		16.2



Plots of Measurement

Measurement Report
P05 WCDMA V_RMC12.2K_Left Cheek_0mm_Ch4182_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 5	WCDMA, 10011-CAC	836.400, 4182	10.39	0.95	43.1

Hardware Setup

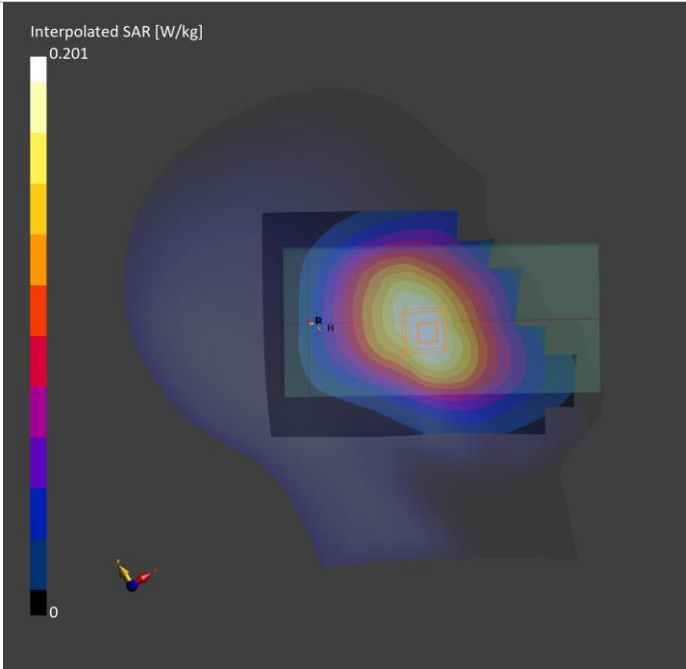
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-15	2024-04-15
psSAR1g [W/kg]	0.176	0.193
psSAR10g [W/kg]	0.121	0.147
Power Drift [dB]	0.04	0.07
M2/M1 [%]		76.2
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P06 LTE 2_QPSK20M_Left Cheek_0mm_Ch19100_1RB_OS0_Reader_4100_Ant 7
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 2	LTE-FDD, 10169-CAF	1900.000, 19100	8.31	1.45	40.7

Hardware Setup

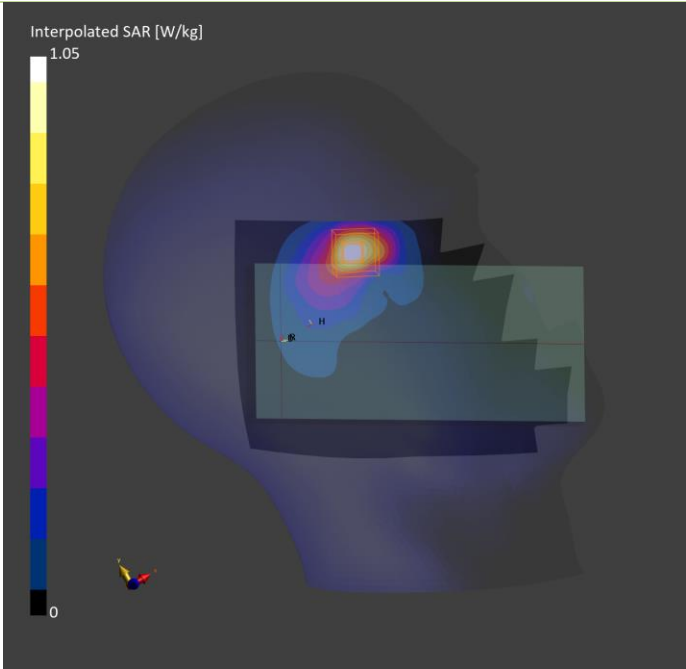
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-18	2024-04-18
psSAR1g [W/kg]	0.807	0.809
psSAR10g [W/kg]	0.412	0.393
Power Drift [dB]	-0.40	0.02
M2/M1 [%]		50.7
Dist 3dB Peak [mm]		8.3



Plots of Measurement

Measurement Report
P07 LTE 4_QPSK20M_Left Cheek_0mm_Ch20300_1RB_OS0_Reader_4770_Ant 7
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 4	LTE-FDD, 10169-CAF	1745.000, 20300	8.74	1.35	40.9

Hardware Setup

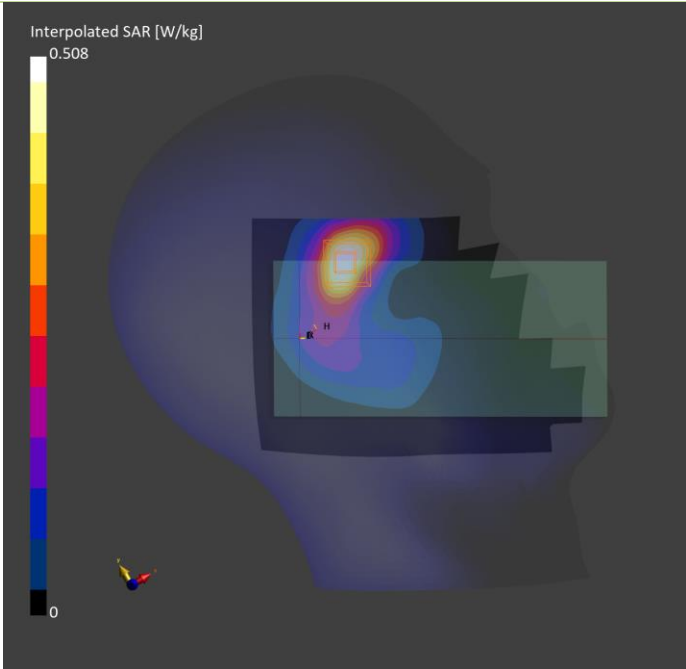
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-18	2024-04-18
psSAR1g [W/kg]	0.414	0.423
psSAR10g [W/kg]	0.236	0.237
Power Drift [dB]	-0.10	-0.14
M2/M1 [%]		55.3
Dist 3dB Peak [mm]		13.0



Plots of Measurement

Measurement Report
P08 LTE 5_QPSK10M_Right Cheek_Ch20525_1RB_OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band 5	LTE-FDD, 10175-CAH	836.500, 20525	10.39	0.927	42.7

Hardware Setup

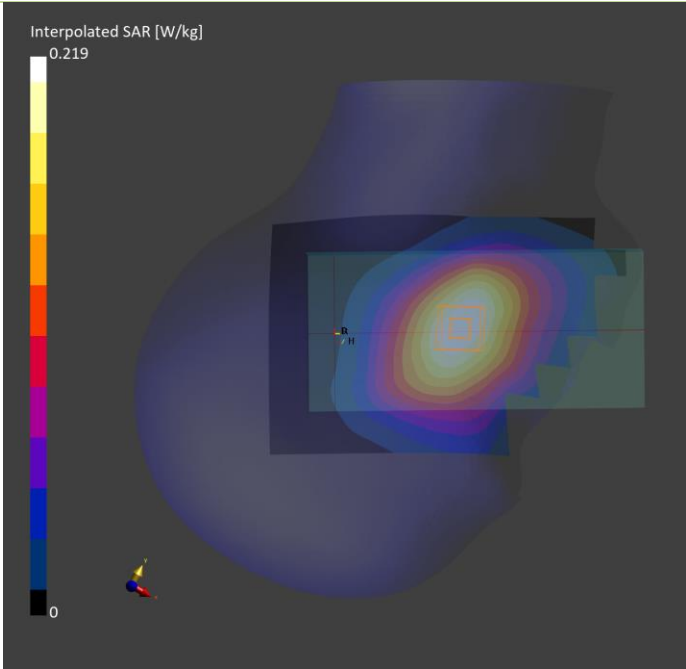
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.192	0.204
psSAR10g [W/kg]	0.133	0.158
Power Drift [dB]	-0.06	0.01
M2/M1 [%]		79.6
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P09 LTE 7_QPSK20M_Left Cheek_0mm_Ch21100_1RB_OS0_Reader_4770_Ant 6
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 7	LTE-FDD, 10169-CAF	2535.000, 21100	7.58	1.89	39.8

Hardware Setup

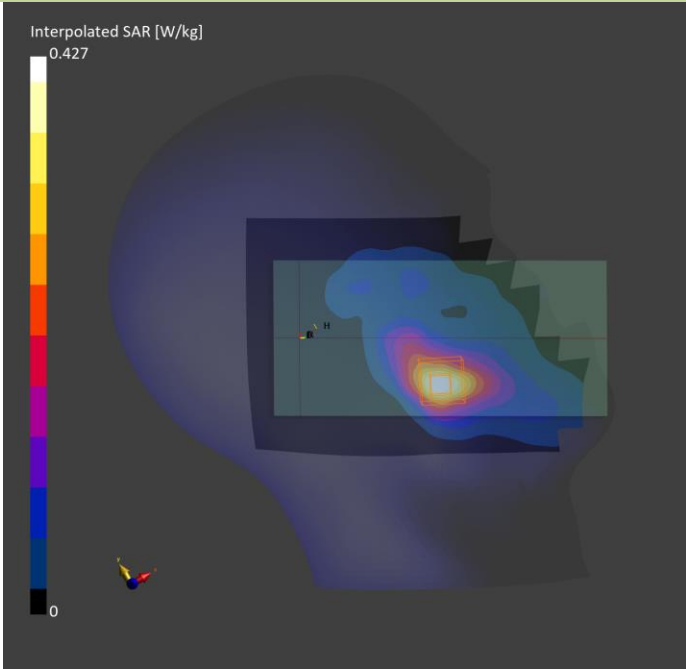
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-18	2024-04-18
psSAR1g [W/kg]	0.324	0.331
psSAR10g [W/kg]	0.158	0.171
Power Drift [dB]	-0.14	-0.01
M2/M1 [%]		82.6
Dist 3dB Peak [mm]		9.1



Plots of Measurement

Measurement Report
P10 LTE 12_QPSK10M_Left Tilted_Ch23095_1RB_OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Tilted, 0.00	Band 12	LTE-FDD, 10175-CAH	707.500, 23095	10.71	0.895	43.4

Hardware Setup

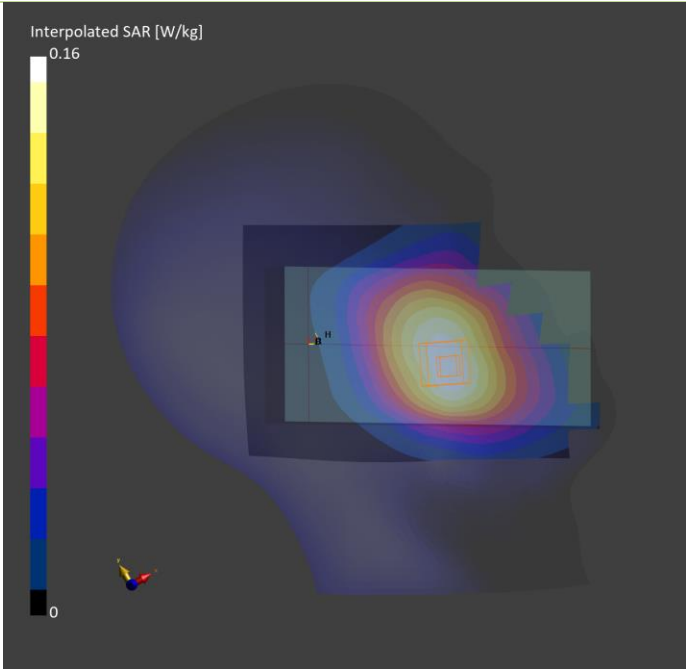
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.141	0.145
psSAR10g [W/kg]	0.098	0.115
Power Drift [dB]	-0.17	-0.06
M2/M1 [%]		80.5
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P11 LTE 13_QPSK10M_Left Tilted_Ch23230_1RB_OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Tilted, 0.00	Band 13	LTE-FDD, 10175-CAH	782.000, 23230	10.71	0.922	43.3

Hardware Setup

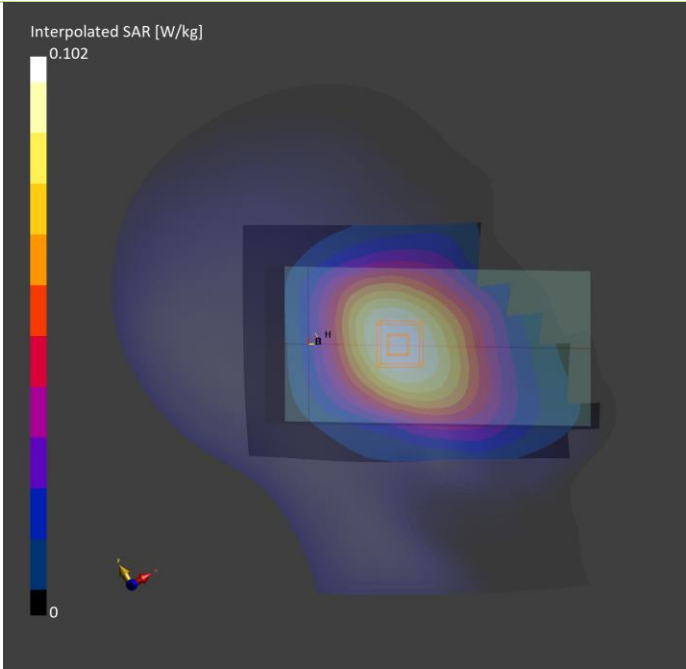
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.089	0.091
psSAR10g [W/kg]	0.063	0.072
Power Drift [dB]	-0.09	-0.05
M2/M1 [%]		83.3
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P12 LTE 14_QPSK10M_Left Tilted_Ch23330_1RB_OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Tilted, 0.00	Band 14	LTE-FDD, 10175-CAH	793.000, 23330	10.71	0.926	43.2

Hardware Setup

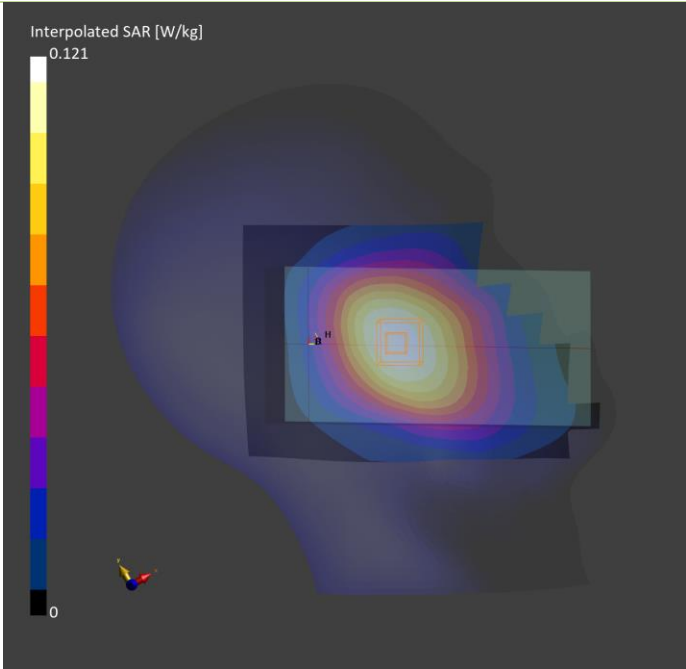
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.106	0.111
psSAR10g [W/kg]	0.074	0.087
Power Drift [dB]	0.03	-0.01
M2/M1 [%]		82.9
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P13 LTE 17_QPSK10M_Left Tilted_Ch23790_1RB_OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Tilted, 0.00	Band 17	LTE-FDD, 10175-CAH	710.000, 23790	10.71	0.896	43.4

Hardware Setup

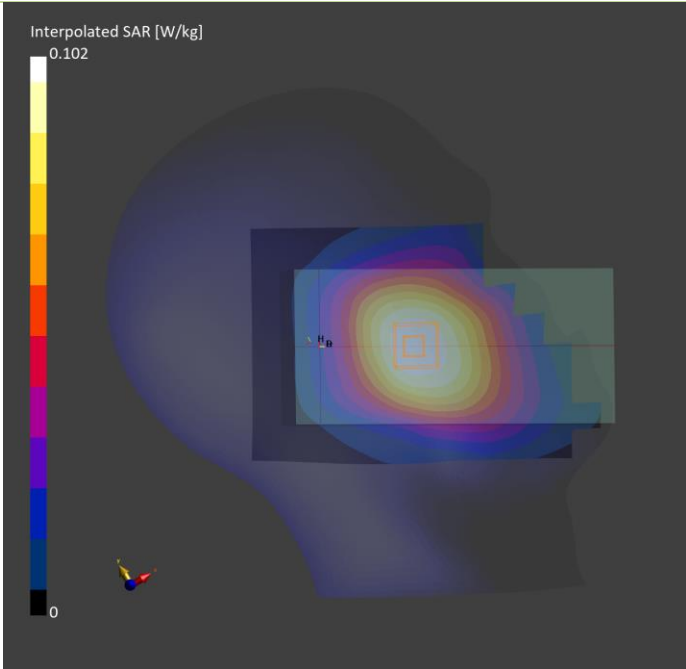
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.090	0.094
psSAR10g [W/kg]	0.064	0.077
Power Drift [dB]	0.01	-0.12
M2/M1 [%]		80.9
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P14 LTE 25_QPSK20M_Left Cheek_Ch26590_1RB_OS0_Reader_4100_Ant 7
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 25	LTE-FDD, 10169-CAF	1905.000, 26590	8.31	1.35	40.0

Hardware Setup

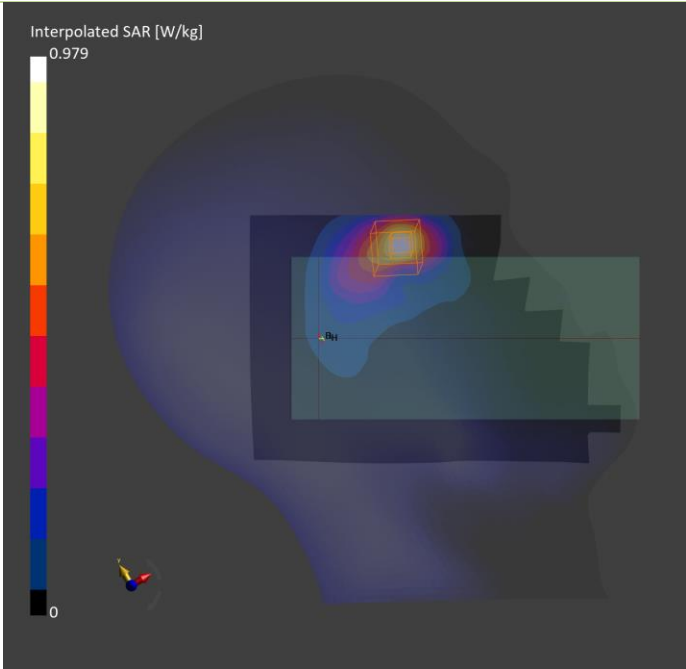
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-18	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-18	2024-05-18
psSAR1g [W/kg]	0.741	0.874
psSAR10g [W/kg]	0.382	0.417
Power Drift [dB]	-0.17	-0.18
M2/M1 [%]		48.6
Dist 3dB Peak [mm]		8.7



Plots of Measurement

Measurement Report
P15 LTE 26_QPSK15M_Left Tilted_Ch26965_1RB_OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Tilted, 0.00	Band 26	LTE-FDD, 10181-CAF	841.500, 26965	10.39	0.93	42.7

Hardware Setup

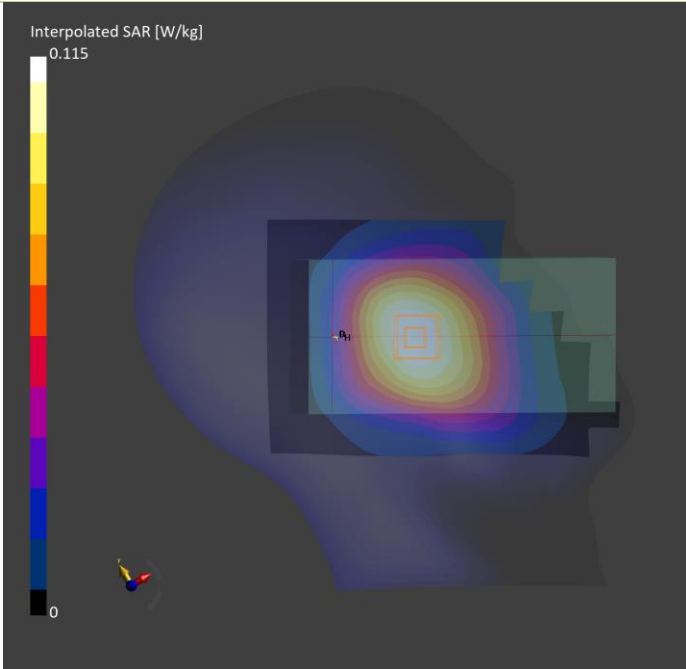
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.102	0.108
psSAR10g [W/kg]	0.071	0.085
Power Drift [dB]	-0.06	-0.01
M2/M1 [%]		78.9
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P16 LTE 30_QPSK10M_Right Cheek_Ch27710_1RB_OS0_Reader_4100_Ant 5
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band 30	LTE-FDD, 10175-CAH	2310.000, 27710	8.12	1.73	39.0

Hardware Setup

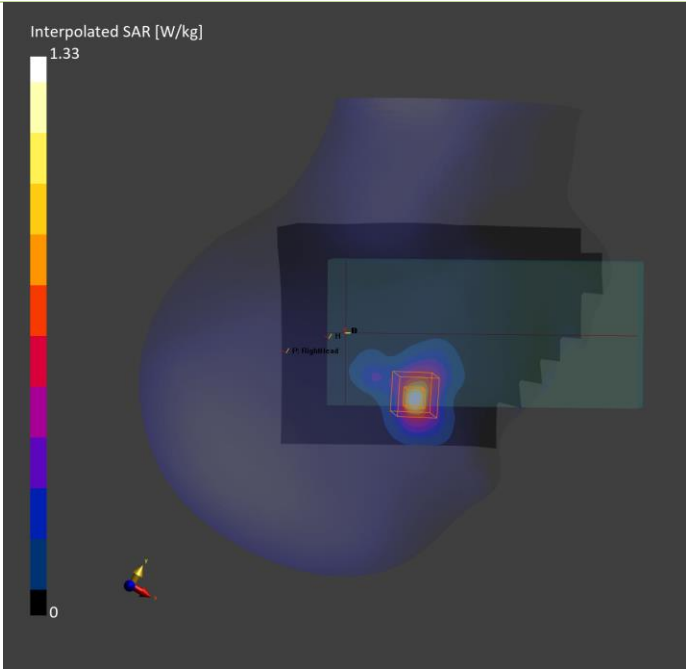
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Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-24	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-24	2024-04-24
psSAR1g [W/kg]	0.924	0.899
psSAR10g [W/kg]	0.400	0.388
Power Drift [dB]	-0.05	-0.09
M2/M1 [%]		45.4
Dist 3dB Peak [mm]		8.1



Plots of Measurement

Measurement Report
P17 LTE 38_QPSK20M_Left Cheek_0mm_Ch38150_1RB_OS0_Reader_4770_Ant 6
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 38	LTE-TDD, 10172-CAH	2610.000, 38150	7.58	1.93	37.5

Hardware Setup

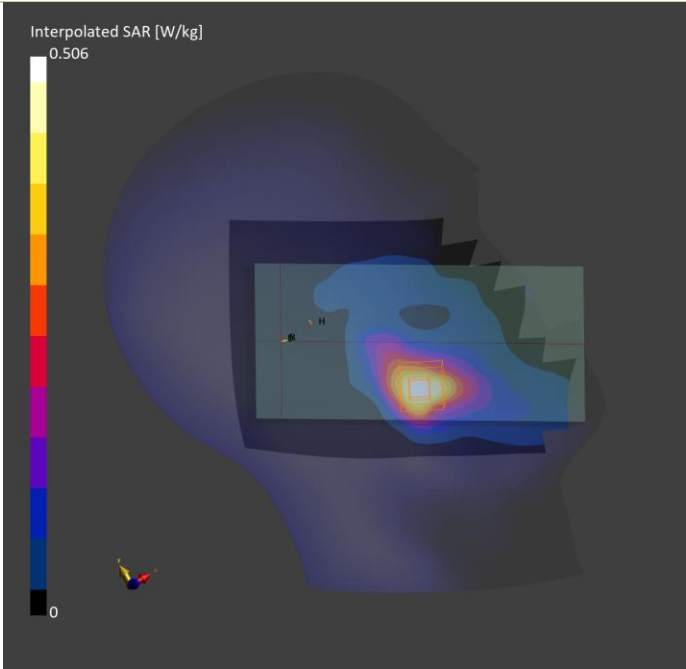
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-19	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-19	2024-04-19
psSAR1g [W/kg]	0.395	0.418
psSAR10g [W/kg]	0.196	0.220
Power Drift [dB]	0.08	0.01
M2/M1 [%]		56.5
Dist 3dB Peak [mm]		11.3



Plots of Measurement

Measurement Report

P18 LTE 41_QPSK20M_Left Cheek_Ch40185_1RB_OS0_Reader_4770_Ant 6

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 41	LTE-TDD, 10172-CAH	2549.500, 40185	7.58	1.93	40.2

Hardware Setup

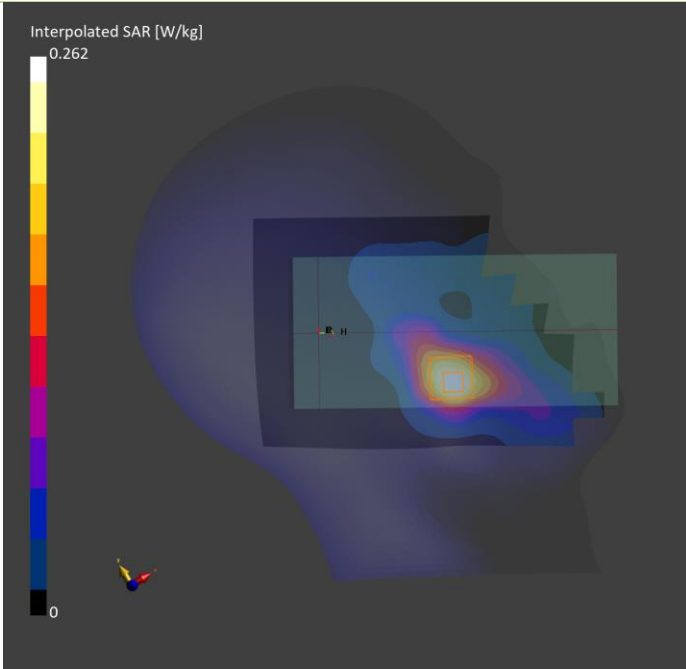
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-03	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-03	2024-05-03
psSAR1g [W/kg]	0.205	0.199
psSAR10g [W/kg]	0.107	0.053
Power Drift [dB]	0.08	-0.16
M2/M1 [%]		55.4
Dist 3dB Peak [mm]		5.1



Plots of Measurement

Measurement Report
P19 LTE 42_QPSK20M_Left Cheek_Ch43490_1RB_OS0_Reader_4770_Ant 7
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 42	LTE-TDD, 10172-CAH	3590.000, 43490	6.65	2.87	38.4

Hardware Setup

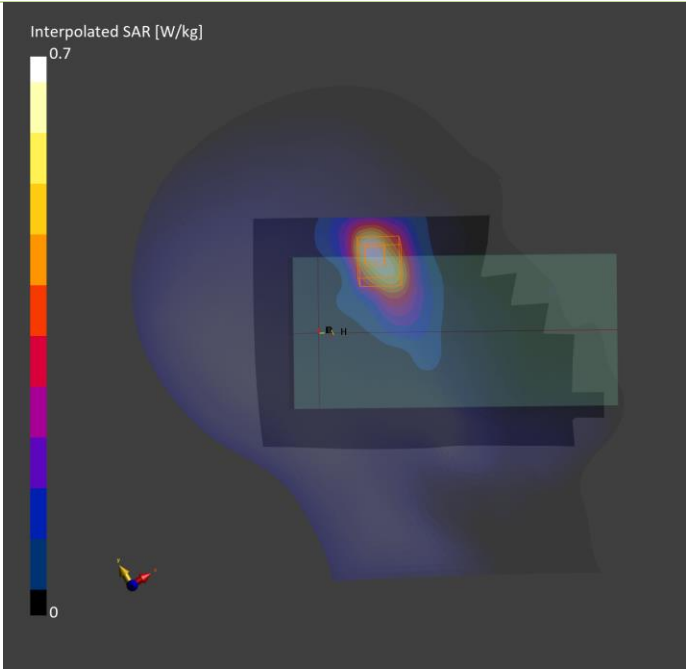
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-03	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-03	2024-05-03
psSAR1g [W/kg]	0.514	0.655
psSAR10g [W/kg]	0.241	0.272
Power Drift [dB]	-0.15	-0.02
M2/M1 [%]		62.5
Dist 3dB Peak [mm]		8.7



Plots of Measurement

Measurement Report

P20 LTE 43_QPSK20M_Left Cheek_Ch44240_1RB_OS0_Reader_4770_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 43	LTE-TDD, 10172-CAH	3665.000, 44240	6.6	2.94	38.3

Hardware Setup

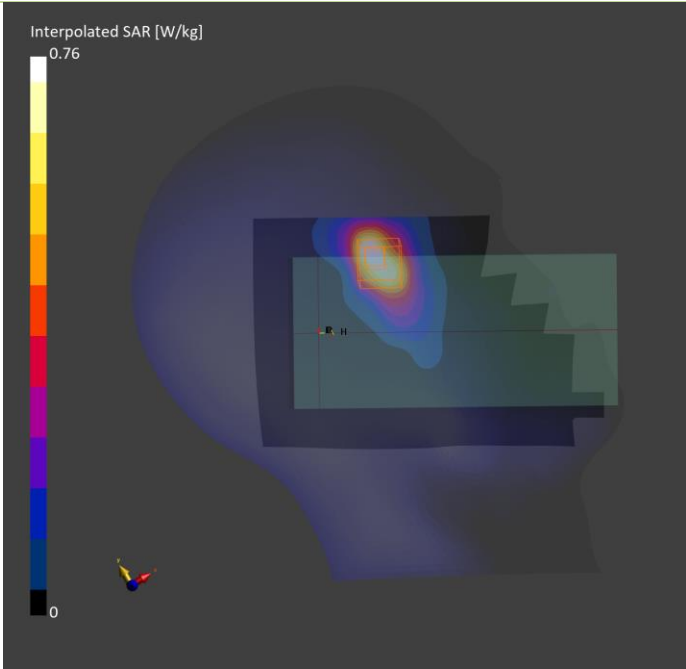
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-03	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-03	2024-05-03
psSAR1g [W/kg]	0.563	0.716
psSAR10g [W/kg]	0.263	0.293
Power Drift [dB]	-0.03	-0.02
M2/M1 [%]		61.3
Dist 3dB Peak [mm]		8.1



Plots of Measurement

Measurement Report
P21 LTE 48_QPSK20M_Left Cheek_Ch55340_1RB_OS0_Reader_4770_Ant 7
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 48	LTE-TDD, 10172-CAH	3560.000, 55340	6.65	2.85	38.8

Hardware Setup

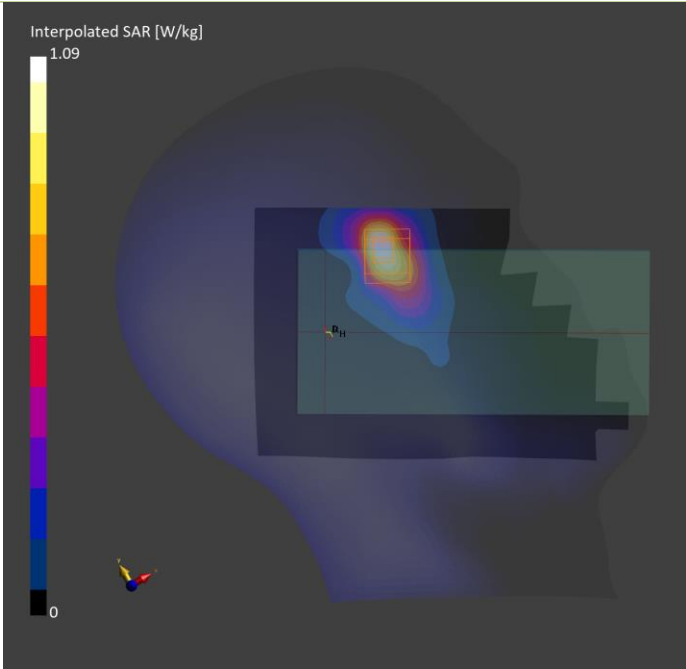
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	0.799	0.956
psSAR10g [W/kg]	0.361	0.401
Power Drift [dB]	0.01	-0.13
M2/M1 [%]		64.1
Dist 3dB Peak [mm]		8.4



Plots of Measurement

Measurement Report
P22 LTE 66_QPSK20M_Left Cheek_Ch132572_1RB_OS0_Reader_4770_Ant 7
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band 66	LTE-FDD, 10169-CAF	1770.000, 132572	9.0	1.38	39.8

Hardware Setup

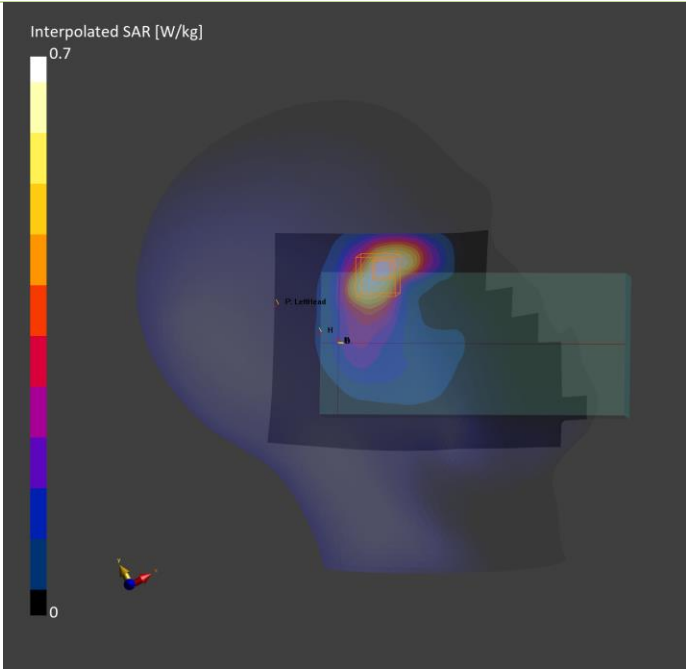
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-24	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-24	2024-04-24
psSAR1g [W/kg]	0.567	0.620
psSAR10g [W/kg]	0.327	0.349
Power Drift [dB]	-0.09	-0.11
M2/M1 [%]		57.9
Dist 3dB Peak [mm]		12.6



Plots of Measurement

Measurement Report
P23 LTE 71_QPSK10M_Right Cheek_Ch133297_1RB_OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band 71	LTE-FDD, 10169-CAF	680.500, 133297	10.71	0.885	43.5

Hardware Setup

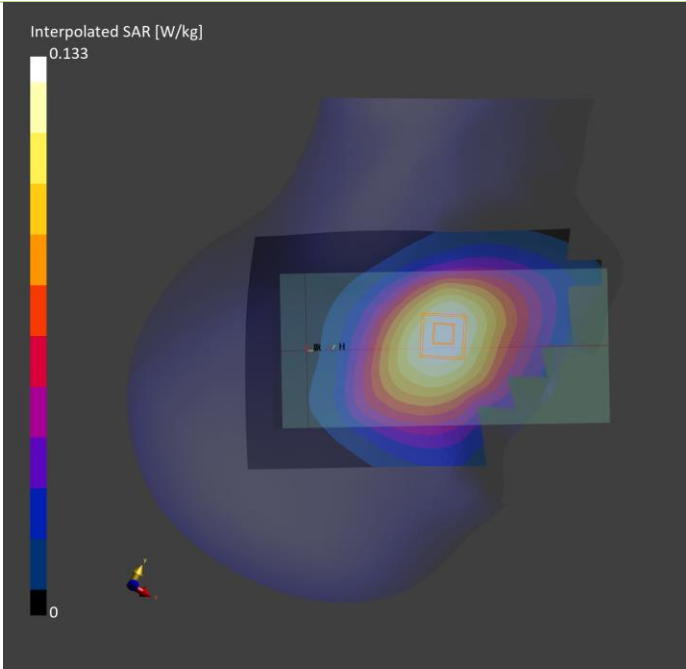
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-16	2024-04-16
psSAR1g [W/kg]	0.117	0.123
psSAR10g [W/kg]	0.082	0.096
Power Drift [dB]	0.02	-0.06
M2/M1 [%]		79.6
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report

P24 5GNR-n2_DFT-s QPSK20M_Left Cheek_Ch380000_1RB_OS1_Reader_4100_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n2	5G NR FR1 FDD, 10931-AAC	1900.000, 380000	8.37	1.45	39.6

Hardware Setup

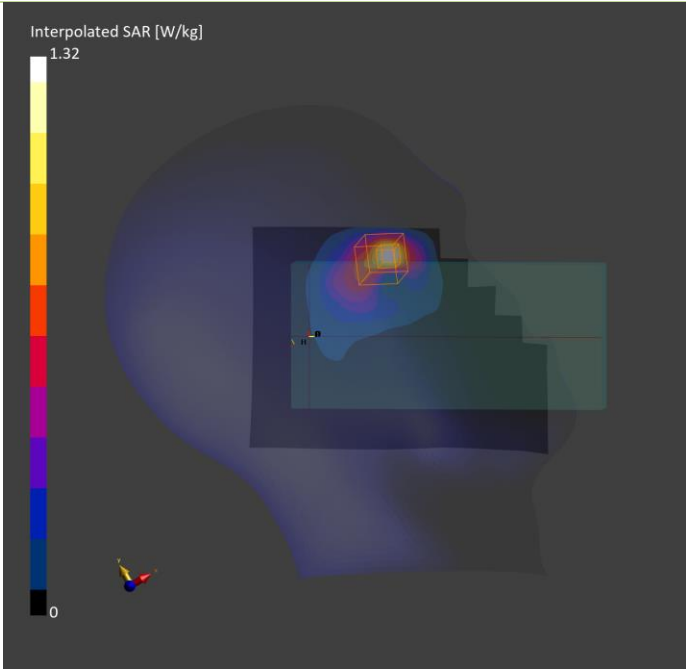
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-26	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-26	2024-04-26
psSAR1g [W/kg]	0.938	1.01
psSAR10g [W/kg]	0.452	0.496
Power Drift [dB]	-0.15	-0.05
M2/M1 [%]		59.3
Dist 3dB Peak [mm]		8.4



Plots of Measurement

Measurement Report

P25 5GNR-n5_DFT-s QPSK20M_Left Cheek_Ch166800_1RB_OS1_Reader_4770_Ant 0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n5	5G NR FR1 FDD, 10931-AAC	834.000, 166800	10.39	0.926	42.7

Hardware Setup

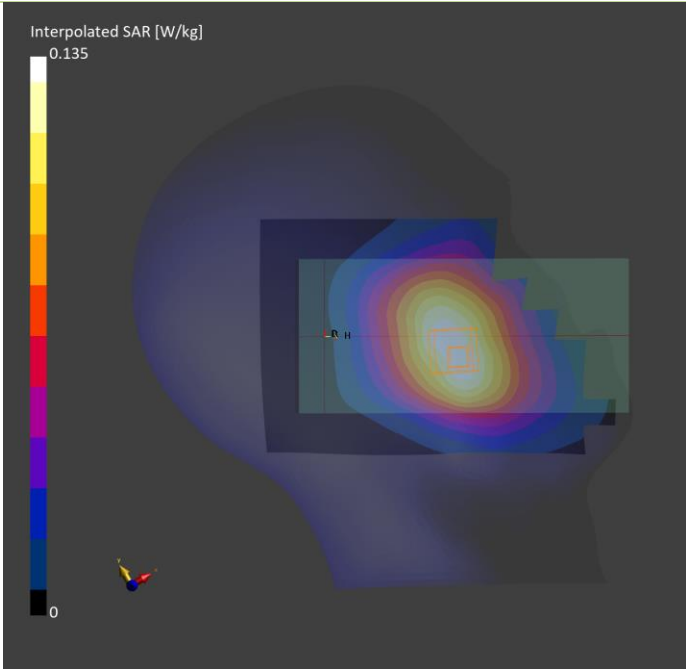
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.118	0.127
psSAR10g [W/kg]	0.081	0.098
Power Drift [dB]	-0.01	0.01
M2/M1 [%]		77.8
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report

P26 5GNR-n7_DFT-s QPSK20M_Left Cheek_Ch512000_1RB_OS1_Reader_4770_Ant 6

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n7	5G NR FR1 FDD, 10931-AAC	2560.000, 512000	7.58	1.94	40.2

Hardware Setup

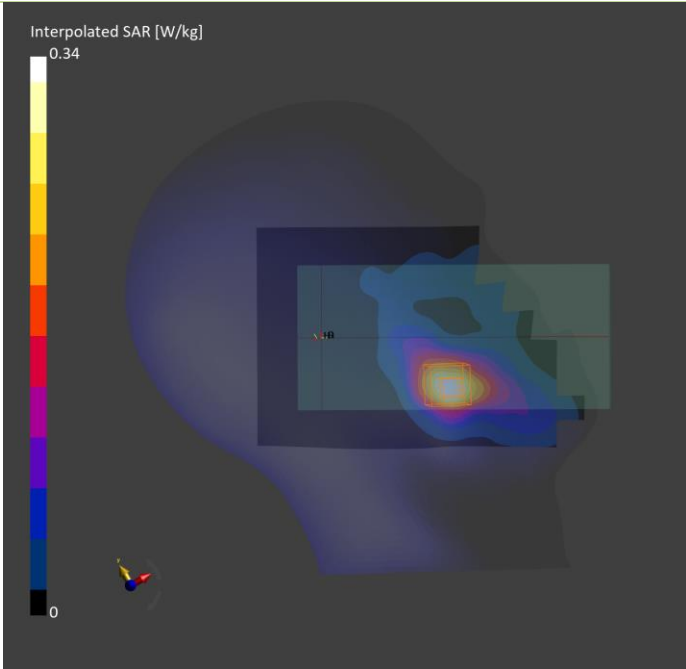
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	0.263	0.287
psSAR10g [W/kg]	0.133	0.154
Power Drift [dB]	0.09	0.01
M2/M1 [%]		56.8
Dist 3dB Peak [mm]		10.9



Plots of Measurement

Measurement Report
P27 5GNR-n12_DFT-s QPSK15M_Right Cheek_Ch141700_1RB_OS1_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band n12	5G NR FR1 FDD, 10930-AAC	708.500, 141700	10.35	0.877	40.2

Hardware Setup

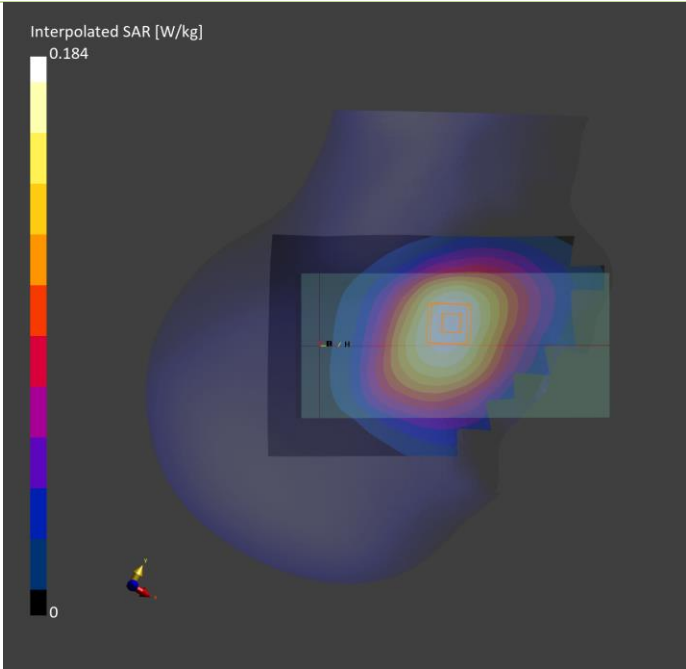
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-25	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-25	2024-04-25
psSAR1g [W/kg]	0.162	0.166
psSAR10g [W/kg]	0.114	0.133
Power Drift [dB]	-0.01	-0.05
M2/M1 [%]		81.9
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P28 5GNR-n14_DFT-s QPSK10M_Right Cheek_Ch158600_1RB_OS1_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band n14	5G NR FR1 FDD, 10929-AAD	793.000, 158600	10.35	0.905	40.2

Hardware Setup

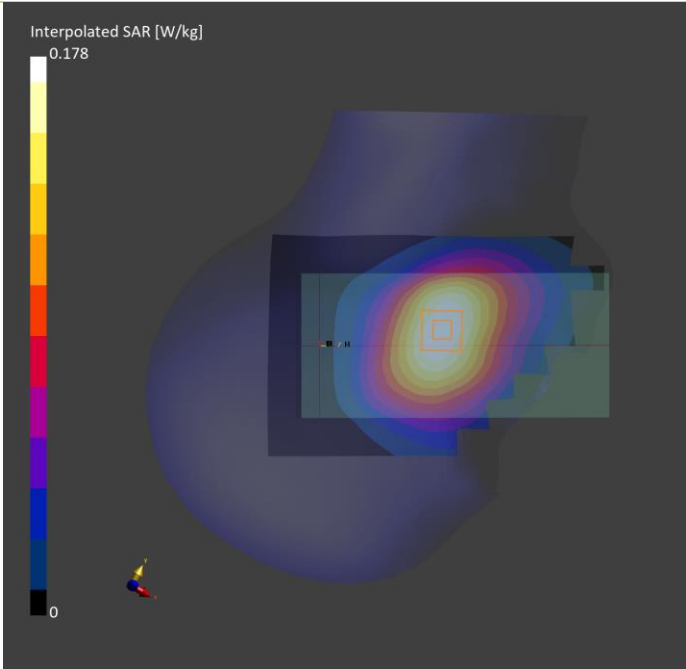
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-25	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-25	2024-04-25
psSAR1g [W/kg]	0.157	0.166
psSAR10g [W/kg]	0.110	0.131
Power Drift [dB]	0.07	-0.01
M2/M1 [%]		81.9
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report

P29 5GNR-n25_DFT-s QPSK20M_Left Cheek_Ch381000_1RB_OS1_Reader_4100_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n25	5G NR FR1 FDD, 10931-AAC	1905.000, 381000	8.37	1.45	39.6

Hardware Setup

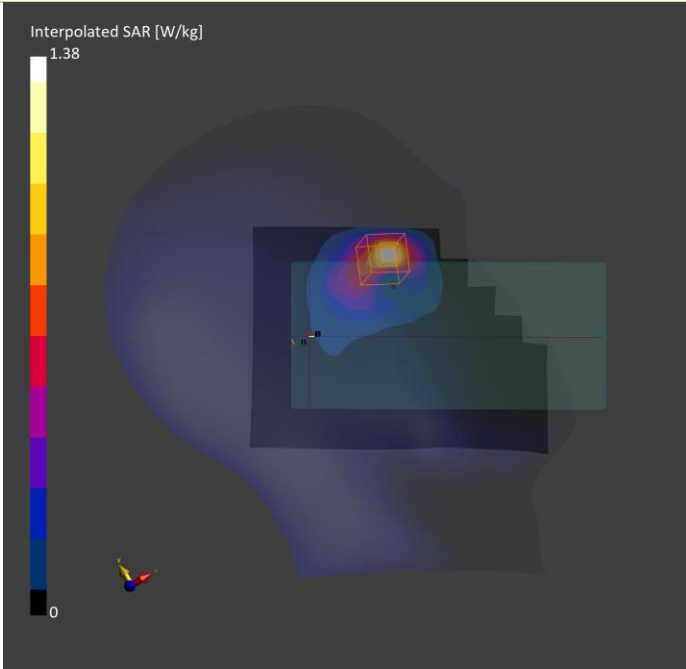
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-26	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-26	2024-04-26
psSAR1g [W/kg]	0.975	1.04
psSAR10g [W/kg]	0.465	0.506
Power Drift [dB]	-0.03	0.01
M2/M1 [%]		58.8
Dist 3dB Peak [mm]		8.4



Plots of Measurement

Measurement Report
P30 5GNR-n26_DFT-s QPSK20M_Right Cheek_Ch167800_1RB_OS1_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band n26	5G NR FR1 FDD, 10931-AAC	839.000, 167800	10.39	0.928	42.7

Hardware Setup

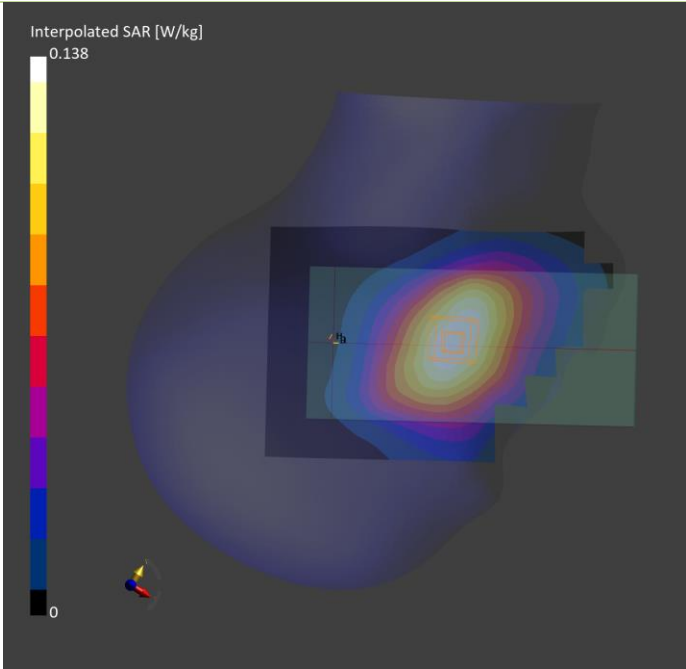
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-17	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-17	2024-04-17
psSAR1g [W/kg]	0.121	0.133
psSAR10g [W/kg]	0.084	0.104
Power Drift [dB]	0.13	-0.06
M2/M1 [%]		80.0
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P31 5GNR-n38_DFT-s QPSK40M_Right Cheek_Ch520000_1RB_OS1_Reader_4770_Ant 5
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band n38	5G NR FR1 TDD, 10903-AAD	2600.000, 520000	7.58	1.93	40.2

Hardware Setup

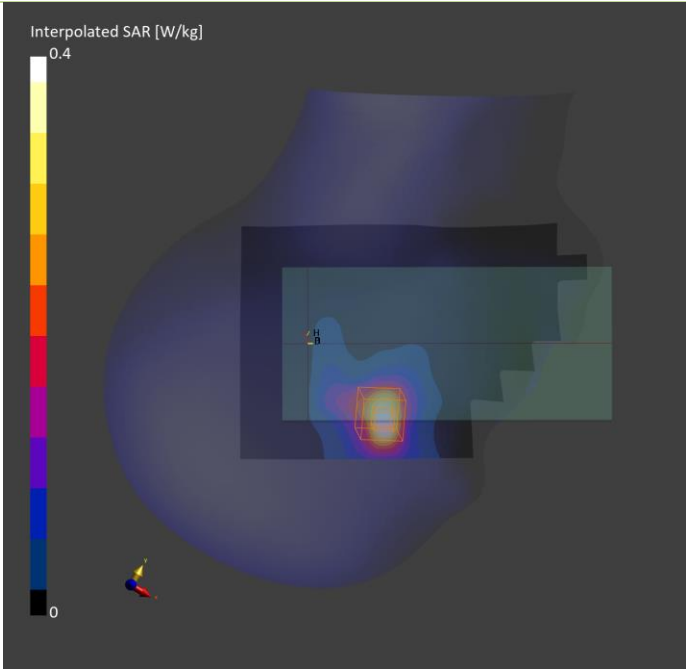
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	0.302	0.382
psSAR10g [W/kg]	0.147	0.169
Power Drift [dB]	0.05	-0.01
M2/M1 [%]		47.2
Dist 3dB Peak [mm]		8.1



Plots of Measurement

Measurement Report
P32 5GNR-n41_HPUE_DFT-s QPSK1000M_Right Cheek_Ch523302_1RB_OS1_Reader_4770_Ant 5
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band n41	5G NR FR1 TDD, 10866-AAF	2616.510, 523302	7.58	1.94	40.1

Hardware Setup

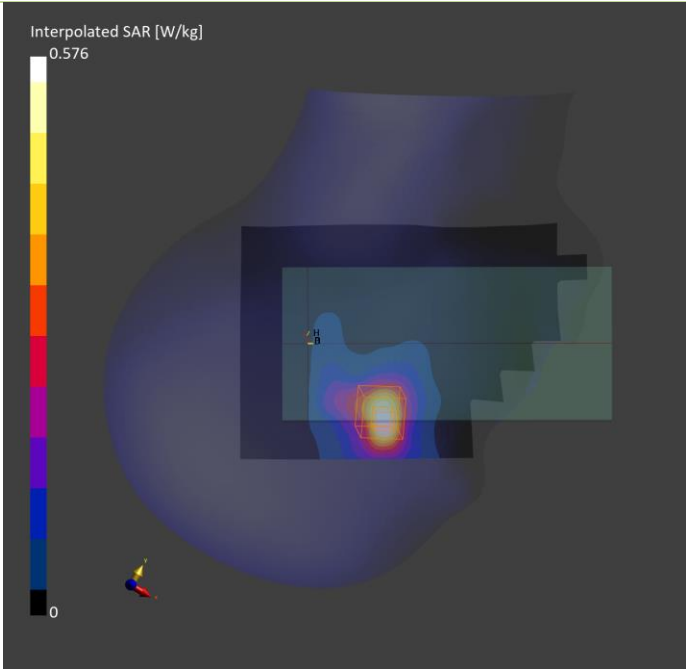
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-07	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-07	2024-05-07
psSAR1g [W/kg]	0.437	0.556
psSAR10g [W/kg]	0.214	0.251
Power Drift [dB]	0.01	-0.01
M2/M1 [%]		47.7
Dist 3dB Peak [mm]		8.6



Plots of Measurement

Measurement Report

P33 5GNR-n48_DFT-s QPSK40M_Left Cheek_Ch642888_1RB_OS1_Reader_4770_Ant 7

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n48	5G NR FR1 TDD, 10903-AAD	3643.32, 642888	6.6	2.93	38.6

Hardware Setup

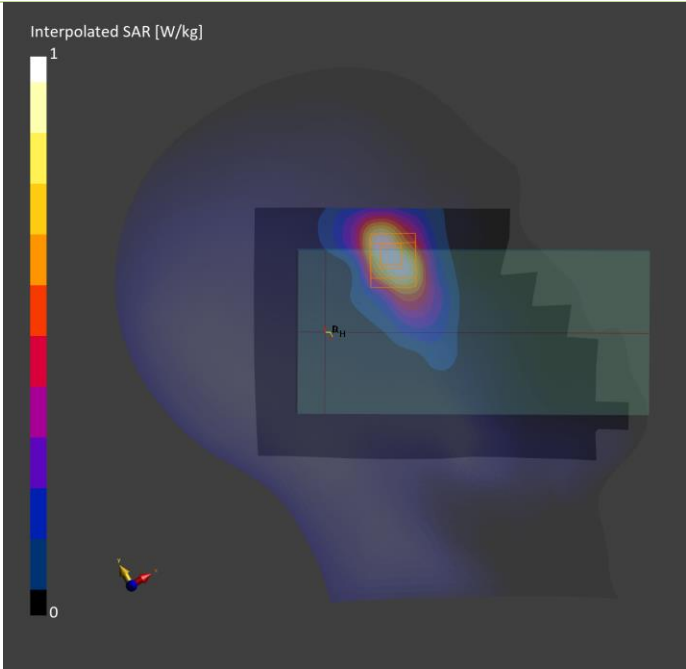
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-05	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-05	2024-05-05
psSAR1g [W/kg]	0.752	0.995
psSAR10g [W/kg]	0.356	0.415
Power Drift [dB]	0.06	0.03
M2/M1 [%]		63.5
Dist 3dB Peak [mm]		8.2



Plots of Measurement

Measurement Report
P34 5GNR-n66_DFT-s QPSK20M_Left Cheek_Ch349000_1RB_OS104_Reader_4770_Ant 7
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n66	5G NR FR1 FDD, 10931-AAC	1745.000, 349000	8.74	1.37	37.9

Hardware Setup

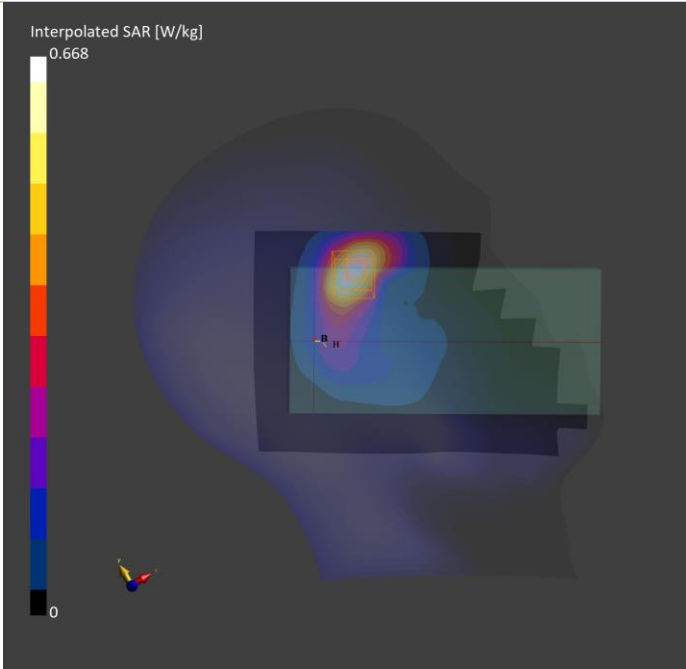
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-14	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-14	2024-05-14
psSAR1g [W/kg]	0.542	0.582
psSAR10g [W/kg]	0.315	0.335
Power Drift [dB]	-0.10	-0.07
M2/M1 [%]		56.7
Dist 3dB Peak [mm]		12.6



Plots of Measurement

Measurement Report
P35 5GNR-n71_DFT-s QPSK20M_Right Cheek_Ch136100_1RB_OS1_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Cheek, 0.00	Band n71	5G NR FR1 FDD, 10931-AAC	680.500, 136100	10.35	0.867	40.4

Hardware Setup

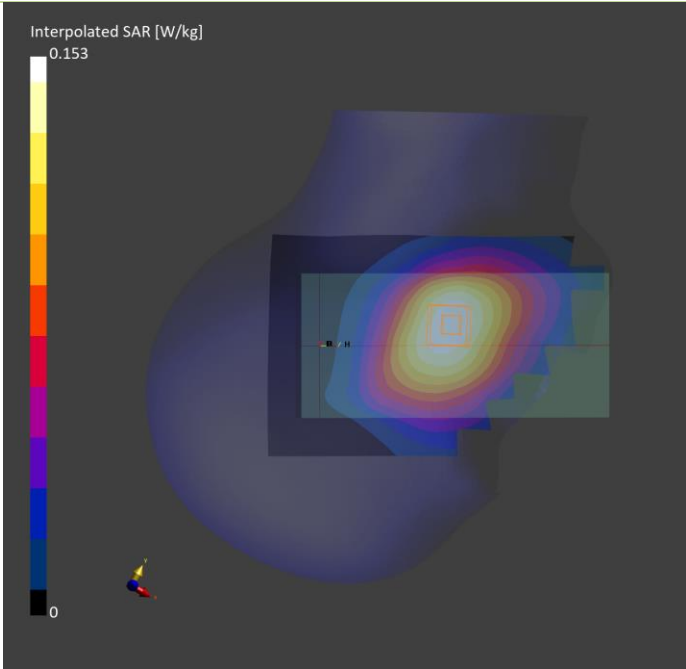
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2122	H06T27N9, 2024-Apr-25	EX3DV4 - SN7472, 2023-10-23	DAE4 Sn1590, 2023-09-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-25	2024-04-25
psSAR1g [W/kg]	0.135	0.138
psSAR10g [W/kg]	0.096	0.110
Power Drift [dB]	0.03	-0.13
M2/M1 [%]		77.0
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P36 5GNR-n77_HPUE_DFT-s QPSK100M_Left Cheek_Ch633332_1RB_OS1_Reader_4770_Ant 7
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n77	5G NR FR1 TDD, 10866-AAF	3499.980, 633332	6.65	2.83	39.2

Hardware Setup

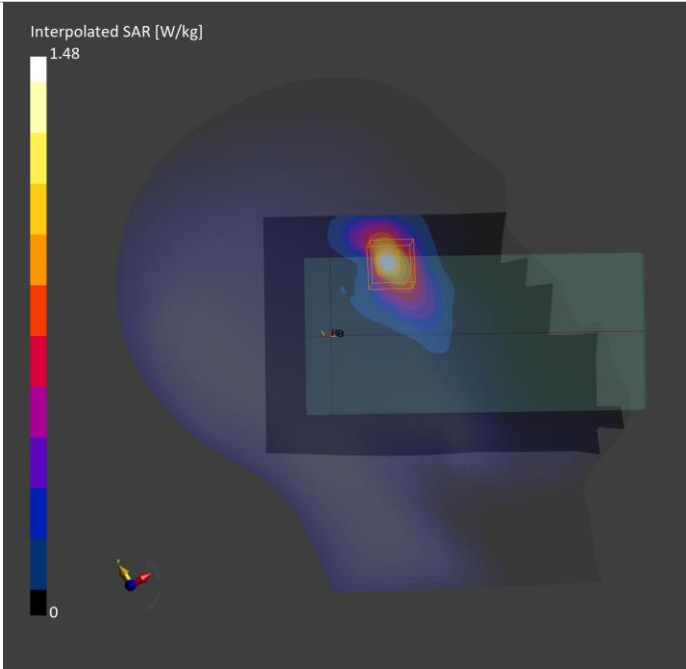
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-09	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-09	2024-05-09
psSAR1g [W/kg]	1.03	1.12
psSAR10g [W/kg]	0.428	0.470
Power Drift [dB]	0.03	-0.05
M2/M1 [%]		64.3
Dist 3dB Peak [mm]		7.3



Plots of Measurement

Measurement Report

P38 5GNR-n78_DFT-s QPSK100M_Left Cheek_Ch633332_1RB_OS1_Reader_4770_Ant 7+5

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	Band n78	5G NR FR1 TDD, 10866-AAF	3499.980, 633332	6.65	2.79	39.6

Hardware Setup

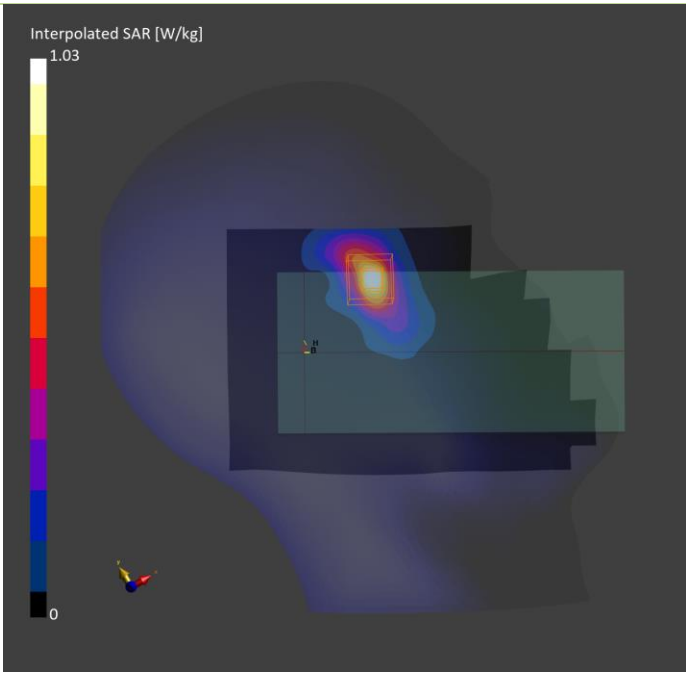
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-10	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-10	2024-05-10
psSAR1g [W/kg]	0.712	0.764
psSAR10g [W/kg]	0.284	0.309
Power Drift [dB]	0.18	0.03
M2/M1 [%]		64.0
Dist 3dB Peak [mm]		7.7



Plots of Measurement

Measurement Report
P40 WLAN 2.4G_802.11b_Left Cheek_Ch6_Reader_4770_Ant 2
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	WLAN 2.4GHz	WLAN, 10012-CAB	2437.000, 6	7.65	1.82	39.8

Hardware Setup

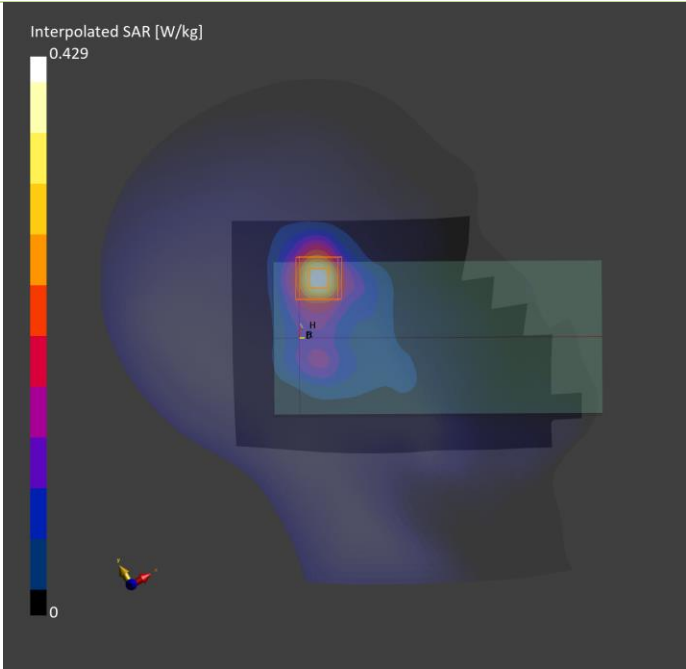
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-28	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-28	2024-04-28
psSAR1g [W/kg]	0.321	0.333
psSAR10g [W/kg]	0.153	0.159
Power Drift [dB]	-0.01	-0.03
M2/M1 [%]		43.9
Dist 3dB Peak [mm]		9.9



Plots of Measurement

Measurement Report
P41 WLAN 5.3G_802.11ac VHT40_Left Cheek_Ch54_Reader_4770_Ant 2
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	WLAN 5GHz	WLAN, 10534-AAD	5270.000, 54	5.52	4.66	37.2

Hardware Setup

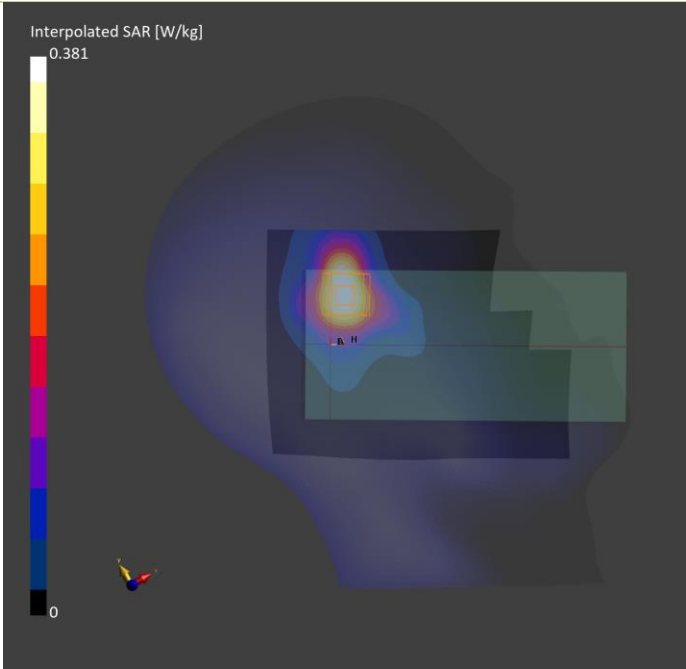
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-27	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-27	2024-04-27
psSAR1g [W/kg]	0.286	0.346
psSAR10g [W/kg]	0.121	0.128
Power Drift [dB]	0.17	-0.01
M2/M1 [%]		67.8
Dist 3dB Peak [mm]		8.6



Plots of Measurement

Measurement Report
P42 WLAN 5.6G_802.11ac VHT40_Left Cheek_Ch110_Reader_4770_Ant 2
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	WLAN 5GHz	WLAN, 10534-AAD	5550.000, 110	4.8	4.90	35.3

Hardware Setup

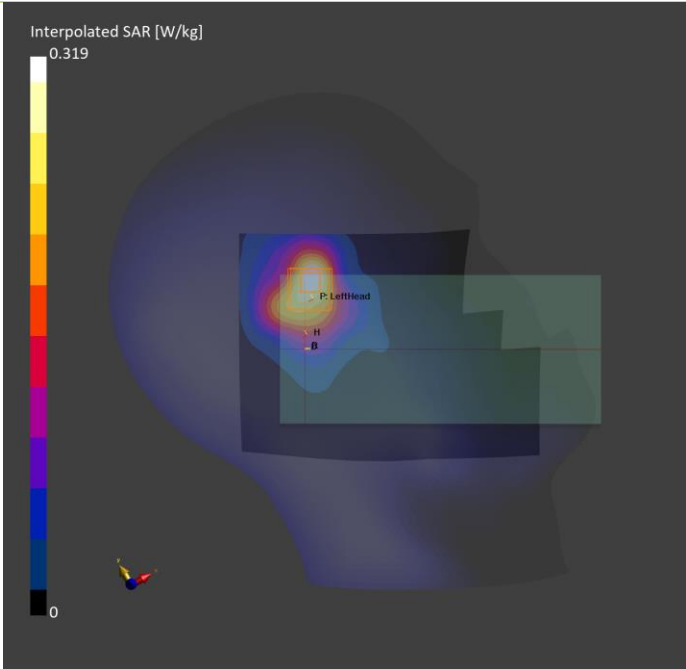
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-27	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-27	2024-04-27
psSAR1g [W/kg]	0.229	0.356
psSAR10g [W/kg]	0.098	0.126
Power Drift [dB]	0.17	-0.11
M2/M1 [%]		64.5
Dist 3dB Peak [mm]		8.0



Plots of Measurement

Measurement Report
P43 WLAN 5.8G_802.11ac VHT40_Left Cheek_Ch159_Reader_4770_Ant 2
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	WLAN 5GHz	WLAN, 10534-AAD	5795.000, 159	4.96	5.19	34.9

Hardware Setup

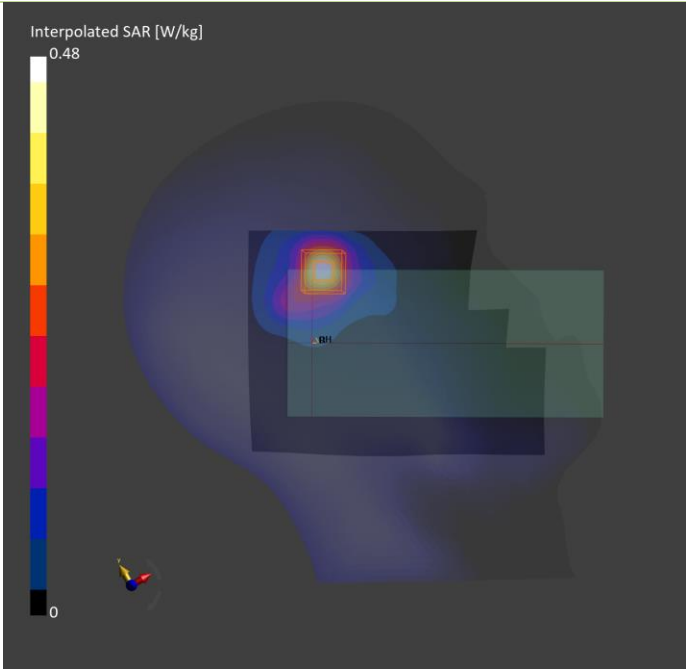
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-27	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-27	2024-04-27
psSAR1g [W/kg]	0.329	0.364
psSAR10g [W/kg]	0.127	0.134
Power Drift [dB]	0.12	-0.11
M2/M1 [%]		59.8
Dist 3dB Peak [mm]		6.6



Plots of Measurement

Measurement Report
P44 BT_BDR_Left Cheek_Ch0_Reader_4770_Ant 2
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	Left Cheek, 0.00	ISM 2.4 GHz Band	Bluetooth, 10032-CAA	2402.000, 0	7.65	1.79	39.8

Hardware Setup

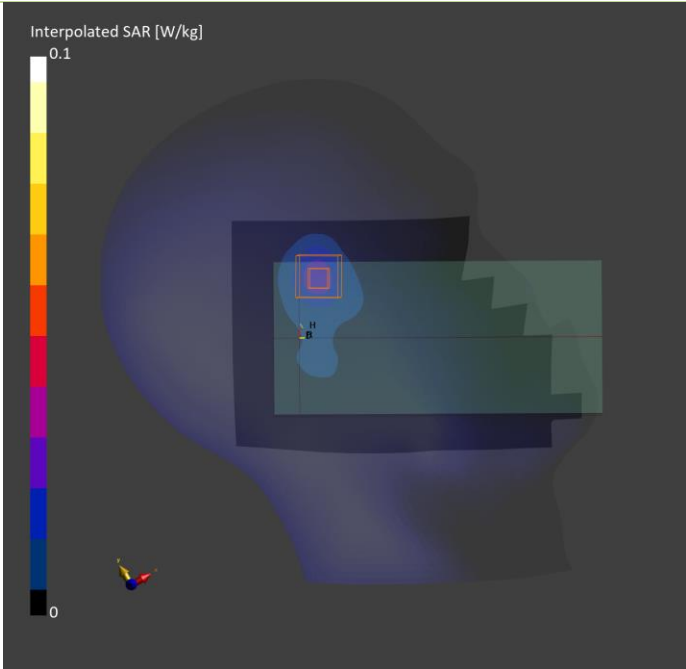
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-Apr-28	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-28	2024-04-28
psSAR1g [W/kg]	0.025	0.026
psSAR10g [W/kg]	0.012	0.012
Power Drift [dB]	0.17	-0.18
M2/M1 [%]		43.8
Dist 3dB Peak [mm]		10.0



Plots of Measurement

Measurement Report

P137 UNII-5_802.11ax HE160_Right Tilted_Ch79_Reader_4770_Ant 2

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	Right Tilted, 0.00	U-NII-5	WLAN, 10755-AAC	6345.000, 79	5.4	5.77	35.4

Hardware Setup

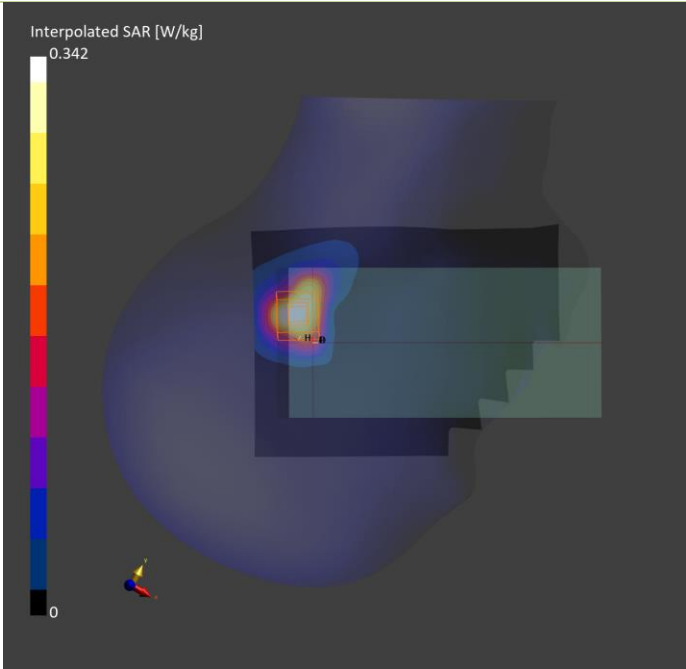
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H51T72N4 , 2024-Apr-29	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 180.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	7.5 x 7.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-04-29	2024-04-29
psSAR1g [W/kg]	0.265	0.324
psSAR10g [W/kg]	0.105	0.107
Power Drift [dB]	-0.18	-0.13
M2/M1 [%]		57.9
Dist 3dB Peak [mm]		8.8



Plots of Measurement

Measurement Report
P137 PD UNII-5_802.11ax HE160_Right Tilted_Ch79_Reader_4770_Ant 2
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
, P23100614	165.0 x 80.0 x 19.0		Phone

Exposure Conditions

Phantom Section	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor
5G Air	Right Tilted, 2.00	U-NII-5	WLAN, 10755-AAC	6345.0, 79	1.0

Hardware Setup

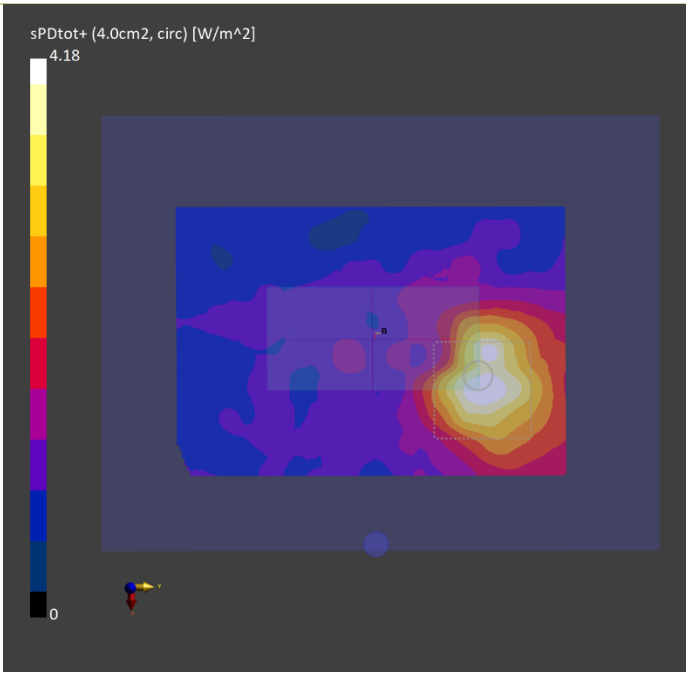
Phantom	Medium	Probe, Calibration Date	DAE, Calibration Date
mmWave- 1029	---Air	EUmmWV4 - SN9615_F1-55GHz, 2023-07-10	DAE4 Sn1431, 2023-08-24

Scan Setup

	5G Scan	
Grid Extents [mm]	95.0 x	95.0
Grid Steps [lambda]	0.0529 x	0.0529
Sensor Surface [mm]		2.0
MAIA		Y

Measurement Results

	5G Scan
Date	2024-05-15
Avg. Area [cm²]	4.00
psPDn+ [W/m²]	2.60
psPDtot+ [W/m²]	4.18
psPDmod+ [W/m²]	5.6
E _{max} [V/m]	40.2
Power Drift [dB]	0.04



Plots of Measurement

Measurement Report
P45 GSM850_GPRS 4Tx Slot_Rear Face_10mm_Ch128_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	GSM 850	GSM, 10028-DAC	824.200, 128	10.39	0.88	43.3

Hardware Setup

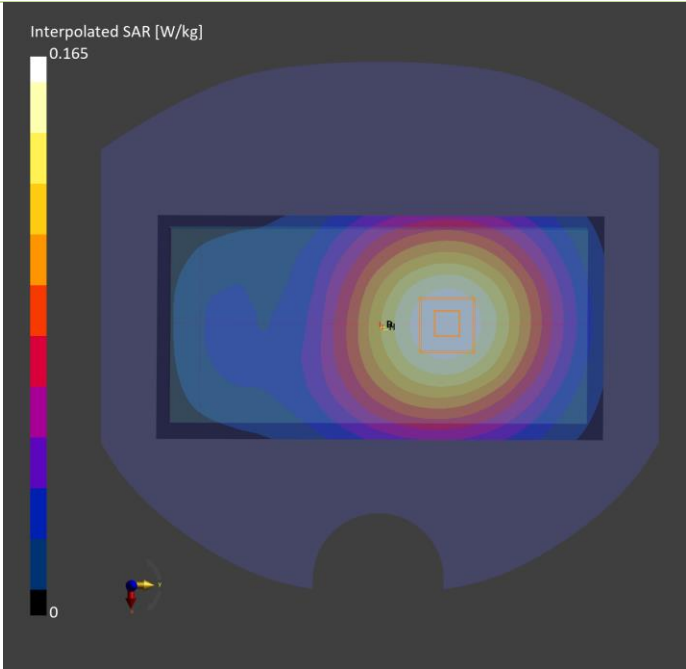
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-06	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-06	2024-05-06
psSAR1g [W/kg]	0.145	0.153
psSAR10g [W/kg]	0.102	0.114
Power Drift [dB]	0.01	-0.08
M2/M1 [%]		75.1
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P46 GSM1900_GPRS 4Tx Slot_Rear Face_10mm_Ch512_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	PCS 1900	GSM, 10028-DAC	1850.200, 512	8.31	1.38	41.5

Hardware Setup

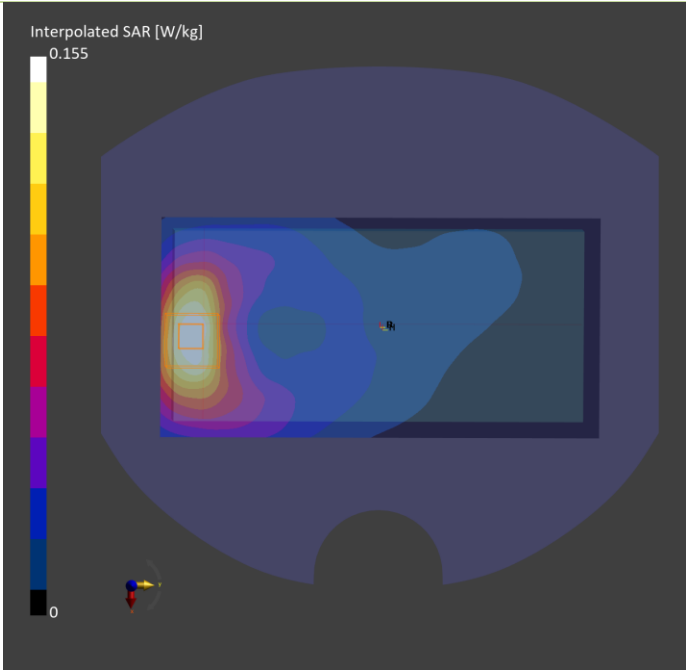
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-06	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1585, 2023-07-14

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-06	2024-05-06
psSAR1g [W/kg]	0.128	0.121
psSAR10g [W/kg]	0.075	0.072
Power Drift [dB]	0.04	-0.09
M2/M1 [%]		60.0
Dist 3dB Peak [mm]		14.4



Plots of Measurement

Measurement Report
P47 WCDMAII_RMC12.2K_Rear Face_10mm_Ch9262_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 2	WCDMA, 10011-CAC	1852.400, 9262	8.31	1.39	41.2

Hardware Setup

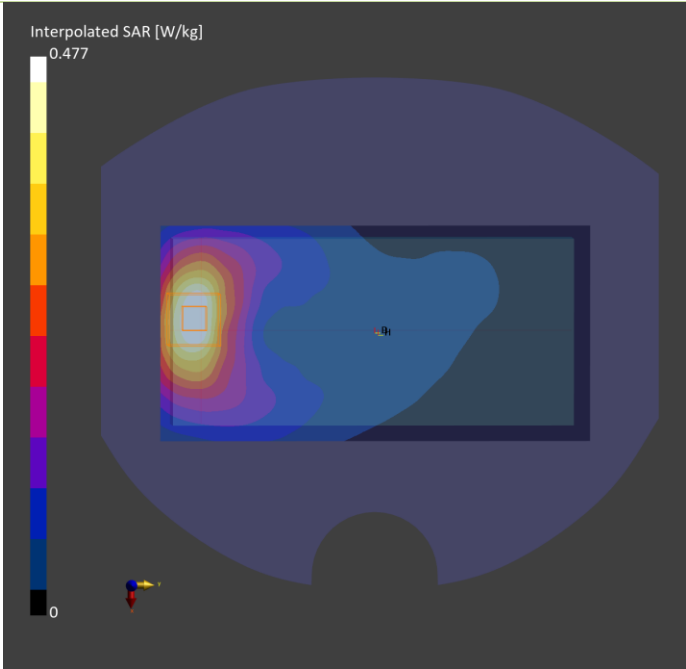
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-08	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-08	2024-05-08
psSAR1g [W/kg]	0.400	0.409
psSAR10g [W/kg]	0.235	0.249
Power Drift [dB]	0.05	0.01
M2/M1 [%]		61.3
Dist 3dB Peak [mm]		14.5



Plots of Measurement

Measurement Report
P48 WCDMA IV_RMC12.2K_Rear Face_10mm_Ch1513_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 4	WCDMA, 10011-CAC	1752.600, 1513	8.74	1.34	41.3

Hardware Setup

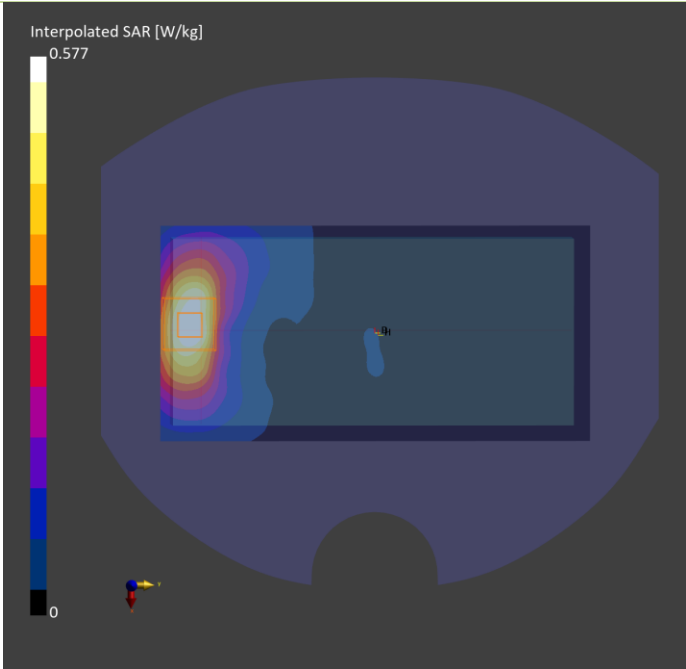
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-08	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-08	2024-05-08
psSAR1g [W/kg]	0.480	0.499
psSAR10g [W/kg]	0.277	0.301
Power Drift [dB]	0.03	0.01
M2/M1 [%]		63.4
Dist 3dB Peak [mm]		12.8



Plots of Measurement

Measurement Report
P49 WCDMA V_RMC12.2K_Rear Face_10mm_Ch4132_Reader_4100_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 5	WCDMA, 10011-CAC	826.400, 4132	10.39	0.93	43.1

Hardware Setup

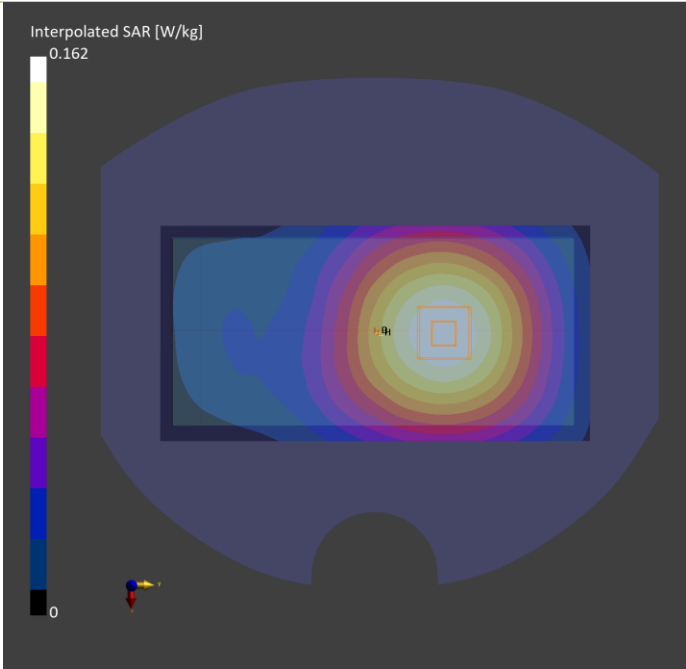
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-08	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-08	2024-05-08
psSAR1g [W/kg]	0.143	0.154
psSAR10g [W/kg]	0.100	0.116
Power Drift [dB]	0.09	-0.01
M2/M1 [%]		72.8
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P50 LTE 2_QPSK20M_Rear Face_10mm_Ch18700_1RB OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 2	LTE-FDD, 10169-CAF	1860.000, 18700	8.31	1.43	38.2

Hardware Setup

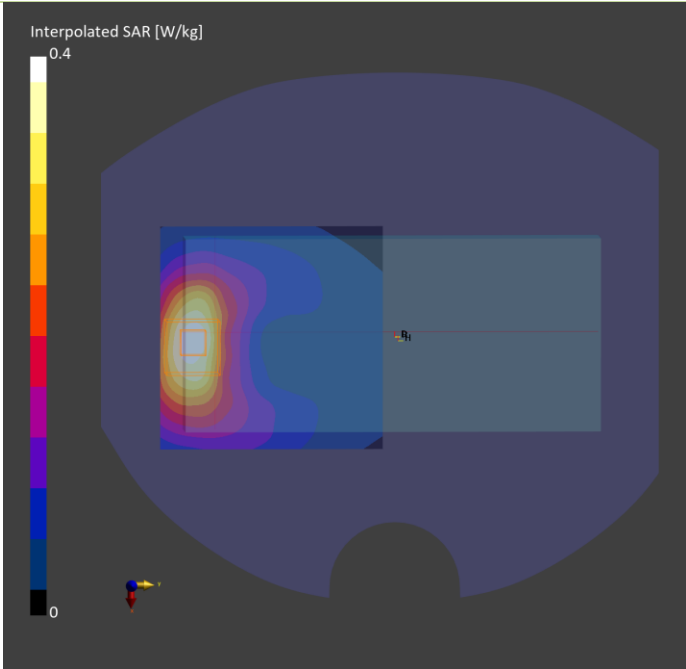
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-11	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 90.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-11	2024-05-11
psSAR1g [W/kg]	0.330	0.341
psSAR10g [W/kg]	0.191	0.204
Power Drift [dB]	0.05	0.01
M2/M1 [%]		62.0
Dist 3dB Peak [mm]		14.4



Plots of Measurement

Measurement Report
P51 LTE 4_QPSK20M_Rear Face_10mm_Ch20300_1RB OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 4	LTE-FDD, 10169-CAF	1745.000, 20300	8.74	1.37	38.4

Hardware Setup

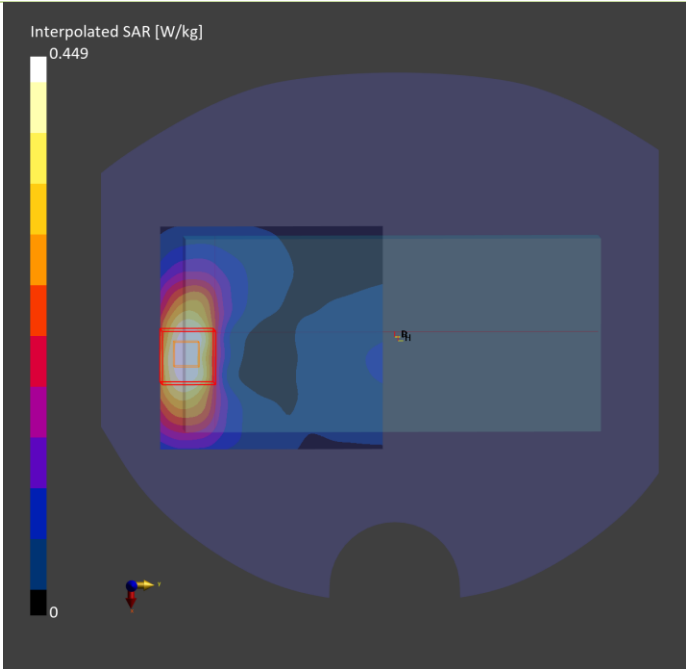
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-11	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 90.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-11	2024-05-11
psSAR1g [W/kg]	0.380	0.397
psSAR10g [W/kg]	0.217	0.233
Power Drift [dB]	0.04	0.02
M2/M1 [%]		61.8
Dist 3dB Peak [mm]		12.8



Plots of Measurement

Measurement Report
P52 LTE 5_QPSK10M_Rear Face_10mm_Ch20600_1RB OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 5	LTE-FDD, 10175-CAH	844.000, 20600	10.39	0.95	43.2

Hardware Setup

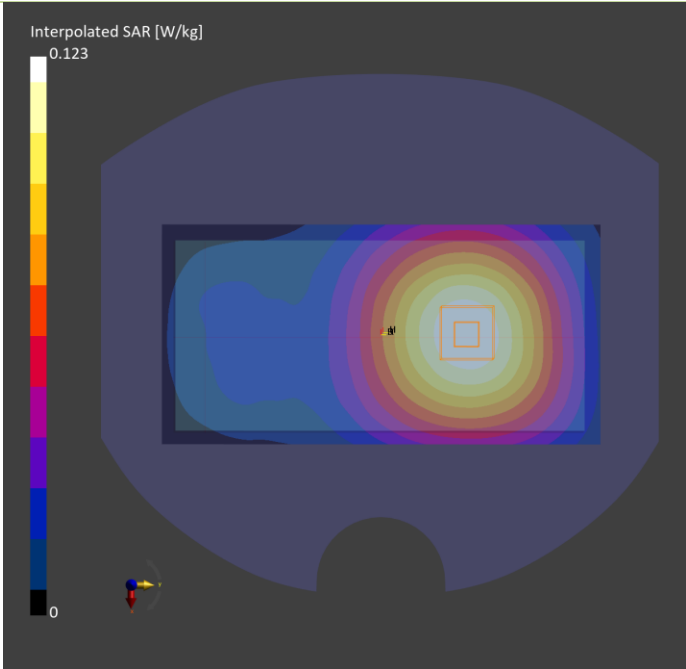
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.109	0.114
psSAR10g [W/kg]	0.076	0.086
Power Drift [dB]	0.08	0.06
M2/M1 [%]		75.5
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P53 LTE 7_QPSK20M_Front Face_10mm_Ch21350_1RB OS0_Reader_4770_Ant 6
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Front Face, 10.00	Band 7	LTE-FDD, 10169-CAF	2560.000, 21350	7.58	1.97	37.2

Hardware Setup

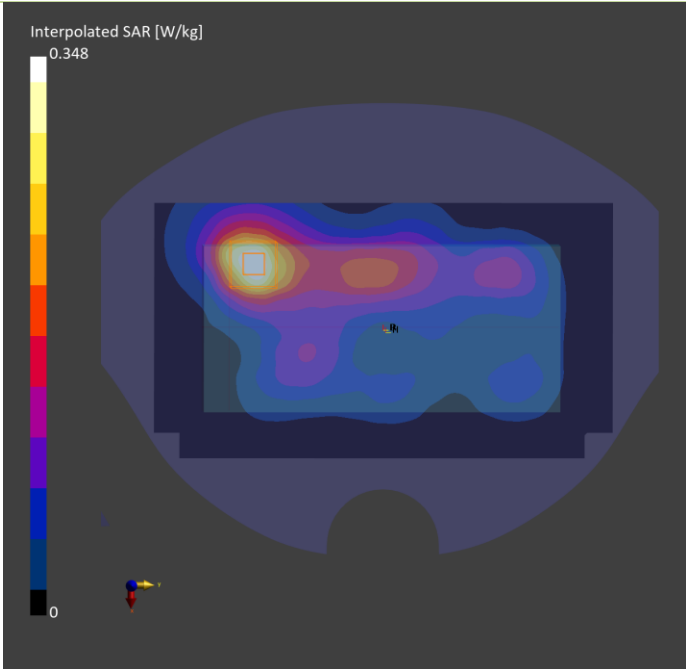
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	0.283	0.299
psSAR10g [W/kg]	0.150	0.157
Power Drift [dB]	0.10	0.09
M2/M1 [%]		79.3
Dist 3dB Peak [mm]		12.8



Plots of Measurement

Measurement Report
P54 LTE 12_QPSK10M_Rear Face_10mm_Ch23130_1RB OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 12	LTE-FDD, 10175-CAH	711.000, 23130	10.71	0.89	43.5

Hardware Setup

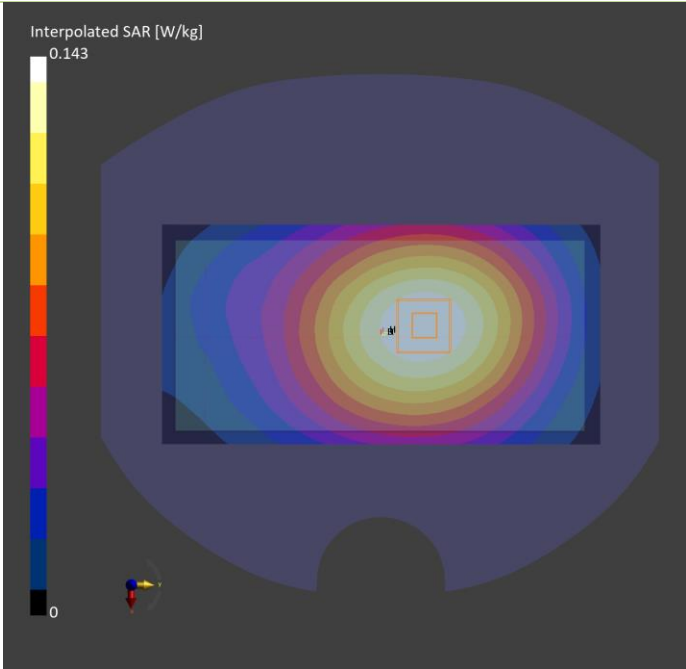
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.127	0.133
psSAR10g [W/kg]	0.091	0.102
Power Drift [dB]	0.05	0.04
M2/M1 [%]		77.6
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P55 LTE 13_QPSK10M_Rear Face_10mm_Ch23230_1RB OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 13	LTE-FDD, 10175-CAH	782.000, 23230	10.71	0.92	43.5

Hardware Setup

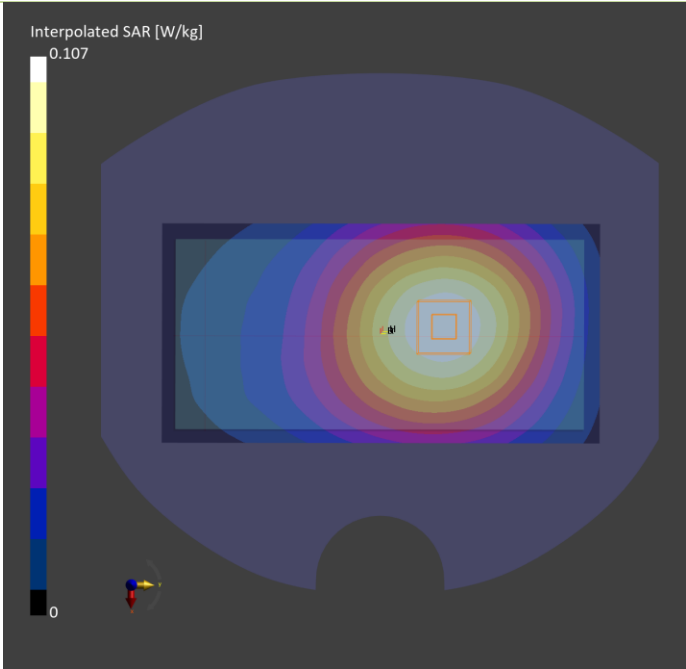
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.094	0.098
psSAR10g [W/kg]	0.067	0.075
Power Drift [dB]	0.03	0.07
M2/M1 [%]		76.8
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P56 LTE 14_QPSK10M_Rear Face_10mm_Ch23330_1RB OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 14	LTE-FDD, 10175-CAH	793.000, 23330	10.71	0.92	43.4

Hardware Setup

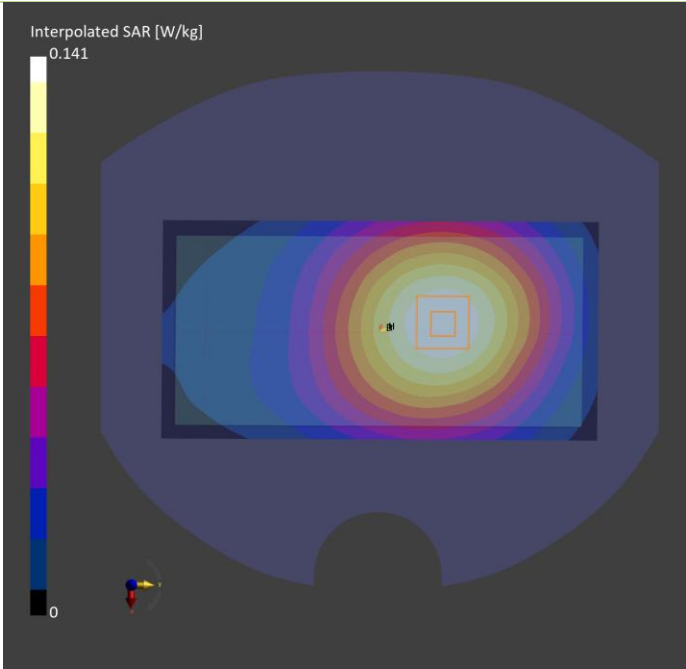
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.124	0.132
psSAR10g [W/kg]	0.088	0.101
Power Drift [dB]	0.03	0.05
M2/M1 [%]		76.9
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P57 LTE 17_QPSK10M_Rear Face_10mm_Ch23800_1RB OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 17	LTE-FDD, 10175-CAH	711.000, 23800	10.71	0.89	43.5

Hardware Setup

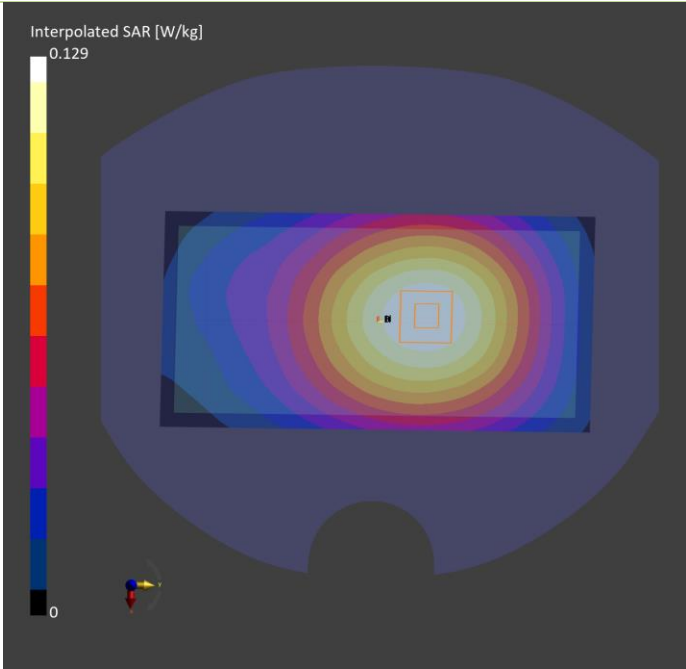
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-12	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-12	2024-05-12
psSAR1g [W/kg]	0.115	0.119
psSAR10g [W/kg]	0.082	0.092
Power Drift [dB]	0.05	0.04
M2/M1 [%]		90.3
Dist 3dB Peak [mm]		> 18.0



Plots of Measurement

Measurement Report
P58 LTE 25_QPSK20M_Rear Face_10mm_Ch26590_1RB OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 25	LTE-FDD, 10169-CAF	1905.000, 26590	8.31	1.46	38.2

Hardware Setup

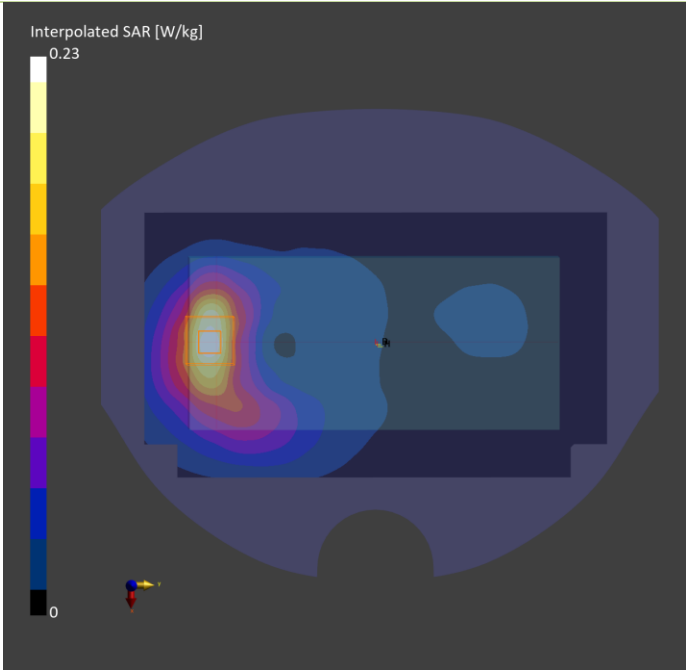
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-11	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-11	2024-05-11
psSAR1g [W/kg]	0.185	0.192
psSAR10g [W/kg]	0.103	0.111
Power Drift [dB]	0.10	0.00
M2/M1 [%]		58.3
Dist 3dB Peak [mm]		12.9



Plots of Measurement

Measurement Report
P59 LTE 26_QPSK15M_Rear Face_10mm_Ch26865_1RB OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 26	LTE-FDD, 10181-CAF	831.500, 26865	10.39	0.87	42.8

Hardware Setup

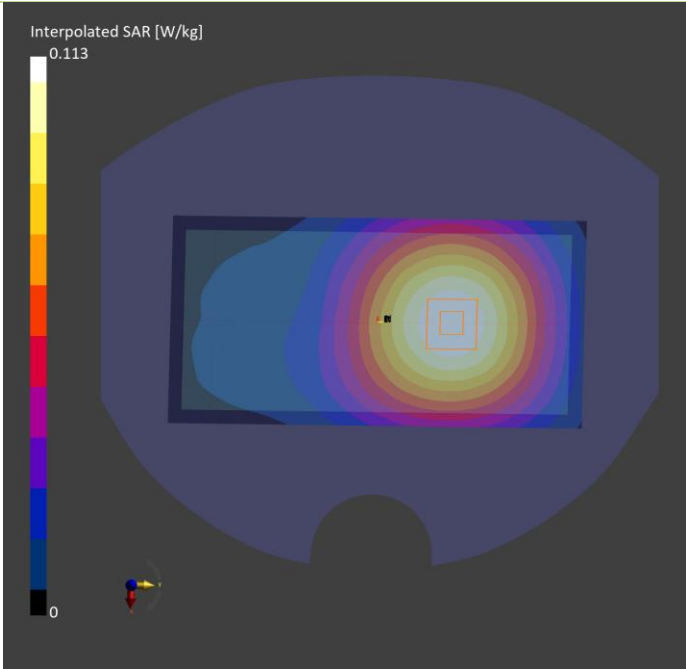
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-13	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 180.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-13	2024-05-13
psSAR1g [W/kg]	0.100	0.106
psSAR10g [W/kg]	0.071	0.080
Power Drift [dB]	0.09	0.09
M2/M1 [%]		76.2
Dist 3dB Peak [mm]		> 16.0



Plots of Measurement

Measurement Report
P60 LTE 30_QPSK10M_Front Face_10mm_Ch27710_1RB OS0_Reader_4770_Ant 6
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Front Face, 10.00	Band 30	LTE-FDD, 10175-CAH	2310.000, 27710	7.95	1.76	37.6

Hardware Setup

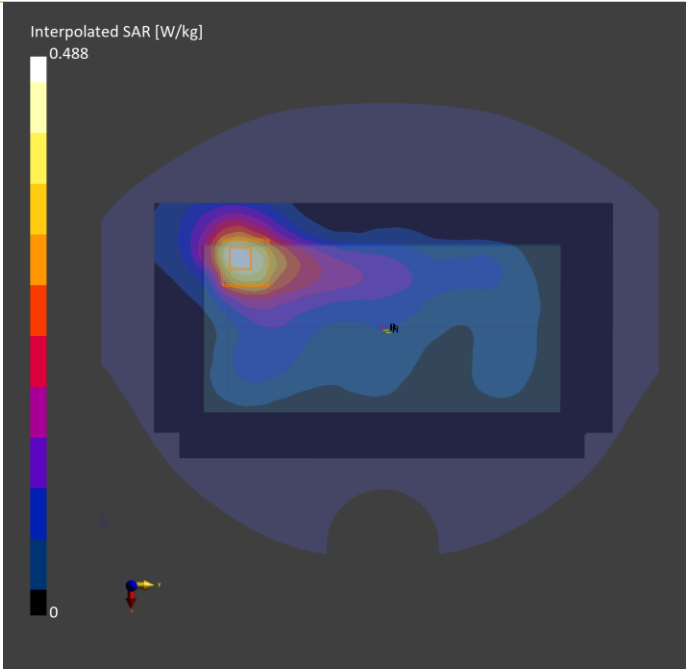
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	0.393	0.418
psSAR10g [W/kg]	0.210	0.222
Power Drift [dB]	0.02	-0.16
M2/M1 [%]		53.6
Dist 3dB Peak [mm]		11.7



Plots of Measurement

Measurement Report
P61 LTE 38_QPSK20M_Front Face_10mm_Ch37850_1RB OS0_Reader_4770_Ant 6
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Front Face, 10.00	Band 38	LTE-TDD, 10172-CAH	2580.000, 37850	7.58	1.99	37.1

Hardware Setup

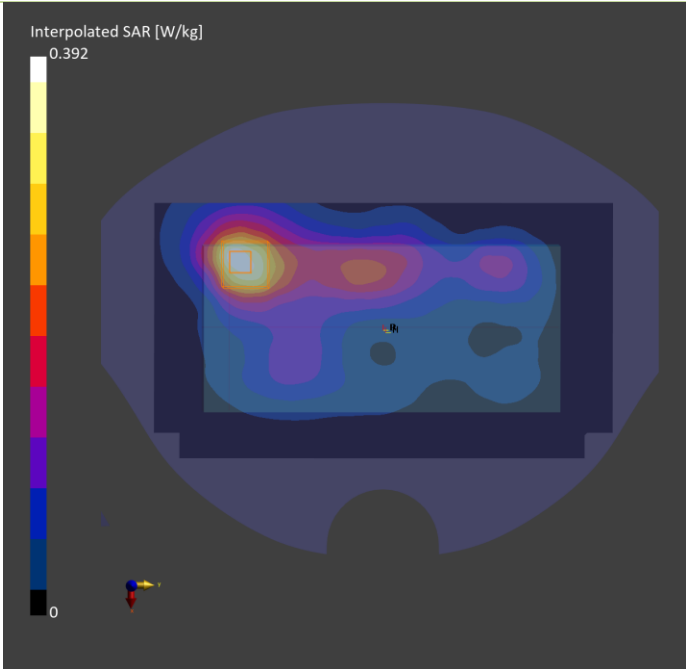
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Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	0.314	0.333
psSAR10g [W/kg]	0.166	0.173
Power Drift [dB]	0.09	0.00
M2/M1 [%]		50.0
Dist 3dB Peak [mm]		12.3



Plots of Measurement

Measurement Report
P62 LTE 41_QPSK20M_Front Face_10mm_Ch40185_1RB OS0_Reader_4770_Ant 6
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Front Face, 10.00	Band 41	LTE-TDD, 10172-CAH	2549.500, 40185	7.58	1.97	37.2

Hardware Setup

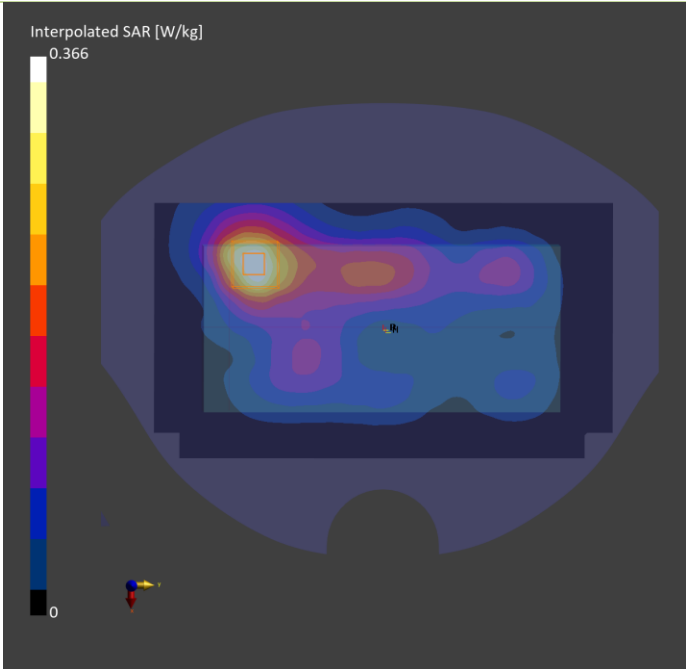
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-16	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 216.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-16	2024-05-16
psSAR1g [W/kg]	0.298	0.317
psSAR10g [W/kg]	0.158	0.165
Power Drift [dB]	0.15	0.04
M2/M1 [%]		50.2
Dist 3dB Peak [mm]		12.3



Plots of Measurement

Measurement Report
P63 LTE 42_QPSK20M_Rear Face_10mm_Ch43340_1RB OS50_Reader_4770_Ant 7
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 42	LTE-TDD, 10172-CAH	3575.000, 43340	6.65	2.85	39.3

Hardware Setup

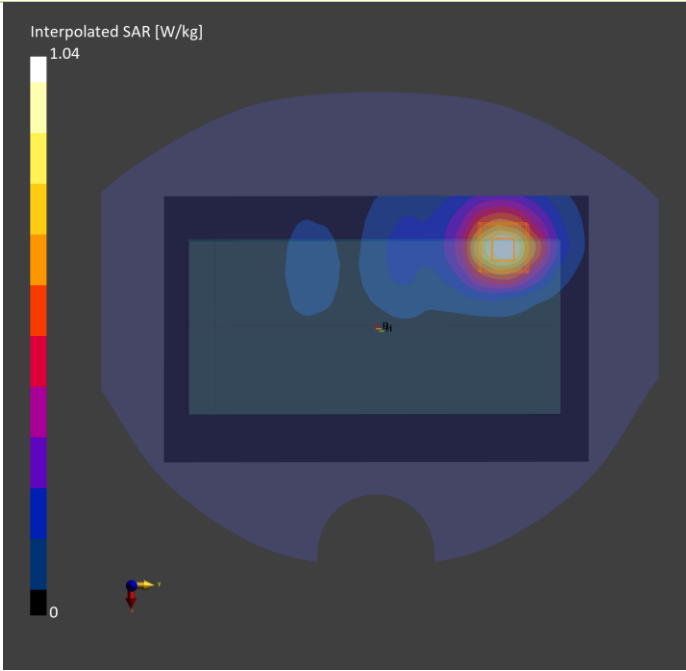
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-13	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 192.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-13	2024-05-13
psSAR1g [W/kg]	0.779	0.813
psSAR10g [W/kg]	0.355	0.380
Power Drift [dB]	0.11	0.05
M2/M1 [%]		64.5
Dist 3dB Peak [mm]		13.1



Plots of Measurement

Measurement Report
P64 LTE 43_QPSK20M_Rear Face_10mm_Ch44190_1RB OS0_Reader_4770_Ant 7
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 43	LTE-TDD, 10172-CAH	3660.000, 44190	6.6	2.93	39.1

Hardware Setup

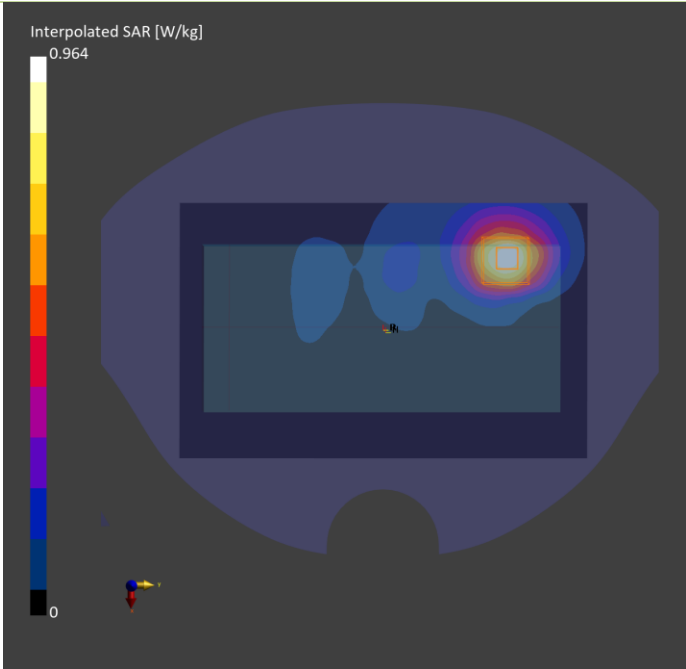
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-13	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 192.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-13	2024-05-13
psSAR1g [W/kg]	0.735	0.806
psSAR10g [W/kg]	0.337	0.372
Power Drift [dB]	-0.09	0.04
M2/M1 [%]		78.1
Dist 3dB Peak [mm]		12.2



Plots of Measurement

Measurement Report
P65 LTE 48_QPSK20M_Rear Face_10mm_Ch55780_1RB OS0_Reader_4770_Ant 7
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 48	LTE-TDD, 10172-CAH	3603.000, 55780	6.6	2.92	39.4

Hardware Setup

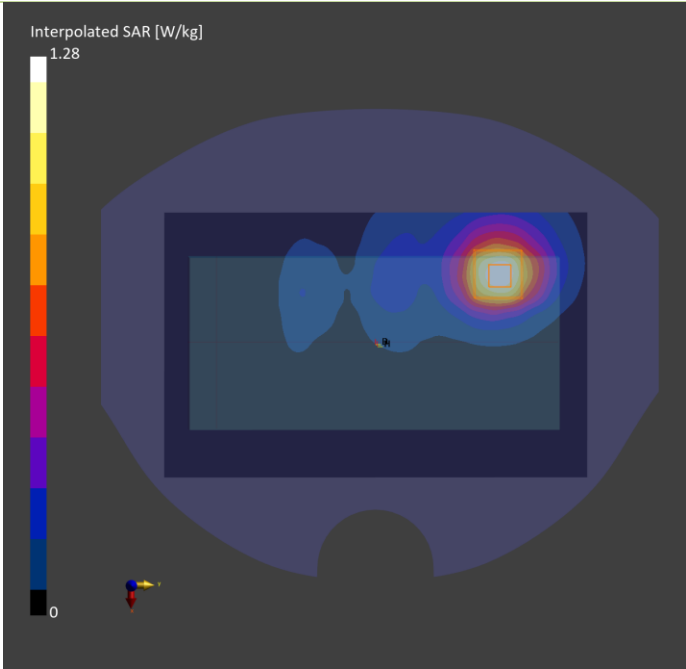
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H33T50N4 , 2024-May-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 192.0	30.0 x 30.0 x 28.0
Grid Steps [mm]	12.0 x 12.0	5.0 x 5.0 x 2.5
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-15	2024-05-15
psSAR1g [W/kg]	0.719	0.736
psSAR10g [W/kg]	0.371	0.324
Power Drift [dB]	0.07	-0.00
M2/M1 [%]		62.2
Dist 3dB Peak [mm]		13.7



Plots of Measurement

Measurement Report
P66 LTE 66_QPSK20M_Rear Face_10mm_Ch132572_1RB OS0_Reader_4770_Ant 0
Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
BCMN-WTW-P23100614,	168.0 x 78.0 x 25.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	Rear Face, 10.00	Band 66	LTE-FDD, 10169-CAF	1770.000, 132572	8.74	1.43	42.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 1987	H06T27N4 , 2024-May-15	EX3DV4 - SN7537, 2023-10-23	DAE4 Sn1762, 2023-11-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4

Measurement Results

	Area Scan	Zoom Scan
Date	2024-05-15	2024-05-15
psSAR1g [W/kg]	0.410	0.436
psSAR10g [W/kg]	0.235	0.266
Power Drift [dB]	0.06	-0.01
M2/M1 [%]		63.5
Dist 3dB Peak [mm]		14.4

